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PCI-5411

NI PXIe-5450

User Manual

National Instruments 400 MS/s, 16-bit differential I/Q generator for the PXI Express platform

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Depending on where it is operated, this Class A product could be subject to restrictions in the FCC rules. (In Canada, the Department of Communications (DOC), of Industry Canada, regulates wireless interference in much the same way.) Digital electronics emit weak signals during normal operation that can affect radio, television, or other wireless products.

All Class A products display a simple warning statement of one paragraph in length regarding interference and undesired operation. The FCC rules have restrictions regarding the locations where FCC Class A products can be operated.

Consult the FCC Web site at www.fcc.gov for more information.

FCC/DOC Warnings

This equipment generates and uses radio frequency energy and, if not installed and used in strict accordance with the instructions in this manual and the CE marking Declaration of Conformity*, may cause interference to radio and television reception. Classification requirements are the same for the Federal Communications Commission (FCC) and the Canadian Department of Communications (DOC).

Changes or modifications not expressly approved by NI could void the user's authority to operate the equipment under the FCC Rules.

Class A

Federal Communications Commission

This equipment has been tested and found to comply with the limits for a Class A digital device, pursuant to part 15 of the FCC Rules. These limits are designed to provide reasonable protection against harmful interference when the equipment is operated in a commercial environment. This equipment generates, uses, and can radiate radio frequency energy and, if not installed and used in accordance with the instruction manual, may cause harmful interference to radio communications. Operation of this equipment in a residential area is likely to cause harmful interference in which case the user is required to correct the interference at their own expense.

Canadian Department of Communications

This Class A digital apparatus meets all requirements of the Canadian Interference-Causing Equipment Regulations.

Cet appareil numérique de la classe A respecte toutes les exigences du Règlement sur le matériel brouilleur du Canada.

Compliance with EU Directives

Users in the European Union (EU) should refer to the Declaration of Conformity (DoC) for information* pertaining to the CE marking. Refer to the Declaration of Conformity (DoC) for this product for any additional regulatory compliance information. To obtain the DoC for this product, visit ni.com/certification, search by model number or product line, and click the appropriate link in the Certification column.

* The CE marking Declaration of Conformity contains important supplementary information and instructions for the user or installer.

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Appendix A

Technical Support and Professional Services

About This Manual

This user manual explains the fundamental and advanced concepts necessary for using the NI 5450 arbitrary function generator and describes the features, functions, and operation of the signal generator.

Conventions

The following conventions are used in this manual:

<>

Angle brackets that contain numbers separated by an ellipsis represent a range of values associated with a bit or signal name—for example, AO <3..0>.

[]

Square brackets enclose optional items—for example, [response].

»

The » symbol leads you through nested menu items and dialog box options to a final action. The sequence **File»Page Setup»Options** directs you to pull down the **File** menu, select the **Page Setup** item, and select **Options** from the last dialog box.

◆

The ◆ symbol indicates that the following text applies only to a specific product, a specific operating system, or a specific software version.



This icon denotes a tip, which alerts you to advisory information.



This icon denotes a note, which alerts you to important information.



This icon denotes a caution, which advises you of precautions to take to avoid injury, data loss, or a system crash. When this symbol is marked on a product, refer to the *Read Me First: Safety and Radio-Frequency Interference* document, included with the device, for information about precautions to take.

bold

Bold text denotes items that you must select or click in the software, such as menu items and dialog box options. Bold text also denotes parameter names.

italic

Italic text denotes variables, emphasis, a cross-reference, or an introduction to a key concept. Italic text also denotes text that is a placeholder for a word or value that you must supply.

<code>monospace</code>	Text in this font denotes text or characters that you should enter from the keyboard, sections of code, programming examples, and syntax examples. This font is also used for the proper names of disk drives, paths, directories, programs, subprograms, subroutines, device names, functions, operations, variables, filenames, and extensions.
monospace bold	Bold text in this font denotes the messages and responses that the computer automatically prints to the screen. This font also emphasizes lines of code that are different from the other examples.
<i>monospace italic</i>	Italic text in this font denotes text that is a placeholder for a word or value that you must supply.
Platform	Text in this font denotes a specific platform and indicates that the text following it applies only to that platform.

Related Documentation

The following documents contain information that you may find helpful as you read this manual:

- *NI Signal Generators Getting Started Guide*—provides instructions for installing and configuring NI signal generators
- *NI Signal Generators Help*—includes detailed information about the NI 5450 and the NI-FGEN VIs and functions
- *NI 5450 Specifications*—provides the published specification values for the NI 5450

Features Supported on SMC Devices

The following table shows the features supported by NI signal generators based on the SMC technology.

	NI 5402	NI 5406	NI 5412	NI 5421	NI 5422	NI 5441	NI 5442	NI 5450
Basic Operation								
Output Modes	Standard Function, Frequency List	Standard Function, Frequency List	Standard Function, Arbitrary Waveform, Arbitrary Sequence	Standard Function, Arbitrary Waveform, Arbitrary Sequence, Script	Standard Function, Arbitrary Waveform, Arbitrary Sequence, Script	Standard Function, Arbitrary Waveform, Arbitrary Sequence, Script, Frequency List	Standard Function, Arbitrary Waveform, Arbitrary Sequence, Script, Frequency List	Arbitrary Waveform, Arbitrary Sequence, Script

	NI 5402	NI 5406	NI 5412	NI 5421	NI 5422	NI 5441	NI 5442	NI 5450
Standard Function Output								
Waveform	Sine, Square, Triangle, Ramp Up, Ramp Down, DC, Noise, User- Defined	Sine, Square, Triangle, Ramp Up, Ramp Down, DC, Noise, User- Defined	Sine, Square, Triangle, Ramp Up, DC, Noise, User- Defined	Sine, Square, Triangle, Ramp Up, Ramp Down, DC, Noise, User- Defined	Sine, Square, Triangle, Ramp Up, Ramp Down, DC, Noise, User- Defined	Sine, Square, Triangle, Ramp Up, Ramp Down, DC, Noise, User- Defined	Sine, Square, Triangle, Ramp Up, Ramp Down, DC, Noise, User- Defined	—
Minimum Frequency	0 Hz	0 Hz	<1 mHz ^{††}	<1 mHz ^{††}	<1 mHz ^{††}	0 Hz	0 Hz	—
Maximum Frequency ^{††}	Sine: 20 MHz, Square: 20 MHz, User- Defined: 20 MHz, Other: 1 MHz	Sine: 40 MHz, Square: 40 MHz, User- Defined: 40 MHz, Other: 5 MHz	Sine: 20 MHz, Square: 5 MHz, Other: 1 MHz	Sine: 43 MHz, Square: 25 MHz, Other: 5 MHz	Sine: 80 MHz, Square: 100 MHz, Other: 10 MHz	Sine: 43 MHz, Square: 25 MHz, User- Defined: 43 MHz, Other: 5 MHz	Sine: 43 MHz, Square: 25 MHz, User- Defined: 43 MHz, Other: 5 MHz	—
SYNC Duty Cycle	20% to 80% for square, 50% for all other	20% to 80% for square, 50% for all other	—	—	—	—	—	—
User- Defined Waveform Size	16,384 samples	16,384 samples	Variable [†]	Variable [†]	Variable [†]	16,384 samples	32,768 samples	—

	NI 5402	NI 5406	NI 5412	NI 5421	NI 5422	NI 5441	NI 5442	NI 5450
Frequency List Output								
Maximum Number of Lists*	9,999 lists	9,999 lists	—	—	—	9,999 lists	9,999 lists	—
Maximum List Length*	58,253 s	58,253 s	—	—	—	932,066 s	932,066 s	—
Maximum Step Duration*	21 s	21 s	—	—	—	21 s	21 s	—
Minimum List Length*	1 s	1 s	—	—	—	1 s	1 s	—
Minimum Step Duration*	1.28 μ s	1.28 μ s	—	—	—	1.28 μ s	1.28 μ s	—
Step Duration Quantum*	80 ns	80 ns	—	—	—	80 ns	80 ns	—
Arbitrary Waveform Output								
Write Quantum	64 samples or 32 complex samples	64 samples or 32 complex samples	64 samples or 32 complex samples	64 samples or 32 complex samples	64 samples or 32 complex samples	64 samples or 32 complex samples	1 sample	1 sample
Waveform Quantum*	—	—	4 samples	4 samples	4 samples	4 samples	1 sample	2 samples

	NI 5402	NI 5406	NI 5412	NI 5421	NI 5422	NI 5441	NI 5442	NI 5450
Minimum Waveform Write Size*	—	—	4 samples	4 samples	4 samples	4 samples	4 samples	4 samples
Maximum Waveform Write Size*†	—	—	4 M, 16 M, 128 M samples	4 M, 16 M, 128 M, 256 M samples	4 M, 16 M, 128 M, 256 M samples	16 M, 128 M, 256 M samples	16 M, 128 M, 256 M samples	67 M, 108 M, 352 M samples
Maximum Number of Waveforms*	—	—	2,097,151	2,097,151	2,097,151	2,097,151	2,097,151	2,097,151
Streaming	—	—	—	Yes	Yes	Yes	Yes	Yes
Onboard Signal Processing	—	—	—	—	—	Yes	Yes	Yes
Arbitrary Sequence Output								
Minimum Sequence Length*	—	—	1	1	1	1	1	1
Maximum Sequence Length*	—	—	16,777,205†	16,777,205†	16,777,205†	16,777,205†	16,777,205†	16,777,205†
Maximum Loop Count*	—	—	16,777,215	16,777,215	16,777,215	16,777,215	16,777,215	16,777,215
Maximum Number of Sequences*	—	—	2,097,151†	2,097,151†	2,097,151†	2,097,151†	2,097,151†	2,097,151†

	NI 5402	NI 5406	NI 5412	NI 5421	NI 5422	NI 5441	NI 5442	NI 5450
Streaming	—	—	—	Yes	Yes	Yes	Yes	Yes
Onboard Signal Processing	—	—	—	—	—	Yes	Yes	Yes
Script Output								
Maximum Number of Script Triggers	—	—	—	4	4	4	4	4
Maximum Number of Markers	—	—	—	4	4	4	4	4
Streaming	—	—	—	Yes	Yes	Yes	Yes	Yes
Output Characteristics								
Output Voltage (at load equal to source impedance)	up to ± 5 V	up to ± 5 V	up to ± 6 V	up to ± 6 V	up to ± 6 V	up to ± 6 V	up to ± 1 V	up to ± 1 V
Offset (at maximum gain)	± 5 V _{pk}	± 5 V _{pk}	± 3 V	± 3 V	± 6 V	± 3 V	± 0.5 V	0 V
Output Impedance	50 Ω , 75 Ω	50 Ω , 75 Ω	50 Ω , 75 Ω	50 Ω , 75 Ω	50 Ω , 75 Ω	50 Ω , 75 Ω	50 Ω , 75 Ω	50 Ω

	NI 5402	NI 5406	NI 5412	NI 5421	NI 5422	NI 5441	NI 5442	NI 5450
Analog Path	Main, Fixed Low-Gain, Fixed High-Gain	Main, Fixed Low-Gain, Fixed High-Gain	Main, Fixed Low-Gain, Fixed High-Gain	Main, Direct, Fixed Low-Gain, Fixed High-Gain	Main, Direct, Fixed Low-Gain, Fixed High-Gain	Main, Direct, Fixed Low-Gain, Fixed High-Gain	Main, Direct	Direct
Analog Filter Option	Yes	Yes	No	Yes	Yes	Yes	Yes	—
Flatness Correction for Sine Waveforms	Yes	Yes	—	—	—	—	—	Yes
Flatness Correction for Arbitrary Waveforms	—	—	—	—	—	—	—	Yes
Digital Filter Option	Yes	Yes	Yes	Yes	—	Yes	Yes	—
Digital Filter Interpolation Factor	2 or 4 (automatic for Standard Function and Frequency List modes)	2 or 4 (automatic for Standard Function and Frequency List modes)	2, 4, or 8 (maximum of 400 MS/s) <i>or</i> automatic	2, 4, or 8 (maximum of 400 MS/s) <i>or</i> automatic	—	2, 4, or 8 (maximum of 400 MS/s) <i>or</i> automatic	2, 4, or 8 (maximum of 400 MS/s) <i>or</i> automatic	—

	NI 5402	NI 5406	NI 5412	NI 5421	NI 5422	NI 5441	NI 5442	NI 5450
DIGITAL DATA & CONTROL CONNECTOR (DDC) or Digital Pattern	—	—	—	Optional†	Optional†	Optional†	—	—
Triggering and Synchronization								
Trigger Modes (Frequency List and Arbitrary Waveform Generation Modes)	Single, Continuous, Stepped, Burst	Single, Continuous, Stepped, Burst	Single, Continuous, Stepped, Burst	Single, Continuous, Stepped, Burst	Single, Continuous, Stepped, Burst	Single, Continuous, Stepped, Burst	Single, Continuous, Stepped, Burst	Single, Continuous, Stepped, Burst
Trigger Sources	Immediate, External, Software, RTSI_ <0..7>, PXI_STAR, PFI <0..1>	Immediate, External, Software, RTSI_ <0..7>, PXI_STAR, PFI <0..1>	Immediate, External, Software, RTSI_ <0..7>, PXI_STAR, PFI <0..1>	Immediate, External, Software, RTSI_ <0..7>, PXI_STAR, PFI <0..1>	Immediate, External, Software, RTSI_ <0..7>, PXI_STAR, PFI <0..1>	Immediate, External, Software, RTSI_ <0..7>, PXI_STAR, PFI <0..1>	Immediate, External, Software, RTSI_ <0..7>, PXI_STAR, PFI <0..1>	Immediate, External, Software, RTSI_ <0..7>, PFI <0..1>
Multiple Device Synchronization	Using NI-TClk	Using NI-TClk	Using NI-TClk except for Standard Function mode	Using NI-TClk except for Standard Function mode	Using NI-TClk except for Standard Function mode	Using NI-TClk	Using NI-TClk	Using NI-TClk

	NI 5402	NI 5406	NI 5412	NI 5421	NI 5422	NI 5441	NI 5442	NI 5450
Events								
Ready for Start	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes
Started	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes
Done	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes
Marker	—	—	Yes	Yes	Yes	Yes	Yes	Yes
Data Marker	—	—	—	Yes	Yes	Yes	Yes	Yes
Clocking								
Sample Rate (Update Rate) before filtering and interpolation	100 MS/s	100 MS/s	Internal Sample clock: 10 S/s to 100 MS/s, External Sample clock: 10 S/s to 105 MS/s	Internal Sample clock: 10 S/s to 100 MS/s, External Sample clock: 10 S/s to 105 MS/s	5 MS/s to 200 MS/s	Internal Sample clock: 10 S/s to 100 MS/s, External Sample clock: 10 S/s to 105 MS/s	Internal Sample clock: 10 S/s to 100 MS/s, External Sample clock: 10 S/s to 105 MS/s	Internal Sample clock: 12.2 kS/s to 400 MS/s, External Sample clock: 10 MS/s, 20 MS/s to 400 MS/s

	NI 5402	NI 5406	NI 5412	NI 5421	NI 5422	NI 5441	NI 5442	NI 5450
Reference Clock Source	Internal (none), External (CLK IN), PXI 10 MHz clock (PXI only), RTSI_7 (RTSI clock; PCI only), Onboard (PCI only)	Internal (none), External (CLK IN), PXI 10 MHz clock (PXI only), RTSI_7 (RTSI clock; PCI only), Onboard (PCI only)	Internal (none), External (CLK IN), PXI 10 MHz clock (PXI only), RTSI_7 (RTSI clock; PCI only), Onboard (PCI only)	Internal (none), External (CLK IN), PXI 10 MHz clock (PXI only), RTSI_7 (RTSI clock; PCI only), Onboard (PCI only)	Internal (none), External (CLK IN), PXI 10 MHz clock	Internal (none), External (CLK IN), PXI 10 MHz clock	Internal (none), External (CLK IN), PXI 10 MHz clock	Internal (none), External (CLK IN), PXI 10 MHz clock
Reference Clock Frequency	5 MHz to 20 MHz in 1 MHz steps	5 MHz to 20 MHz in 1 MHz steps	5 MHz to 20 MHz in 1 MHz steps	5 MHz to 20 MHz in 1 MHz steps	5 MHz to 20 MHz in 1 MHz steps	5 MHz to 20 MHz in 1 MHz steps	5 MHz to 20 MHz in 1 MHz steps	1 to 100 MHz in 1 MHz steps, 102 MHz to 200 MHz in 2 MHz steps, 204 MHz to 400 MHz in 4 MHz steps
Clock Mode (Arbitrary Waveform Generation Mode)	—	—	Divide-Down, High-Resolution, Automatic	Divide-Down, High-Resolution, Automatic	Divide-Down, High-Resolution, Automatic	Divide-Down, High-Resolution, Automatic	Divide-Down, High-Resolution, Automatic	High-Resolution, Automatic

	NI 5402	NI 5406	NI 5412	NI 5421	NI 5422	NI 5441	NI 5442	NI 5450
Sample Clock Source (Arbitrary Waveform Generation Mode)	—	—	Internal, External (CLK IN), PXI_STAR (PXI only), RTSI_ <0..7>	Internal, External (CLK IN), DDC CLK IN [†] , PXI_STAR (PXI only), RTSI_ <0..7>	Internal, External (CLK IN), DDC CLK IN [†] , PXI_STAR	Internal, External (CLK IN), DDC CLK IN [†] , PXI_STAR	Internal, External (CLK IN), PXI_STAR	Internal, External (CLK IN)
Calibration								
Self-Calibration Functions	niFgen_Se1fCal, niFgen_RestoreLastExtCalConstants	niFgen_Se1fCal, niFgen_RestoreLastExtCalConstants	niFgen_Se1fCal, niFgen_RestoreLastExtCalConstants	niFgen_Se1fCal, niFgen_RestoreLastExtCalConstants	niFgen_Se1fCal, niFgen_RestoreLastExtCalConstants	niFgen_Se1fCal, niFgen_RestoreLastExtCalConstants	niFgen_Se1fCal, niFgen_RestoreLastExtCalConstants	niFgen_Se1fCal, niFgen_RestoreLastExtCalConstants
Calibration Utility Functions [‡]	niFgen_functions	niFgen_functions	niFgen_functions	niFgen_functions	niFgen_functions	niFgen_functions	niFgen_functions	niFgen_functions

	NI 5402	NI 5406	NI 5412	NI 5421	NI 5422	NI 5441	NI 5442	NI 5450
External Calibration Functions**	niFgen_In itExtCal and associated functions	niFgen_In itExtCal and associated functions	niFgen_In itExtCal and associated functions	niFgen_In itExtCal and associated functions	niFgen_In itExtCal and associated functions	niFgen_In itExtCal and associated functions	niFgen_In itExtCal and associated functions	niFgen_In itExtCal and associated functions
<p>* You can get the value of this characteristic by calling a query function or by reading an attribute. NI recommends that your programs query or read the characteristic rather than depend on a certain value.</p> <p>† Varies with the device model or the amount of memory on the device. Memory use is a function of the number and size of waveforms and (in Arbitrary Sequence mode) the number and length of sequences. Typically, waveforms use most of the memory, but if you have a very large number of sequences, the available waveform memory is reduced.</p> <p>‡ Calibration utility functions include: niFgen_GetSelfCalSupported, niFgen_GetSelfCalLastDateAndTime, niFgen_GetExtCalLastDateAndTime, niFgen_GetSelfCalLastTemp, niFgen_GetExtCalLastTemp, niFgen_GetExtCalRecommendedInterval, niFgen_ChangeExtCalPassword, niFgen_SetCalUserDefinedInfo, niFgen_GetCalUserDefinedInfo, niFgen_GetCalUserDefinedInfoMaxSize, niFgen_ReadCurrentTemperature</p> <p>** External calibration functions and steps vary from device to device. For more information about calibrating your device, refer to the calibration procedure for your device.</p> <p>†† Refer to the device specifications for conditions.</p> <p>‡‡ The minimum frequency available on these devices depends on the memory size of the device, as well as the value of the NIFGEN_ATTR_FUNC_MAX_BUFFER_SIZE attribute.</p>								

NI 5450 Overview

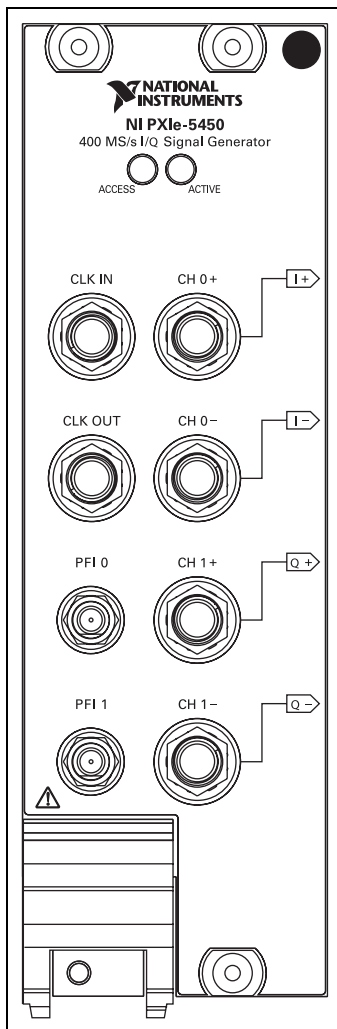
The NI 5450 is a 400 MS/s, 16-bit differential I/Q generator for the PXI Express platform with the following features:

- Onboard signal processing (OSP) with 120 MHz of baseband I/Q bandwidth, flatness correction, and interpolation
- 16-bit resolution output, two channels, differential output
- Differential output amplitude with a maximum of $1.0 V_{pk-pk}$ into a 100Ω differential load
- 50Ω output impedance (100Ω differential output impedance), and output attenuation levels from 0 to 3 dB
- High-Resolution internal clocking
- External clocking options
- PLL synchronization to external clocks or to PXI clock
- TCclk synchronization
- Sample rate up to 400 MS/s
- Up to 2 GB of onboard waveform memory
- Waveform linking and looping for arbitrary waveform generation
- Digital gain
- 2 bidirectional PFI lines for importing triggers and exporting events
- PXI trigger lines

All NI 5450 devices follow industry-standard Plug and Play specifications for the PXI Express bus and offer seamless integration with compliant systems.

Front Panel

The following figure shows the NI PXIe-5450 front panel. This front panel has two SMB connectors and six SMA connectors.



The CLK IN SMA connector accepts an external clock that can be used as a Reference clock, a Sample clock, or a Sample clock timebase.

The CLK OUT SMA connector provides a clock signal that can be shared by other devices.

The PFI 0 and PFI 1 SMB connectors are bidirectional connections that can accept a trigger from an external source and can start or step through waveform generation or route signals from several clock, event, and trigger sources.

The CH 0+/I+ SMA connector provides differential waveform output for channel 0.

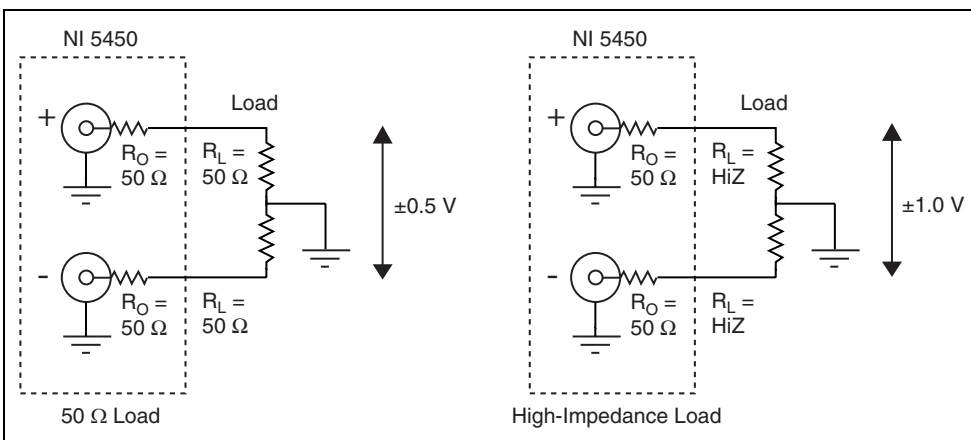
The CH 0–/I– SMA connector provides complementary differential waveform output for channel 0.

The CH 1+/Q+ SMA connector provides differential waveform output for channel 1.

The CH 1–/Q– SMA connector provides complementary differential waveform output for channel 0.

Differential Channel Connectors

The CH 0+/- and CH 1+/- connectors are the analog waveform output terminals. These connectors provide differential waveform output; they cannot be used for single-ended operation. The connectors must terminate into balanced loads. The maximum output levels from these connectors depend on the type of load termination. For example, if the output of the device terminates into a balanced 50 Ω load with flatness correction disabled, the maximum output levels are ± 0.5 V, while the maximum output levels are ± 1.0 V when the device terminates into a high-impedance load (HiZ). This difference is illustrated in the following figure.



If the output terminates into any other load, the levels are defined by the following formula:

$$V_{out} = \pm [R_L / (R_L + R_O)] \times 2 \text{ V}$$

where

V_{out} is the maximum peak output voltage level

R_L is the load impedance in ohms

R_O is the output impedance of the module in ohms



Note For loads less than 50 Ω , load impedance compensation supports only combinations of gain and load impedance that meet the previous V_{out} equation.

Set the amplitude of the generated output signal in terms of peak voltage by setting the gain value. NI-FGEN calculates and sets the correct amount of attenuation required for the desired gain value. Configure the output signal

amplitude by calling the `Arbitrary Waveform Gain` property or `NIFGEN_ATTR_ARB_GAIN` attribute.

Load Impedance Compensation

The NI 5450 has the ability to configure the output signal amplitude based on a user-configured load impedance setting. This capability is desirable when you use the NI 5450 with loads that are between $0\ \Omega$ and a high impedance. Refer to the device specifications for information about the output impedance tolerance.

By default, NI-FGEN assumes that the load impedance is equal to the output impedance. If they do not match, you can change the load impedance value that NI-FGEN uses in its load impedance compensation algorithm. NI-FGEN takes the load impedance into account when setting the amplitude and provides the amplitude specified in the configured gain setting, eliminating the need to use the voltage divider equation. NI-FGEN compensates to give the desired peak-to-peak voltage amplitude or arbitrary gain (relative to 1 V). You can configure the load impedance by calling the `Load Impedance` property or `NIFGEN_ATTR_LOAD_IMPEDANCE` attribute.



Note The voltage output levels are set in the software and are based upon a $50\ \Omega$ load termination (the default), or based on the user-specified load resistance.

For waveform output signal specifications, refer to the device specifications.

CLK IN Connector

The CLK IN front panel connector can accept an external Reference clock, external Sample clock, or external Sample clock timebase.



Caution Do *not* change the external clocks while generating waveforms. Only modify the frequency of the external clock *before* you start the waveform generation or *after* you stop the waveform generation. NI cannot guarantee the quality of the generated signal if you change the external clock during waveform generation.

External Reference Clock Input

The CLK IN connector can accept a Reference clock from an external source and phase-lock the internal clock of the signal generator to this external Reference clock. Refer to the device specifications for the allowable Reference clock frequencies and signal characteristics.

The Reference clock uses the internal clock by default. Call the niFgen Configure Reference Clock VI or the `niFgen_ConfigureReferenceClock` function to configure the Reference clock source.

When configuring an external Reference clock, you must configure the external Reference clock frequency if it is different from the 10 MHz default setting. Set the Reference clock frequency with the niFgen Configure Reference Clock VI or the `niFgen_ConfigureReferenceClock` function.



Note You also can phase-lock the signal generator to other NI devices using the common PXI 10 MHz backplane clock on PXI devices.

External Sample Clock Input

In addition to phase-locking, the CLK IN connector also can receive an external Sample clock. Refer to the device specifications for the allowable external Sample clock frequencies and signal characteristics.



Tip When configuring an external Sample clock, set the sample rate to the exact frequency you are using to avoid data errors. Set the sample rate by calling the niFgen Set Sample Rate VI or `niFgen_ConfigureSampleRate` function.

Configure the Sample clock source with niFgen Configure Sample Clock Source VI or the `niFgen_ConfigureSampleClockSource` function. The Sample clock uses the internal clock by default.

External Sample Clock Timebase Input

The CLK IN connector also can receive an external Sample clock timebase. Refer to the device specifications for the allowable external Sample clock timebase frequencies and signal characteristics.

Configure the Sample clock timebase source with the Sample Clock Timebase Source and Sample Clock Timebase Rate properties or the `NIFGEN_ATTR_SAMPLE_CLOCK_TIMEBASE_SOURCE` and `NIFGEN_ATTR_SAMPLE_CLOCK_TIMEBASE_RATE` attributes. The device uses the internal sample clock timebase by default.

CLK OUT Connector

The CLK OUT connector is typically used as an output terminal to provide a clock signal that can be shared by other devices. The CLK OUT connector is designed to allow the NI 5450 to generate high speed clock signals with very low jitter.

As an output, the CLK OUT line routes a signal out from the following sources:

- PLL Reference clock source
- Sample Clock Out (with $/K$ where K is an integer used to divide the Sample clock)
- Sample clock timebase (with $/M$ where M is an integer used to divide the Sample clock timebase frequency)

Refer to the device specifications for information about the signal characteristics for the CLK OUT connector.

PFI Connectors

PFI 0 and PFI 1 are bidirectional connectors. As an input, the PFI terminals can accept a trigger from an external source that can start or step through waveform generation.

As an output, the PFI lines route a signal out from the following sources:

- Marker events
- Start trigger
- PLL Reference clock source
- Sample Clock Out (with $/K$ where K is an integer used to divide the Sample clock)
- Started, Done, and Ready for Start events
- Sample clock timebase (with $/M$ where M is an integer used to divide the Sample clock timebase frequency)
- Script trigger

Refer to the device specifications for information about acceptable input signal characteristics for the PFI lines and output signal characteristics.

ACCESS and ACTIVE LEDs

The ACCESS and ACTIVE LEDs indicate the status of the PXIe module:

ACCESS LED

The ACCESS LED indicates basic hardware status as shown in the following table.

Color	Indications
Off	Device is not yet functional, or the device has detected a problem with a power rail.
Amber	The device is being accessed.
Green	The device is ready to be programmed by NI-FGEN.

ACTIVE LED

The ACTIVE LED indicates the device state as shown in the following table.

Color	Indications
Off	Device is not generating.
Amber	The device is armed and waiting for a trigger.
Green	The device has received a trigger. Also indicates that the device is generating a waveform.
Red	The device has detected an error. NI-FGEN must access the device to determine the cause of the error. The LED remains red until the error condition is removed. Errors might include unlocked PLLs or an over-temperature condition.

Power-Up and Reset Conditions

The signal generator is in the following state from the time at which the computer begins to power up until the operating system is fully booted and NI-FGEN is loaded.

- The CH 0+/- and CH 1+/- differential output connectors are disabled and each has 50 Ω impedance to ground. This impedance is the same as its previous setting before the device was powered down. The output voltage amplitude of this connector is 0 V.
- The CLK IN connector has high-impedance to ground.
- PFI 0 and PFI 1 are tristated and have a 10 k Ω impedance to ground.
- The CLK OUT connector is tristated and has a high-impedance to ground.
- PXI trigger lines are tristated and floating.

After the operating system is fully booted and NI-FGEN is loaded, or when you perform a hard reset to the device directly from MAX or using NI-FGEN, the signal generator is in the following state:

- CH 0+/- and CH 1+/- output is enabled.
- CH 0+/- and CH 1+/- output attenuation is set to 0 dB.
- CLK OUT output impedance is set to high-impedance.
- CLK IN is disabled and has a high-impedance to ground.
- PFI 0 and PFI 1 are tristated and have a 10 k Ω impedance to ground.
- PXI trigger lines are tristated and floating.
- The sample rate is set to the maximum rate, with the Sample clock source set to the internal Sample clock timebase.
- The Sample clock timebase is tuned by the internal reference control voltage.

Thermal Shutdown

NI-FGEN supports thermal shutdown capability for the NI 5450. This capability allows the signal generator to detect when it has reached a dangerously high temperature and to then power down to prevent damage to the device.

Air circulation paths, fan settings, and space allowances are several factors that can influence device temperature. To prevent thermal shutdown, follow the guidelines described in the *Maintain Forced-Air Cooling Note to Users* document that shipped with your device. Refer to the device specifications to find the correct operating temperature range.

In the event that the signal generator powers down, you are notified with an error message in one of the following ways:

- NI-FGEN returns an error when you use any of the VIs or functions that program the hardware or check hardware status, for example, the niFgen Commit VI or the `niFgen_commit` function and the niFgen Self Cal VI or the `niFgen_SelfCal` function.
- MAX returns an error message if you run a self-test on your device after it exceeds the thermal shutdown temperature.

To re-enable your device after thermal shutdown, use one of the following methods:

- Power down the computer or chassis that contains the signal generator.

or

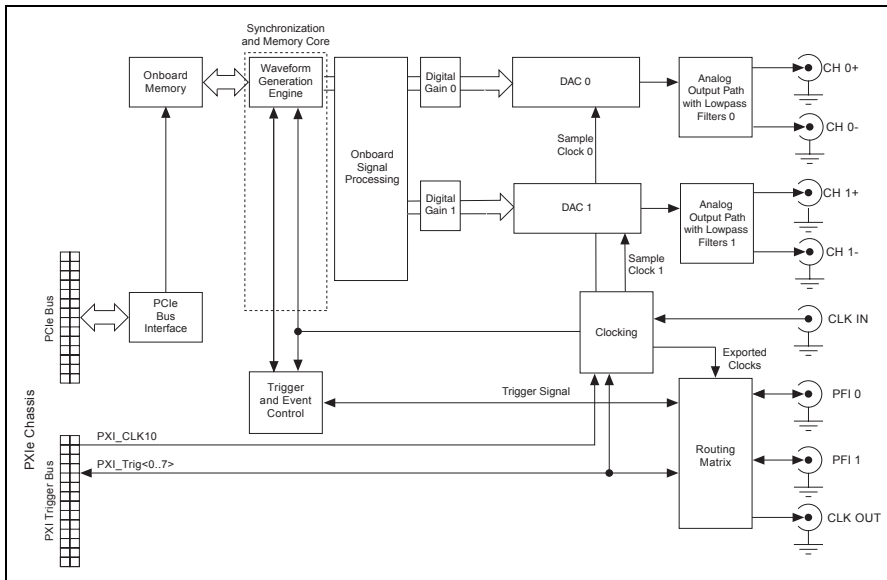
- Call the niFgen Reset Device VI or the `niFgen_ResetDevice` function or perform a device reset in MAX. For more information about resetting a device in MAX, select **Help»Help Topics»NI-DAQmx»MAX Help for NI-DAQmx** within MAX.

Review the guidelines in the *Maintain Forced-Air Cooling Note to Users* document that shipped with the product and make any necessary adjustments to ensure that the signal generator cools effectively. The thermal shutdown error continues to be reported until the device is successfully reset.

Theory of Operation

Block Diagram

This topic contains information about the NI 5450 top-level block diagram and descriptions of the individual blocks.

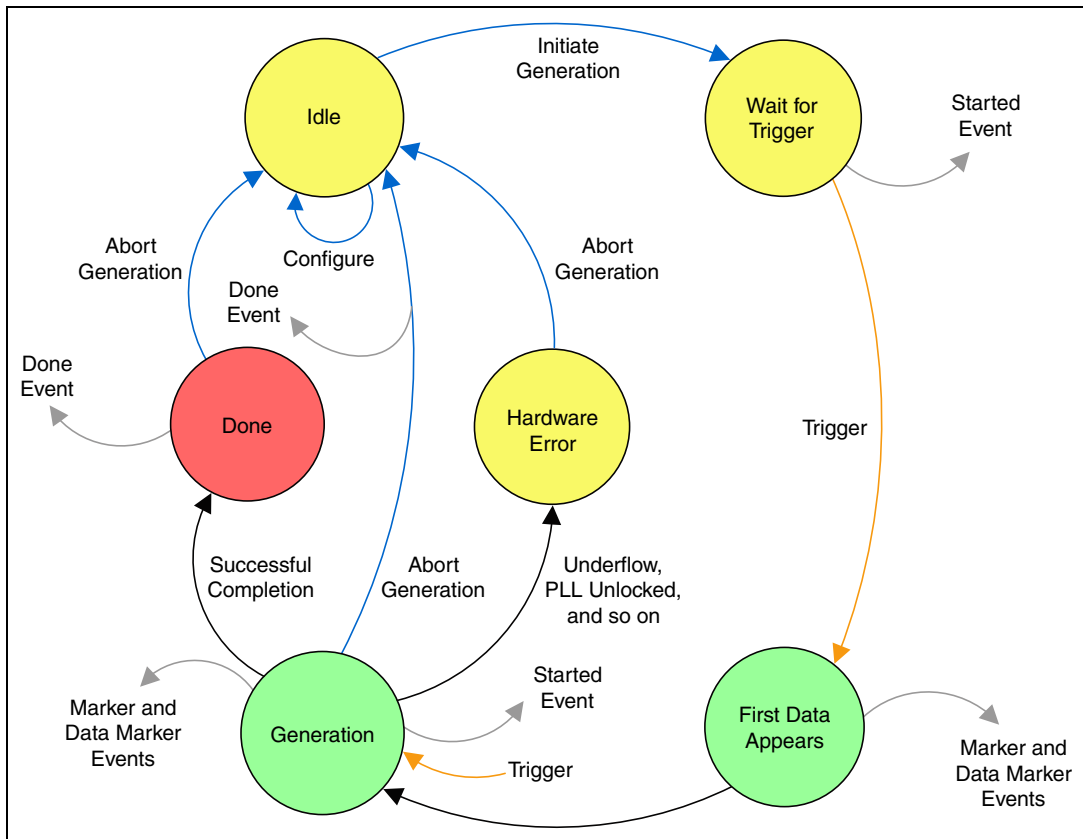


The following list describes the individual blocks:

- **Onboard Memory** stores the waveform data and generation instructions that you load into the device.
- **Clocking** allows you to create your Sample clock and Reference clock.
- The **Waveform Generation Engine** retrieves the waveform data and instructions from the **Onboard Memory** using the Sample clock. The **Waveform Generation Engine** also uses this clock to retrieve triggers from **Trigger and Event Control**.
- The output from the **Waveform Generation Engine** is sent to the **DAC** device after any digital gain or onboard signal processing is applied.
- The waveform data is sent from the **DAC** to the **Analog Output path** where the waveform data is filtered.
- The **Routing Matrix** allows flexible routing of the PXI Trigger lines and the external PFI lines.

Hardware State Diagram

The following diagram shows the hardware states of the signal generator.



The signal generator can be in one of the following six basic states during the course of operation.

Idle—The device is not generating a waveform. All session properties or attributes can be programmed in the Idle state. In the Idle state, the properties or attributes have not necessarily been applied to hardware, so the hardware configuration of the device may not match the session property or attribute values. The device remains configured as it was the last time a session was committed. If the computer has just been powered on, reset, or the niFgen Reset Device VI or the niFgen_ResetDevice function has just been called, the device is in the default hardware state.

Wait for Trigger—After initiating generation, the device shifts to the Wait for Trigger state. If the trigger source is immediate, the device immediately shifts from this state and generates a Started event. If the trigger sources are configured for a software trigger or for a hardware trigger from one of the available sources, the device remains in this state until the configured trigger occurs. When the device recognizes a trigger condition, the device immediately shifts out of this state and generates a Started event.

First Data Appears—This state is temporary and indicates that waveform data is just starting to appear at the front panel connector.

Generation—In the Generation state, the device is generating a waveform as specified by the session attributes configured. Dynamic (or on-the-fly) properties and attributes, such as the Amplitude, Arbitrary Waveform Gain, and Arbitrary Waveform Offset properties, or the `NIFGEN_ATTR_FUNC_AMPLITUDE`, `NIFGEN_ATTR_ARB_GAIN`, and the `NIFGEN_ATTR_ARB_OFFSET` attributes, are applied immediately to hardware. Started Event trigger is generated as the device recognizes triggers. Depending on the configured trigger mode, the device may stay in the Generation state until the generation is aborted.

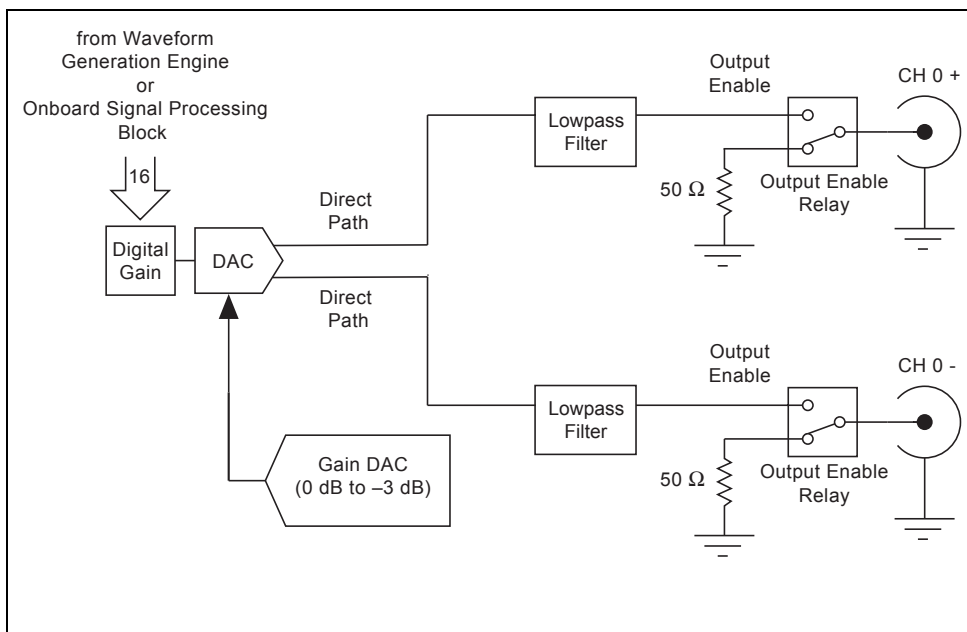
Dynamic properties and attributes, such as amplitude, gain, and offset, can be applied to the device immediately if you set them while the session is in the Generation state. Refer to the *NI-FGEN LabVIEW Reference* or the *NI-FGEN C Function Reference* for information about the specific property or attribute that you want to set during generation.

Done—The device has completed the waveform generation as configured for this session. This state only occurs at the end of a generation state configured for the Single trigger mode. The device remains in this state until the you use NI-FGEN to abort the waveform generation and to return the device to the Idle state.

Hardware Error—An internal hardware error occurred, such as data underflow, the PLL became unlocked, the device shut down due to an over-temperature condition, and so on. The signal generator may still be generating and may be unpredictable at this point. When the driver software checks the status of the device, an error is returned.

Analog Output

The following figure shows the NI 5450 Analog Output signal path.



NI 5450 analog waveforms are generated as follows:

1. The 16-bit digital waveform data from the Waveform Generation Engine or OSP is passed to a digital gain circuit and then high-speed DAC. This DAC also implements a portion of the Analog Output signal path attenuation with a range of 0 to 3 dB. Refer to the NI 5450 specifications for the exact resolution. You can adjust the amount of attenuation by configuring the Arbitrary Waveform Gain property or the `NIFGEN_ATTR_ARB_GAIN` attribute. NI-FGEN calculates and sets the correct amount of attenuation required, corresponding to the gain setting.
2. Following the DAC, the signal follows the Direct path. The Direct path can provide a maximum of 1.0 V_{pk-pk} differential output into 50 Ω with a maximum of 3 dB attenuation.
3. The signal then passes through the Output Enable relay. When the Output Enable relay is disabled, ground is connected to the output through a 50 Ω resistor. Intentionally, waveform generation continues while the output enable relay is disabled. When the relay is enabled, the analog waveform is seen at the CH 0 +/- connector. Enable or disable the output of the analog waveform generator by using the

niFgen Output Enable VI or the
niFgen_ConfigureOutputEnabled function.

- The signal then passes to the differential channel connector. You can configure the output impedance of the analog waveform generator by using the niFgen Configure Output Impedance VI or the niFgen_ConfigureOutputImpedance function.



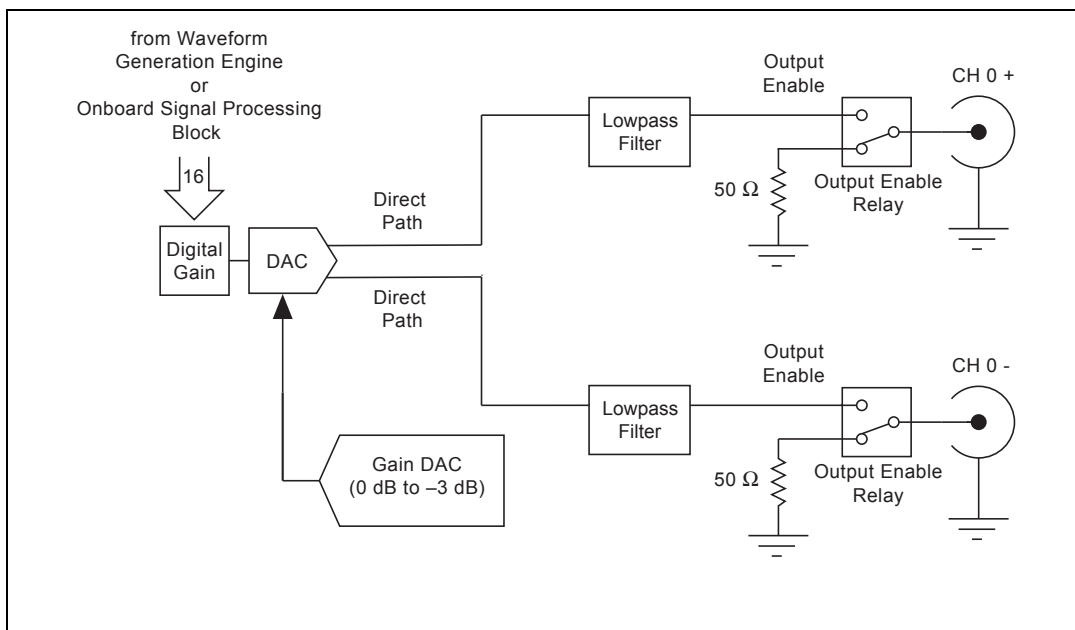
Note The NI 5450 uses mechanical relays to switch between the optional paths and sections in the Analog Output path. When you change a setting that results in a relay switch, the bouncing of electromechanical relays on the NI 5450 distorts the output signal for about 10 ms.

Waveform Amplitude Control

The NI 5450 can be configured to achieve required amplitude settings.

Output Paths and Amplifiers

The following figure shows the Direct path.



The Direct path provides the output of the main DAC to the CH 0+/- connectors with the fewest electronic components in the path. There are no programmable amplifiers and there is no method for adding DC offset to the waveform. The Direct path can generate a maximum of $1.0 V_{pk-pk}$ at the

CH 0+/- output into matched load impedance. The maximum gain setting for an Analog Output path configured to the Direct path is 0.5 (gain is a unitless value).

Attenuation

The main DAC output can be fine-tuned for attenuation, which provides 0 to 3 dB of the Analog Output path signal attenuation. Attenuating the DAC output signal allows you to vary the signal amplitude while maintaining the dynamic range of the DAC. You do not lose any bits from the digital representation of the signal and you do not sacrifice dynamic range, as you would if you control amplitude by using smaller data ranges of the DAC. The main DAC also provides the fine resolution for the attenuation settings.

Fine-tuning of the main DAC attenuation is performed by the gain DAC. Adjust the gain DAC using the Gain DAC Value property or the `NIFGEN_ATTR_GAIN_DAC_VALUE` attribute.

Analog Gain Settings

The following table summarizes the maximum and minimum gain setting that you can apply for the NI-FGEN Analog path options. Refer to the device specifications for more information about gain resolution.

Analog Path Gain Summary (Matched Load Impedance)		
NI-FGEN Analog Path	Maximum Gain Value	Minimum Gain Value
Direct Path without flatness correction	0.5	0.354
Direct Path with flatness correction	0.4	0.284
Note: Gain is unitless.		



Note Digital gain is applied to the digital data before the data is passed to the DAC. Because relays are not used, digital gain allows glitch-free gain control at the expense of dynamic range.

Digital Gain

Digital gain multiplies waveform data by a factor you specify in the Digital Gain property or the `NIFGEN_ATTR_DIGITAL_GAIN` attribute before converting the data to an analog signal in the DAC. Digital gain can be changed during generation without the glitches caused by relay switching that are common when changing analog gains. However, the output resolution of the DAC is a function of digital gain, meaning that only analog gain makes full use of the resolution of the DAC.

Flatness Correction

The NI 5450 can use flatness correction to ensure a consistent power level when generating arbitrary waveforms at any frequency. Flatness correction is disabled by default in NI-FGEN. You can enable or disable flatness correction by calling the Flatness Correction Enabled property or the `NIFGEN_ATTR_FLATNESS_CORRECTION_ENABLED` attribute.

During external calibration, the frequency response of the Analog path in its different configurations is measured using the `niFgen Initialize Flatness Calibration VI` or the `niFgen_InitializeFlatnessCalibration` function and the `niFgen Cal Adjust Flatness VI` or the `niFgen_CalAdjustFlatness` function.

During generation, these measured values are used to compensate for any attenuation at the requested sample rate. The compensation is applied by a flatness-correcting FIR filter. This FIR filter applies attenuation to higher power frequencies so that they become equal to the attenuated frequencies. As a result, the maximum output voltage is $1.0 V_{pk-pk}$ into a 50Ω load.

Filtering Effects

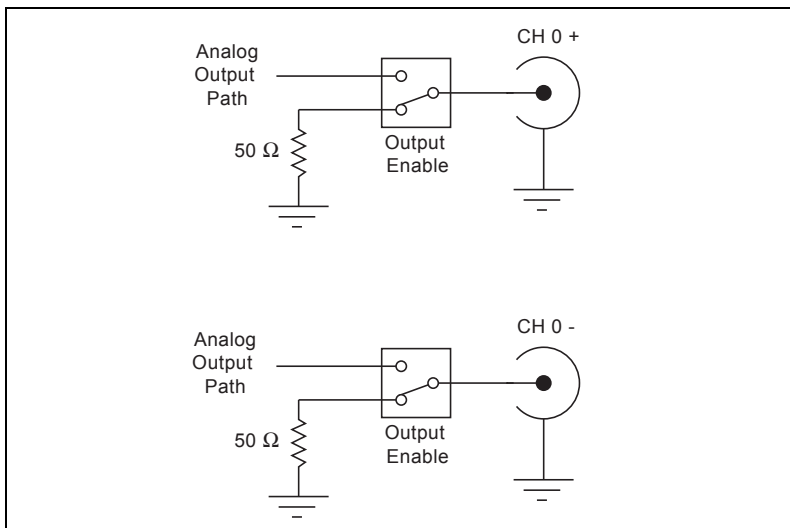
The delay from the time at which the device receives a trigger to the time at which the analog output signal is generated increases if the digital and/or analog filters in the Analog Output path are enabled. In the case of digital filtering, delay also increases with increase in interpolation. Enabling the onboard signal processing block can also introduce delay.



Note The digital filter for the signal generator is inside the FPGA, before the Analog Output path.

Output Enable

You can disable the analog output signal at the differential channel connectors by controlling the output enable relay, as shown in the following figure.



When the output enable relay is disabled, the output signal is connected to ground through a 50 Ω resistance. The output enable relay is enabled for normal waveform generation and connects the differential channel SMA connectors to the Analog Output path. You can change the output enable state at any time during waveform generation, and generation continues internally.

You can enable the output by calling the `niFgen Output Enable VI` or the `niFgen_ConfigureOutputEnabled` function.



Note The signal generator uses mechanical relays to switch between the output enable states. When you change a setting that causes a relay to switch, electromechanical relay bouncing interrupts the output signal for up to 10 ms.

Multichannel Configuration

The NI 5450 has two channels that can be configured as active by calling the `niFgen Configure Channels VI` or the `niFgen_ConfigureChannels` function with a string containing the channel(s) that you wish to activate. You must configure the channels immediately after calling the `niFgen Initialize VI` or the `niFgen_init` function. The `niFgen Configure Channels VI` or the `niFgen_ConfigureChannels` function cannot be called after the session has been committed. If a channel is inactive, it will maintain its output voltage and state until it is made active again or until the device is reset.

The NI 5450 has two memory banks, one for each channel. When the `niFgen Configure Channels VI` or the `niFgen_ConfigureChannels` function is called to configure only one channel as active, both channel memory banks will be configured. This allows you to use the entire onboard memory for one channel of generation.

Configuring Channels for OSP

The NI 5450 supports one channel of real or complex baseband OSP generation. When the OSP is enabled, only one channel may be configured as active. Individual OSP properties can be configured using the I and Q channel strings (“I” and “Q”, respectively).

Multichannel Waveform Allocation

A *waveform* consists of all of the data to be generated on all active channels of a device. A waveform is allocated on a per-device basis, and when waveform allocation occurs, space is allocated on the device onboard memory for each channel. Waveform data must therefore be the same size for each channel.

Because waveforms contain data for all channels, you can only generate one script, sequence, or arbitrary waveform at a time for all active channels of the device; you *cannot* generate separate scripts, sequences, or arbitrary waveforms on different channels at the same time.

Writing Data

On the NI 5450, data can either be written to channel 0 and 1 independently, to I and Q independently, or to both channels simultaneously.



Tip The flexibility to write waveform data to channels either separately or simultaneously is especially useful when configuring applications for I/Q generation.

To write waveform data to an individual channel, begin by allocating space for waveform data by calling the niFgen Allocate Waveform or niFgen Allocate Named Waveform VI or the niFgen_AllocateWaveform or niFgen_AllocateNamedWaveform function. Once you have allocated the waveform data, call the appropriate niFgen Write Waveform (poly) VI or one of the niFgen Write Waveform functions with the **Channel Name** parameter set to “0” or “1” and the **Waveform Name** or **waveformHandle** parameter set to the name of the waveform previously allocated. You can repeat these steps to write waveform data to another channel.

To write waveform data to both channels at once, you must first interleave the data. Once the data is interleaved, call the niFgen Write Waveform (poly) VI or one of the niFgen Write Waveform functions with the **Channel** parameter set to “0,1”.

Interleaved Waveform Data

In order to write data to multiple channels on the same device simultaneously, the data must be interleaved.

Interleaved samples prioritize samples before channels, such that the array lists the first sample from every channel in the task, then the second sample from every channel, up to the last sample from every channel.



Note When interleaved waveform data is allocated, one sample includes data on multiple channels. Therefore, the allocation size of interleaved data, in bytes, is equal to (number of channels being used) × (the number of samples on each channel) × 2.

Channel 0—Sample 1
Channel 1—Sample 1
Channel 0—Sample 2
Channel 1—Sample 2
...
Channel 0—Sample <i>N</i>
Channel 1—Sample <i>N</i>

Onboard Signal Processing (OSP)

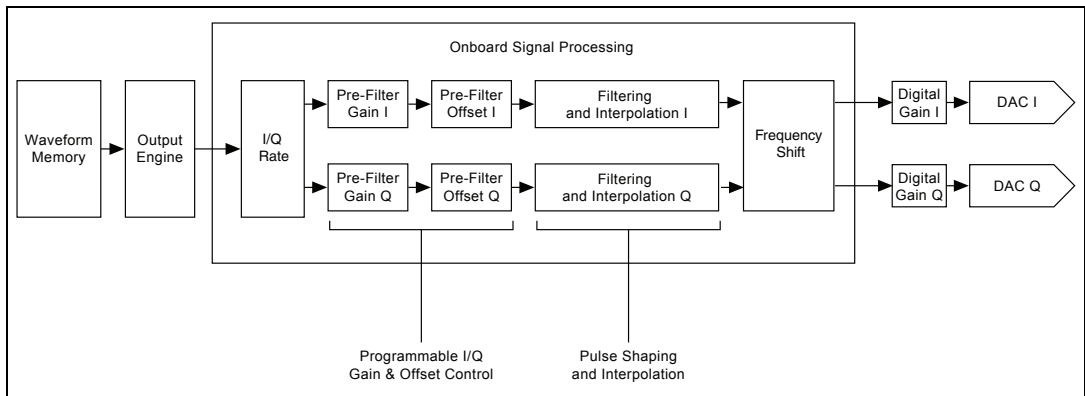
The onboard signal processing (OSP) block is a general-purpose block of digital signal processing components that can be used to modify the data pulled from waveform memory during generation.

The OSP block can be used for the following common applications:

- Arbitrary Waveform Generation
- Baseband Interpolation
- Baseband I/Q Interpolation

Onboard Signal Processing Components

The following figure shows the block diagram of the OSP block.



The OSP block includes the following components:

- Prefilter Gain and Prefilter Offset
- FIR filters
- Filtering and Interpolation
- Writing I/Q Data

I/Q Rate

The I/Q rate component holds off the data from the output engine so that a new sample is only returned once every Total_OSP_Interpolation Sample clocks.



Note The Total_OSP_Interpolation is the amount of interpolation applied within the Filtering and Interpolation component, and does not include the DAC interpolation.

Prefilter Gain

Prefilter gain can change the gain of the I and Q stream during signal generation. You can change the I and Q prefilter gains independently by setting the Pre-Filter Gain I and Pre-Filter Gain Q properties or the NIFGEN_ATTR_OSP_PRE_FILTER_GAIN_I and NIFGEN_ATTR_OSP_PRE_FILTER_GAIN_Q attributes. The gain can range from -16.0 to +16.0 (unitless). Any time the prefilter gain changes, the OSP block ignores all overflows for the next I/Q samples. If an overflow occurs during these samples, the data is clipped but an error is not returned. The prefilter gain can be used to attenuate the I/Q data to eliminate overflows in later stages of the OSP block.

Prefilter Gain Overflow

Any time the following condition is not true for the I or Q data stream, an overflow occurs when prefilter gain is applied:

$$-1 \leq \text{User Data} \times \text{Prefilter Gain} \leq 1$$

If an overflow occurs, the data is clipped and NI-FGEN returns an error. To prevent data clipping, attenuate the waveform data or reduce the prefilter gain.



Tip To disable error reporting caused by OSP overflows, use the OSP Overflow Error Reporting property or the NIFGEN_ATTR_OSP_OVERFLOW_ERROR_REPORTING attribute.

Prefilter Offset

Prefilter offset can add offset to the I and Q stream during signal generation. Change the I and Q prefilter offsets independently by setting the Pre-Filter Offset I and Pre-Filter Offset Q properties or the NIFGEN_ATTR_OSP_PRE_FILTER_OFFSET_I and NIFGEN_ATTR_OSP_PRE_FILTER_OFFSET_Q attributes. The offset can

range from negative full scale (–1) to positive full scale (+1). Any time the prefilter offset changes, the OSP block ignores all overflows for the next I/Q samples. If an overflow occurs during these samples, the data is clipped but an error is not returned.

Prefilter Offset Overflow

Any time the following condition is not true for the I or Q data stream, an overflow occurs when prefilter offset is applied:

$$-1 \leq (\text{User Data} \times \text{Pre-Filter Gain}) + \text{Pre-Filter Offset} \leq 1$$

If an overflow occurs, the data is clipped and NI-FGEN returns an error. To prevent data clipping, reduce the prefilter gain, attenuate the waveform data, or reduce the prefilter offset.



Tip To disable error reporting caused by OSP overflows, use the OSP Overflow Error Reporting property or the `NIFGEN_ATTR_OSP_OVERFLOW_ERROR_REPORTING` attribute.

FIR Filter Types

There are a number of built-in low-pass pulse-shaping filters available in NI-FGEN. Because the coefficients are scaled for unity-gain, the filters may overflow if transients (such as step response) are presented at the input of the filter. Use the Filter Type property or the `NIFGEN_ATTR_OSP_FIR_FILTER_TYPE` attribute to set the FIR filter type. The following filters are currently available:

- Flat
- Raised Cosine
- Root Raised Cosine



Note Enabling filters in the OSP will add a constant group delay to your signal.

Digital Filter Overflow

FIR filters may overflow. If an overflow occurs, data is clipped and NI-FGEN returns an error.

Digital filter overflows are caused by transients. Transients can occur as an abrupt jump at the beginning of a waveform or they may be present in the data you supply. NI-FGEN ignores overflows that are caused by transients at the beginning of a waveform. You can choose to ignore overflow errors caused by transients present in your data with the OSP Overflow Error Reporting property or the `NIFGEN_ATTR_OSP_OVERFLOW_ERROR_REPORTING` attribute.

FIR Filter Type: Flat

Passband Value: 0.40

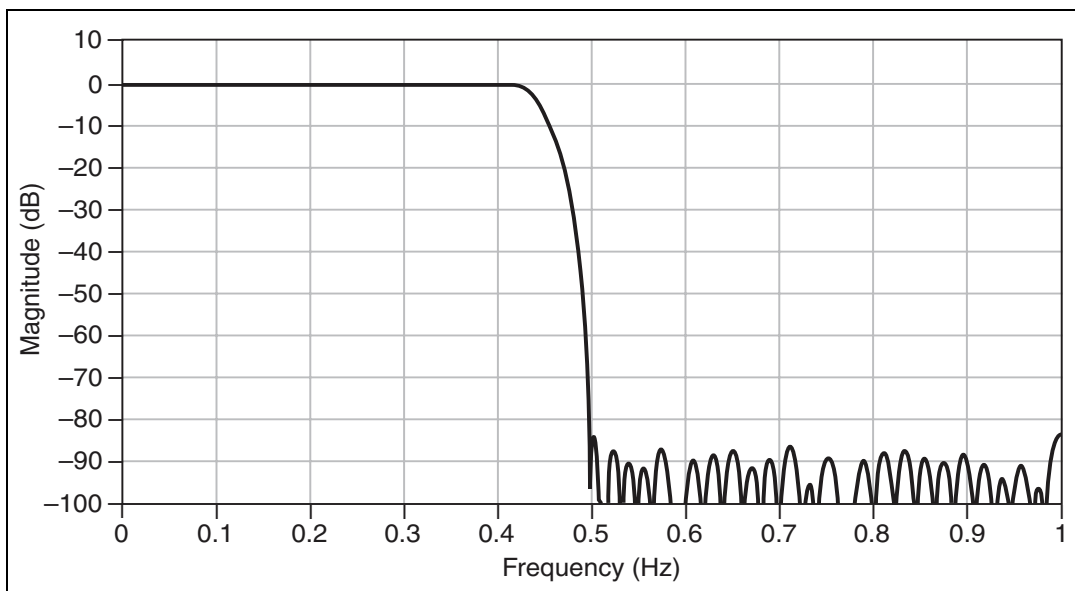
This lowpass filter is designed to give a flat response until the passband value. The passband value is a fraction of the I/Q Rate coming into the FIR filter. Use the Flat Filter Passband property or the

`NIFGEN_ATTR_OSP_FIR_FILTER_FLAT_PASSBAND` attribute to set the passband value.



Caution The Flat filter stopband does not begin until $0.6 \times I/Q$ Rate. If you provide data that has frequency content above $0.4 \times I/Q$ Rate, then aliasing occurs in the output spectrum. NI recommends you keep all frequency content below $0.4 \times I/Q$ Rate when using the Flat filter.

The following diagram shows the Flat Filter response with a passband of 0.4. The frequency axis is scaled as a fraction of the I/Q Rate.



FIR Filter Type: Raised Cosine

Alpha Values: 0.1 to 0.4

This lowpass filter is commonly used in communications applications. The passband of the raised cosine filter stops at $0.5 \times (1 - \alpha)$ of the I/Q Rate. The stopband of the raised cosine filter begins at $0.5 \times (1 + \alpha)$ of the I/Q Rate. The transition-band of the raised cosine filter (in dB) follows the following formula:

$$\text{Ideal Raised Cosine Response}(f) = 20\log_{10}\left(0.5 + 0.5\cos\left[\frac{\pi(f-S)}{\alpha}\right]\right)$$

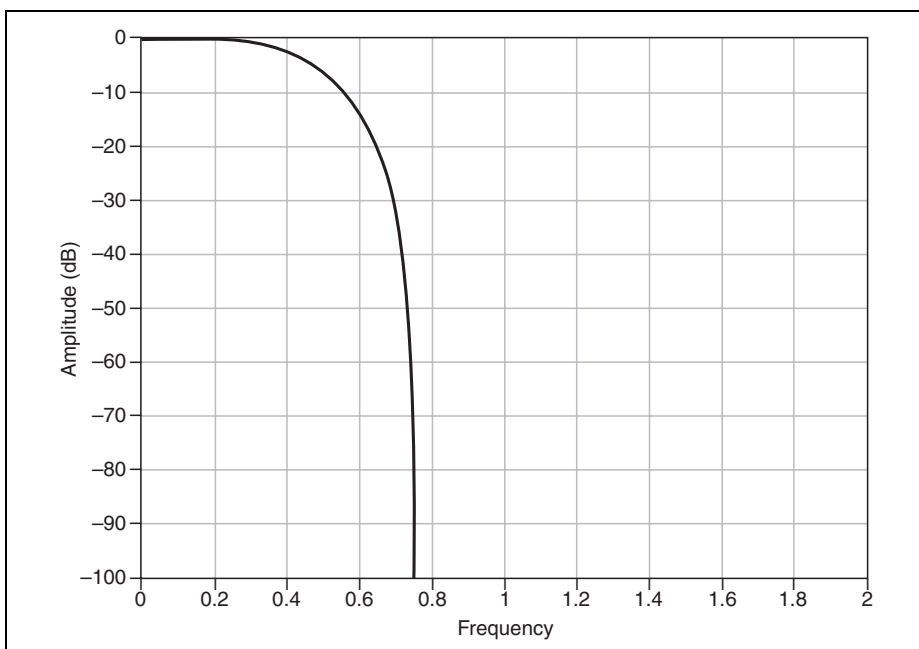
where

S is $0.5 \times (1 - \alpha)$

f is Frequency (fraction of the I/Q Rate)

Use the Raised Cosine Filter Alpha property or the NIFGEN_ATTR_OSP_FIR_FILTER_RAISED_COSINE_ALPHA attribute to set the α value.

The following diagram shows an ideal raised cosine filter response with an α of 0.5. The frequency axis is scaled as a fraction of the I/Q Rate.



FIR Filter Type: Root Raised Cosine

Alpha Values: 0.1 to 0.4

This lowpass filter is commonly used in communications applications. The passband of the root raised cosine filter stops at $0.5 \times (1 - \alpha)$ of the I/Q Rate. The stopband of the root raised cosine filter begins at $0.5 \times (1 + \alpha)$ of the I/Q Rate. The transition-band of the root raised cosine filter (in dB) follows the following formula:

$$\text{Ideal Root Raised Cosine Response}(f) = 20 \log_{10} \sqrt{0.5 + 0.5 \cos \left[\frac{\pi(f-S)}{\alpha} \right]}$$

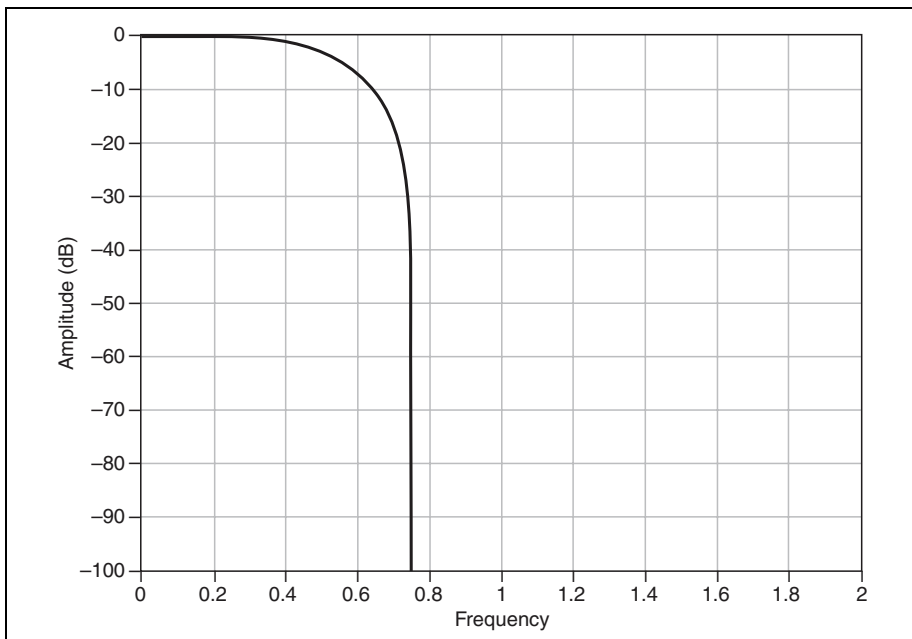
where

S is $0.5 \times (1 - \alpha)$

f is Frequency (fraction of the I/Q Rate)

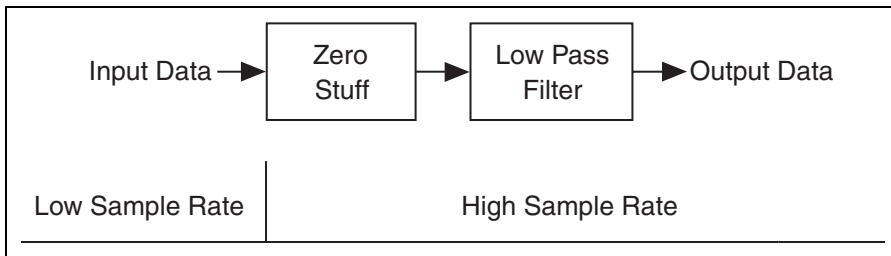
Use the Raised Cosine Filter Alpha property or the `NIFGEN_ATTR_OSP_FIR_FILTER_RAISED_COSINE_ALPHA` attribute to set the α value.

The following diagram shows an ideal root raised cosine filter response with an α of 0.5. The frequency axis is scaled as a fraction of the I/Q Rate.



Filtering and Interpolation

The filtering and interpolation stage of the OSP block increases the effective sample rate of the signal generator while protecting the frequency spectrum of the interpolated data from images. This protection occurs when the data passes through a lowpass filter after zero stuffing. The frequency response of the low pass filter can be changed with the Filter Type property or the `NIFGEN_ATTR_OSP_FIR_FILTER_TYPE` attribute.



Writing I/Q Data

On multichannel devices, I/Q data can either be written to individual channels (for example, designating one channel for I data and one channel for Q data) or to both channels of the device at once when following the multichannel waveform allocation guidelines.

Basic Onboard Signal Processing Properties

The following properties must be configured before you can use the OSP block:

- OSP Mode
- OSP Enabled
- Data Processing Mode
- IQ Rate
- Frequency Shift
- FIR Filter Type

OSP Mode

The OSP Mode property or the `NIFGEN_ATTR_OSP_MODE` attribute specifies the generation mode implemented by the OSP block. The OSP block can operate in IF and Baseband modes. On the NI 5450, the default OSP mode is Baseband generation.

In baseband mode, I/Q data is filtered, interpolated, and scaled in the device OSP. The device generates I data at the CH 0+ and CH 0– differential output terminals and Q data on the CH 1+ and CH 1– differential output terminals.

OSP Enabled

The OSP Enabled property or the `NIFGEN_ATTR_OSP_ENABLED` attribute activates the functionality of the OSP block. To use any of the features in the OSP block, you must enable onboard signal processing by setting this property or attribute.

Data Processing Mode

Data Processing mode determines whether the OSP block uses only the I signal path to generate waveforms or uses the I and Q signal paths to generate complex waveforms. If the waveform data is configured for real data points by setting the Data Processing Mode property or the `NIFGEN_ATTR_OSP_DATA_PROCESSING_MODE` attribute, only the I signal path is used. If the Data Processing Mode property is set to Complex or the `NIFGEN_ATTR_OSP_DATA_PROCESSING_MODE` attribute is set to `NIFGEN_VAL_OSP_COMPLEX`, both the I and Q signal paths are used. Complex waveform data should be downloaded to the signal generator using the niFgen Write Waveform Complex VI or the `niFgen_WriteWaveformComplexf64` function.

IQ Rate

The IQ Rate property or the `NIFGEN_ATTR_OSP_IQ_RATE` attribute defines the rate at which data is processed by the OSP block. If the waveform data is configured for real data points by setting the Data Processing Mode property or the `NIFGEN_ATTR_OSP_DATA_PROCESSING_MODE` attribute, then it is the rate at which each sample from waveform memory is taken from memory and inserted into the OSP block. If the waveform data is configured for complex data points by setting the Data Processing Mode property or the `NIFGEN_ATTR_OSP_DATA_PROCESSING_MODE` attribute, then it is the rate at which each complex sample is taken from memory and inserted into the OSP block.



Note When the onboard signal processing is enabled by setting the OSP Enabled property or the `NIFGEN_ATTR_OSP_ENABLED` attribute, you cannot set the Sample Rate property or the `NIFGEN_ATTR_ARB_SAMPLE_RATE` attribute.

Using an External Clock with the OSP Block

Some applications may require lower jitter or phase noise than is provided by the onboard High-Resolution clock. You can use an external clock source to achieve spectral purity at any arbitrary I/Q rate. To determine the frequency of the sample rate for the external clock source, complete the following steps.

1. Set the Sample Clock Source property or the `NIFGEN_ATTR_SAMPLE_CLOCK_SOURCE` attribute to the external clock source you are using.
2. Set the IQ Rate property or the `NIFGEN_ATTR_OSP_IQ_RATE` attribute.
3. Read the value of the Sample Rate property or the `NIFGEN_ATTR_ARB_SAMPLE_RATE` attribute.
4. Set the external clock source sample rate to the frequency of the Sample Rate property or the `NIFGEN_ATTR_ARB_SAMPLE_RATE` attribute that you just read.
5. Validate that the external Sample clock source is connected to the NI 5450 connector specified in the Sample Clock Source property or the `NIFGEN_ATTR_SAMPLE_CLOCK_SOURCE` attribute and is generating a clock before you continue configuring the NI 5450.

For more information about using external clocks, refer to External Sample Clock Sources.

Frequency Shift

The Frequency Shift property or the `NIFGEN_ATTR_OSP_FREQUENCY_SHIFT` attribute can be used to shift the frequency of a baseband signal. This property can only be used when the OSP mode has been configured for baseband by setting the OSP Mode property or the `NIFGEN_ATTR_OSP_MODE` attribute.

When you are using the NI 5450 with an external I/Q modulator, the Frequency Shift property or the `NIFGEN_ATTR_OSP_FREQUENCY_SHIFT` attribute modifies the baseband I/Q data such that the resulting RF signal is shifted in frequency.



Note When the NI 5450 is configured for single-channel operation in Real data processing mode, you can use the active baseband channel as a direct, frequency-shifted output, in addition to creating RF frequency shifts with an I/Q modulator.

FIR Filter Type

Use the FIR Filter Type property or the `NIFGEN_ATTR_OSP_FIR_FILTER_TYPE` attribute to set the FIR filter type. The following filter types are supported:

- Flat
- Raised Cosine
- Root Raised Cosine

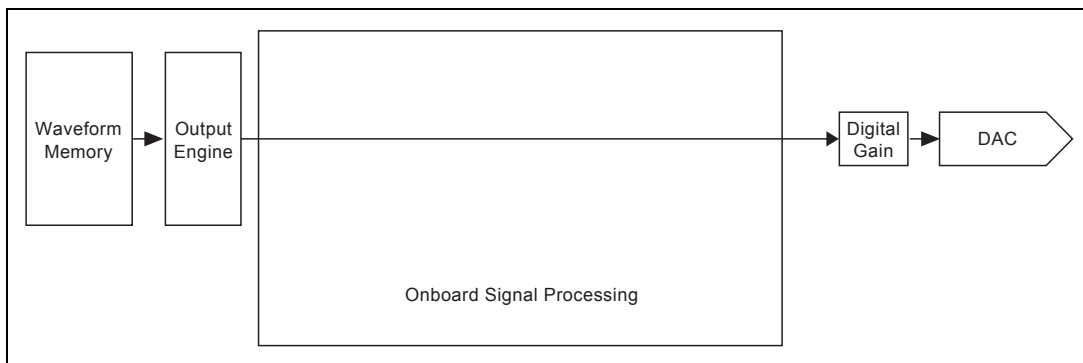
Common Onboard Signal Processing Applications

The OSP block is particularly useful for the following common applications:

- Arbitrary Waveform Generation
- Baseband Interpolation
- Baseband I/Q Interpolation

Arbitrary Waveform Generation

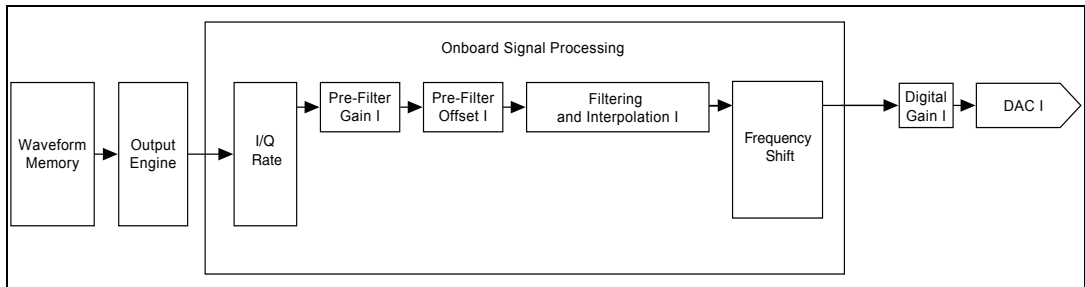
The following figure shows the behavior of the OSP block during arbitrary waveform generation.



For normal arbitrary waveform generation, disable onboard signal processing by setting the OSP Enabled property or the `NIFGEN_ATTR_OSP_ENABLED` attribute.

Baseband Interpolation

The following figure shows the behavior of the OSP block during baseband interpolation.

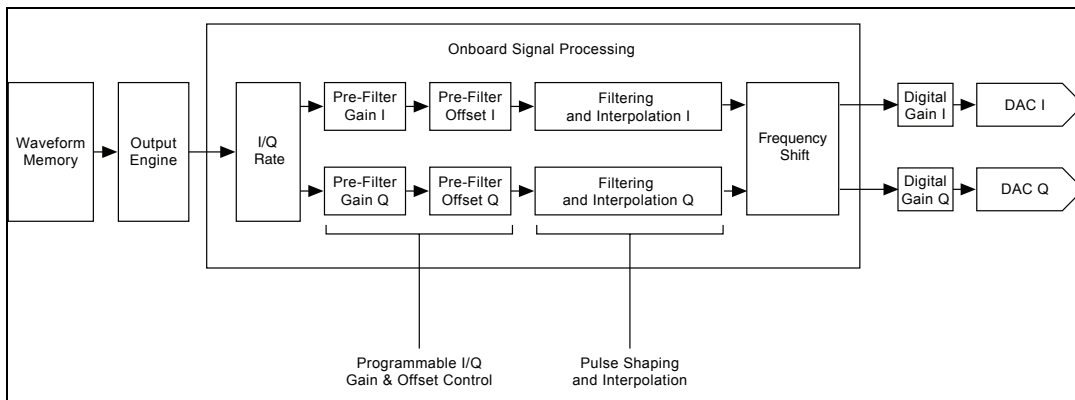


Baseband interpolation allows the OSP block to interpolate signals at a low sample rate up to a high sample rate. Arbitrary pulse shaping of the data can also be done in the FIR filter. For baseband interpolation, complete the following steps.

1. Enable onboard signal processing by setting the OSP Enabled property or the `NIFGEN_ATTR_OSP_ENABLED` attribute.
2. Specify the use of real numbers for the waveform data by setting the Data Processing Mode property or the `NIFGEN_ATTR_OSP_DATA_PROCESSING_MODE` attribute.
3. Set the IQ Rate property or the `NIFGEN_ATTR_OSP_IQ_RATE` attribute to the low sample rate of the waveform data.
4. Set the FIR Filter Type property or the `NIFGEN_ATTR_OSP_FIR_FILTER_TYPE` attribute.
5. Set the corresponding filter parameter.
6. Disable the carrier by setting the Carrier Enabled property or the `NIFGEN_ATTR_OSP_CARRIER_ENABLED` attribute.
7. Download the low sample rate waveform(s) to the signal generator.

Baseband I/Q Interpolation

The following figure shows the behavior of the OSP block during baseband I/Q interpolation.



Baseband I/Q interpolation allows the OSP block to interpolate complex data signals at a low sample rate up to a high sample rate. Arbitrary pulse shaping of the data can also be done in the FIR filter. For baseband I/Q interpolation, complete the following steps.

1. Enable onboard signal processing by setting the OSP Enabled property or the `NIFGEN_ATTR_OSP_ENABLED` attribute.
2. Set the OSP mode to Baseband by calling the OSP Mode property or the `NIFGEN_ATTR_OSP_MODE` attribute.
3. Specify the use of complex numbers for the waveform data by setting the Data Processing Mode property or the `NIFGEN_ATTR_OSP_DATA_PROCESSING_MODE` attribute.
4. Set the IQ Rate property or the `NIFGEN_ATTR_OSP_IQ_RATE` attribute to the low sample rate of the waveform data.
5. Set the FIR Filter Type property or the `NIFGEN_ATTR_OSP_FIR_FILTER_TYPE` attribute.
6. Set the corresponding filter parameter.
7. (Optional) Shift the frequency by calling the Frequency Shift property or the `NIFGEN_ATTR_OSP_FREQUENCY_SHIFT` attribute.
8. Download the low sample rate waveform(s) to the signal generator.
9. Read the sample rate by calling the Sample Rate property or the `NIFGEN_ATTR_ARB_SAMPLE_RATE` attribute.

Baseband Interpolation Considerations

The NI 5450 implements baseband interpolation in order to reduce the power of aliased images. Interpolation is a process that effectively turns a lower sample rate into a higher sample rate. Because the signal is now at a higher sample rate, images are moved to higher frequencies, where they fall in the rejection band of the image rejection filter and are suppressed.

NI-FGEN automatically selects the largest interpolation factor to achieve the maximum possible DAC sample rate. The interpolated sample rate can then be read with the Sample Rate property or the `NIFGEN_ATTR_ARB_SAMPLE_RATE` attribute.



Note For optimum performance, National Instruments recommends maintaining the sample rate between 270 MS/s and 400 MS/s due to the fixed frequency characteristics of the image rejection filter. For more information about the image rejection filter, refer to the NI 5450 specifications.

Interpolation Settings

To determine the total interpolation and interpolated sample rate, divide 400 MS/s by your desired sample rate and round down to the nearest step, as noted in the Interpolation table for your total interpolation value. Then, consult the following table for settings that will allow you to achieve your desired interpolated sample rate.



Note With OSP enabled, Desired Sample Rate (Data Rate) = Symbol Rate × Samples/Symbol.

Example: At a desired sample rate of 4.5 MS/s, the total interpolation will be determined by the following calculations:

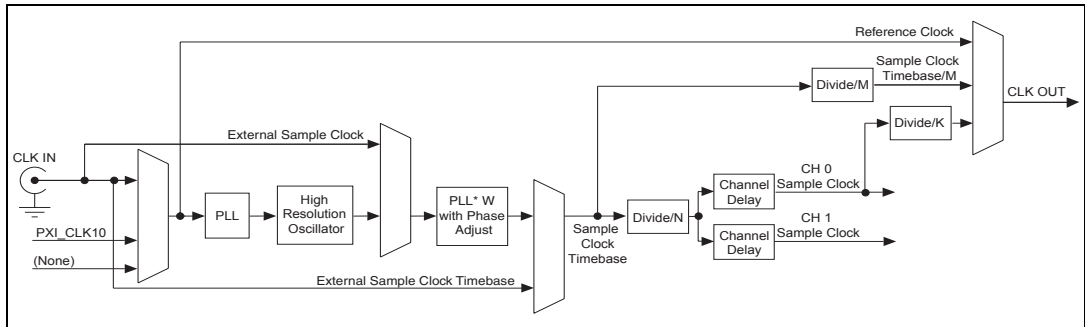
$$400 \text{ MS/s} \div 4.45 \text{ MS/s} = 89.88 \times \text{total interpolation}$$

A total interpolation rate of 89.88× falls in the 24-8192 Total Interpolation range in the Interpolation table. As this range is measured in steps of 8, you must round down to the nearest multiple of 8, yielding a total interpolation rate of 88×. This value corresponds to a sample rate of 391.6 MS/s and a worst case image at or below –100 dB.

Desired Sample Rate (S/s)	I/Q Bandwidth (Hz) 1 Sample /symbol	Total Interpolation	Interpolated Sample Rate* (MS/s)	Theoretical Worst Case Image Feed-through (dB), 20 MS/s Bandwidth Signal	Theoretical Worst Case Image Feed-through [†] (dB), Maximum I/Q Bandwidth
12 to 24 k	4.8 to 9.6 k	16384 to 32768 in steps of 32	370 to 400	N/A	<-100
24 to 48 k	9.6 to 19.2 k	8192 to 16384 in steps of 16	370 to 400	N/A	<-100
48k to 16.66 M	19.2 k to 6.664 M	24 to 8192 in steps of 8	310 to 400	N/A	-100
16.66 to 33.33 M	6.664 to 13.332 M	12 to 24 in steps of 4	300 to 400	N/A	-88
33.33 to 50 M	13.332 to 20 M	8	267 to 400	N/A	-61
50 to 67.5 M	20 to 27 M	4	200 to 270	-31	-23
67.5 to 100 M	27 to 40 M	4	270 to 400	-62	-45
100 to 135 M	40 to 54 M	2	200 to 270	-31	-31
135 to 200 M	54 to 80 M	2	270 to 400	-62	-28
200 to 270 M	80 to 108 M	1	200 to 270	-31	-8
270 to 399 M	108 to 159.6 M	1	270 to 399	-62	-8
400 M	120 M	1	400	-82	-52
<p>Assumptions: Internal Sample clock, High Resolution clock mode. Desired sample rate ranges do not include the first point (a desired sample rate of 50 MS/s yields 8x total interpolation).</p> <p>* If your interpolated sample rate falls within an undesirable band, you can use the Modulation Toolkit to provide fractional resampling that will adjust the sample rate to achieve better image rejection.</p> <p>[†] Calculated from sinc response and typical filter rejection for the NI 5450. Refer to the NI 5450 specifications for more information about the expected performance of the NI 5450.</p>					

Clock Source and Frequency

The NI 5450 has a Sample clock rate of 12.2 kHz to 400 MHz. The timing of the device is very flexible, and you have multiple choices for deriving the Sample clock. There are modes for deriving the Sample clock from the internal Sample clock timebase, as well as modes to provide external clocks. You also have several choices for providing the frequency reference for the onboard phase-locked loop.



Clocking Options

Waveform generation is driven by the Sample clock; depending on your application, some sources may be better choices than others. You can use the following sources for the NI 5450 Sample clock:

- **Internal Sample clock**—the onboard clock is used as the Sample clock source and the Sample clock is derived from the Sample clock timebase.
- **External Sample clock**—the Sample clock has an external source that derives device clocking by directly driving the DAC and all waveform generation operations on the device.
- **Reference clock**—the Sample clock is derived from an external source that is phase-locked to the Sample clock timebase. The phase-locked loop (PLL) Reference clock source specifies the source of the control voltage that tunes the VCXO of the Sample clock timebase for internal clock update sources. The PLL circuit adjusts the Sample clock timebase VCXO to synchronize to a Reference clock. The frequency stability of the Sample clock timebase matches that of the PLL Reference clock when the two are phase-locked. Phase-locking also synchronizes multiple device clocks that are phase-locked to the same Reference clock.

- External Sample clock timebase—the Sample clock timebase has an external source that derives device clocking by directly driving the DAC and all waveform generation operations on the device.

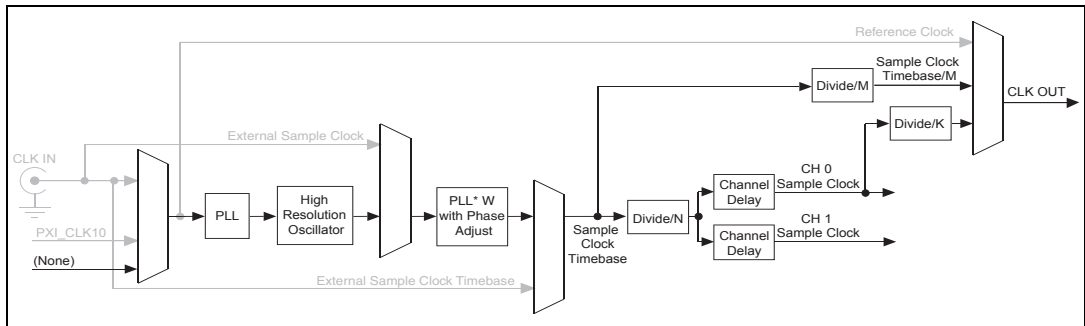
The following table shows the valid NI-FGEN property or attribute value combinations that can be used to configure the clock settings for an internal Sample clock, an external Sample clock, or a Reference clock. The term *Update clock* is synonymous with *Sample clock*.

Sample Clock Source*	Clock Mode*	PLL Reference Clock Source*
“OnboardClk” (default)	NIFGEN_VAL_HIGH_RESOLUTION	“None” (default)
		“PXI_CLK10”
		“ClkIn”
	NIFGEN_VAL_AUTOMATIC (default)	“None” (default)
		“PXI_CLK10”
		“ClkIn”
“ClkIn”	Not Applicable	Not Applicable
* These column headings refer to NI-FGEN properties. The attributes that correspond to these properties are NIFGEN_ATTR_SAMPLE_CLOCK_SOURCE, NIFGEN_ATTR_CLOCK_MODE, and NIFGEN_ATTR_REFERENCE_CLOCK_SOURCE. The values in the columns represent the values that can be set on these properties or attributes. Settings that line up horizontally show valid combinations of the NI-FGEN settings.		

Internal Sample Clock

The NI 5450 can derive a Sample clock from its main internal timing source—the Sample clock timebase. The signal generator provides a high-precision 400 MHz oscillator clock source for the Sample clock timebase.

The following figure shows the NI 5450 internal Sample clock Source path.



The NI 5450 has a high-resolution internal clock. You can change the frequency of this clock by calling the `niFgen Set Sample Rate VI` or the `niFgen_ConfigureSampleRate` function. When you set a desired sample rate, NI-FGEN will internally determine and apply appropriate divide-down factors.



Note The jitter of the High-Resolution clocking mode is frequency-dependent. At low frequencies the jitter increases. Refer to the device specifications for more information about jitter.

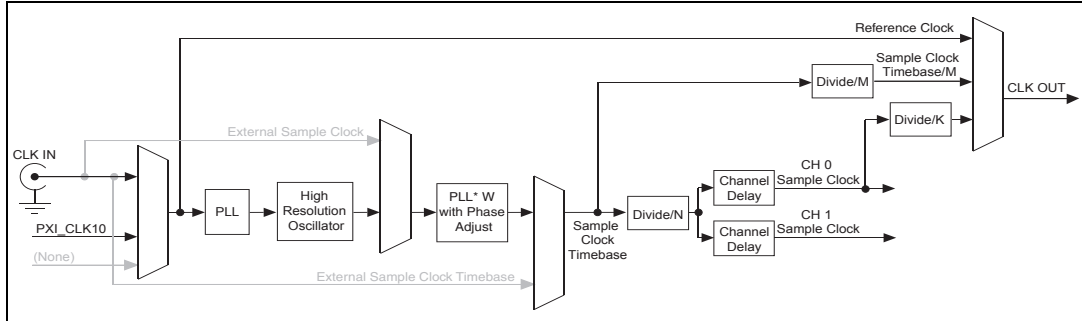
Phase-Locked Loop Reference Clock

A phase-locked loop (PLL) is a circuit that tunes the Sample clock timebase to phase-lock to an external Reference clock. The PLL Reference clock source controls the source of the control voltage that tunes the VCXO of the Sample clock timebase for internal clock update sources. The frequency stability and accuracy of the Sample clock timebase matches that of the Reference clock when they are phase-locked. Using the PLL on your device enables you to frequency-lock multiple devices in a single chassis or devices in separate chassis.



Note Refer to the device specifications for information about the PLL reference frequencies available on your device.

The following figure shows the NI 5450 Reference Clock Source path.



To begin the PLL, the phase comparator compares the selected Reference clock to the 400 MHz clock of the Sample clock timebase. Next, a control voltage proportional to the phase difference between the two clocks is developed and used to tune the Sample clock timebase into alignment with the Reference clock. Finally, the Sample clock timebase output is routed back to the phase comparator, and the loop is closed.



Note When the Reference Clock Source property or the `NIFGEN_ATTR_REFERENCE_CLOCK_SOURCE` attribute is set to “None”; the internal calibration DAC generates the calibration voltage, and the PLL circuit is not used.

Reference Clock Sources

The NI 5450 can phase-lock its Sample clock timebase to an external signal that is present on the CLK IN front panel connector. PXI devices can also phase-lock to a 10 MHz Reference clock signal provided by the PXI bus (PXI_CLK10).

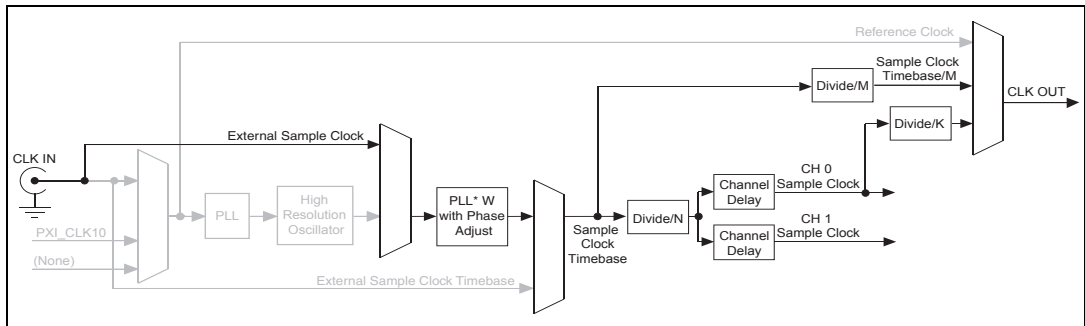


Note Refer to the device specifications for information about available signal levels on the CLK IN front panel connector.

External Sample Clock Sources

The NI 5450 can accept an external clock to directly drive the Sample clock. When using an external Sample clock, the frequency stability and accuracy of the Sample clock is determined by the provided external Sample clock.

The following figure shows possible Sample Clock paths.



You can set the clock source by calling the niFgen Configure Sample Clock Source VI or the niFgen_ConfigureSampleClockSource function.

You can multiply the clock by an integer, W (or 1/W) by calling the External Sample Clock Multiplier property or the NIFGEN_ATTR_EXTERNAL_SAMPLE_CLOCK_MULTIPLIER attribute.

When using an external Sample clock you should configure the Sample clock rate by calling the niFgen Set Sample Rate VI or the niFgen_ConfigureSampleRate function.



Note Refer to the device specifications for the allowable voltages, signal types, and clocks that you can use for all external Sample clocks.

External Sample Clock Considerations

The NI 5450 incorporates high-speed digital clocking technology and requires a stable, free-running Sample clock to operate properly. When the signal generator is committed—either explicitly by calling the niFgen Commit VI or the `niFgen_Commit` function or implicitly by writing waveforms or sequences or initiating a generation—the external Sample clock must be available to the device. If the external clock becomes unstable due to glitching, changing frequency, or is removed entirely, NI-FGEN returns a hardware clocking error.

If necessary, you can change the rate or the source of the external Sample clock between subsequent generations by first calling the niFgen Abort Generation VI or the `niFgen_AbortGeneration` function, changing the rate or source, and then calling the niFgen Commit VI or the `niFgen_Commit` function. NI-FGEN reprograms the NI 5450 for the new settings, and you can call the niFgen Initiate Generation VI or the `niFgen_InitiateGeneration` function to start the next generation.

If you must remove the external Sample clock between generations (after calling the niFgen Abort Generation VI or `niFgen_AbortGeneration` function, but before calling the niFgen Initiate VI or the `niFgen_Init` function), but are not changing the frequency or source of the external clock, you can choose one of the following options:

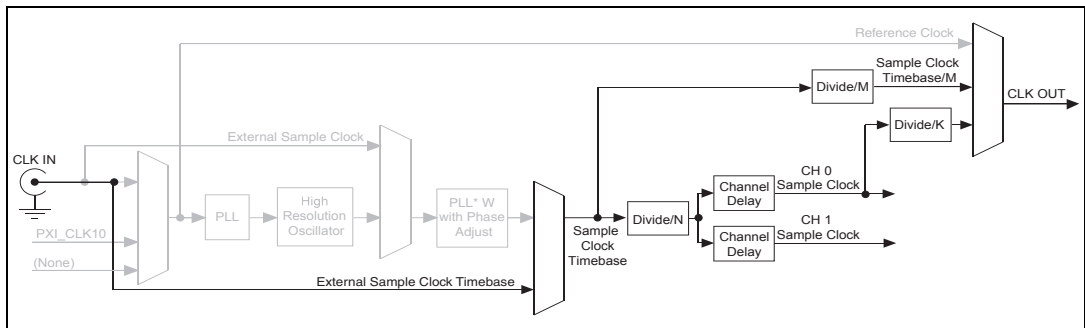
- Call the niFgen Initiate VI or the `niFgen_Init` function, which returns a hardware clocking error because the external Sample clock is gone, then clear the error and call the niFgen Initiate VI or the `niFgen_Init` function again. NI-FGEN then reprograms the hardware to use the external clock again.
- Force the device to be recommitted by changing a property or attribute to another value and then back to its original value. This action causes NI-FGEN to re-commit the settings to hardware, which does not happen otherwise because NI-FGEN does not know that the external Sample clock is gone.



Caution When configuring an external Sample clock, you can set the sample rate to the exact frequency you are using to avoid data errors by calling the niFgen Set Sample Rate VI or the `niFgen_ConfigureSampleRate` function.

External Sample Clock Timebase

The Sample clock timebase has an external source that derives device clocking by directly driving the DAC and all waveform generation operations on the device.



You can set the Sample clock timebase source by calling the Sample Clock Timebase Source property or the `NIFGEN_ATTR_SAMPLE_CLOCK_TIMEBASE_SOURCE` attribute. You can set the Sample clock timebase rate with the Sample Clock Timebase Rate property or the `NIFGEN_ATTR_SAMPLE_CLOCK_TIMEBASE_RATE` attribute.

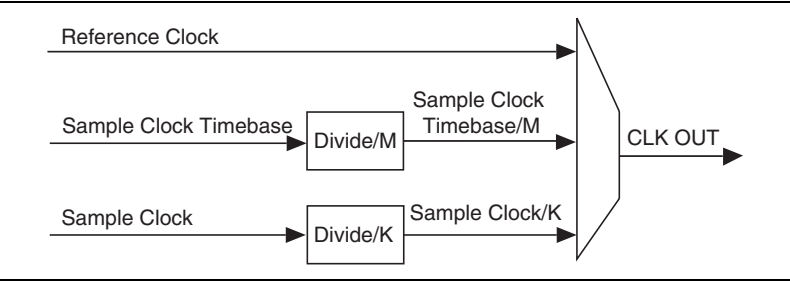
You can export the Sample clock timebase to a terminal configured by the Sample Clock Timebase Export Output Terminal property or the `NIFGEN_ATTR_EXPORTED_SAMPLE_CLOCK_TIMEBASE_OUTPUT_TERMINAL` attribute.



Note Refer to the device specifications for the allowable voltages, signal types, and clocks that you can use for an external Sample clock timebase.

Exporting Clocks

The NI 5450 provides resources for exporting your clocks and multiple destinations for routing.



The following table shows the available clock signals that can be routed to devices external to the signal generator and the destination options.



Note The PFI outputs have a bandwidth of 200 MHz. The PXI Trigger lines have a bandwidth of <20 MHz. The following table shows the software limits of the export destinations.

Clock to be Exported	Destination Options		
	CLK OUT	PFI<0..1>	PXI_Trig<0..6>
Sample Clock/K	$K \geq 1$	$K \geq 2$	$K \geq 2$
SCTB/M	$M \geq 1$	$M \geq 2$	$M \geq 2$
Reference Clock	Always	Always	Always
Note: All divisors have a default value of 1.			

For synchronization purposes, the NI 5450 allows you to export your clocks so that other devices can share the timing of the NI 5450. The following sections describe the possible clock routing configurations.

Sample Clock

The Sample clock can be routed to the CLK OUT front panel SMA connector.

Additionally, the exported clock can be divided down by an integer value (no less than 2) before being exported to the PFI <0..1> connectors, the

CLK OUT connector, or the PXI_Trig<0..6> lines. Refer to the Exported Sample Clock Divisor property or the NIFGEN_ATTR_EXPORTED_SAMPLE_CLOCK_DIVISOR attribute for more information about configuring the Sample clock divisor.

Sample Clock Timebase

The Sample clock timebase can be routed to the CLK OUT front panel SMA connector.

Additionally, the exported clock can be divided down by an integer value before being exported to the PFI <0..1> connectors, the CLK OUT connector, or the PXI_Trig<0..6> lines. You can configure the Sample clock divisor by calling the Exported Sample Clock Timebase Divisor property or the NIFGEN_ATTR_EXPORTED_SAMPLE_CLOCK_TIMEBASE_DIVISOR attribute.

Reference Clock

The Reference clock is the actual clock that is configured for the signal generator phase-locked loop circuit to use as a reference. You configure a Reference clock as a PLL Reference clock source for the signal to be available for exporting. The Reference clock can be routed to the PFI <0..1> front panel SMB connectors, the CLK OUT front panel SMA connector, or the PXI_Trig<0..6> lines on the PXI trigger bus.



Note NI-FGEN allows values for Reference clock frequency on the NI 5450 from 1 to 100 MHz in 1 MHz increments, 102 to 200 MHz in 2 MHz increments, and 204 to 400 MHz in 4 MHz increments.

Destination Options

The following sections define the destinations for exported clocks.

PFI <0..1>—The Sample clock (when $K \geq 2$), the Sample clock timebase (when $M \geq 2$), and the Reference clock can be exported to the PFI 0 and PFI 1 SMB connectors on the front panel to synchronize external devices. You must configure the device to export the desired clock to the PFI SMB connectors.

CLK OUT—The Sample clock, the Sample clock timebase, and the Reference clock can be exported to the CLK OUT SMA connectors on the front panel to synchronize external devices. You must configure the device to export the desired clock to the CLK OUT SMA connector.

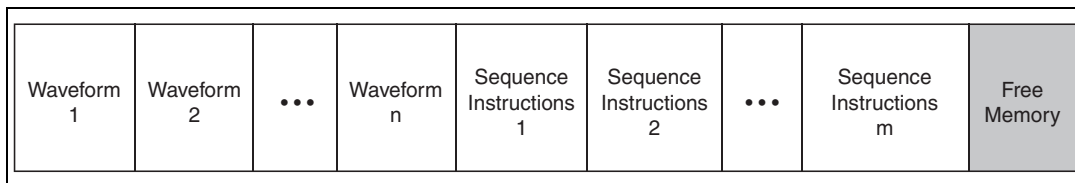
PXI_Trig<0..6>—Sample clock (when $K \geq 2$), the Sample clock timebase (when $M \geq 2$), and the Reference clock can be exported to the PXI_Trig lines. The PXI standards allow for devices to route signals to other devices in your PXI Express chassis to enhance device-to-device synchronization. Refer to the chassis documentation for specifications to ensure the reference signal is within tolerance. You must configure the device to export the desired clock to the PXI_Trig line.

Refer to niFgen Export Signal VI or the `niFgen_ExportSignal` function for more information about configuring the destinations for the desired clock signal.

Onboard Memory

The NI 5450 signal generator uses an onboard memory that is 16-bits wide. The minimum standard memory size for the NI 5450 is 128 MB. With the minimum standard memory size, you can store very long waveforms on the device and obtain reliable waveform generation at full sample rate of 400 MS/s. The NI 5450 also comes with higher memory options of 512 MB or 2 GB.

The onboard memory is a single large memory area per channel that stores both waveforms and sequence instructions to generate the waveforms. The instructions for a complicated sequence can occupy a significant portion of memory. The architecture of the NI 5450 allows you to load multiple waveforms and multiple sequence instructions into the memory. The following diagram illustrates NI 5450 memory allocation. A number of waveforms are stored in the onboard memory ranging from 1 to n ; there are also a number of sequence instructions ranging in number from 1 to m . The values of n and m depend on the waveform and instructions configured and are ultimately limited by the amount of memory.



The following tables list the types of information that are used to make up the instructions that are saved to memory. You can store the instructions for multiple sequences to the onboard memory ahead of time and generate them later, allowing for quick reconfiguration times between tests. There are two example sequences. Sequence 1 represents the instructions for a sequence containing a maximum number of segments k . Sequence m is an example of a sequence containing 8 segments. Each sequence downloads different waveforms to the onboard memory, and uses various looping and Marker placement options to construct the resulting waveform.

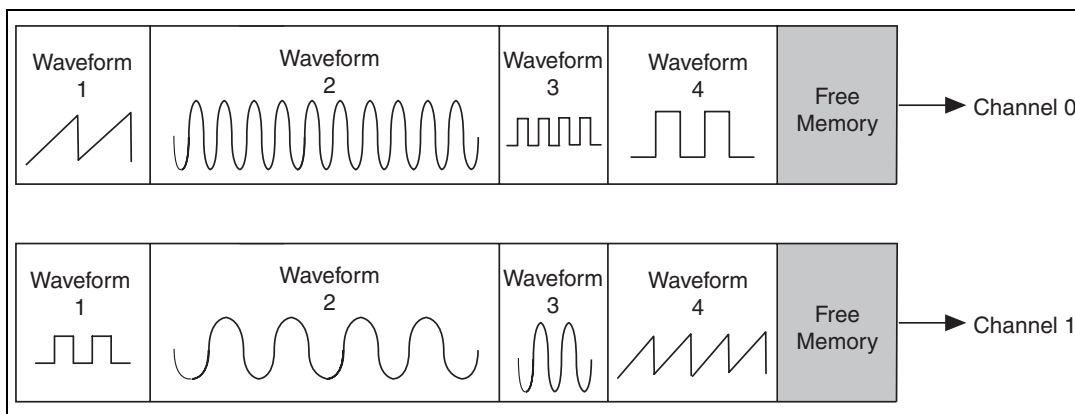
Sequence 1: Burst Trigger Mode			
Sequence Segment	Waveform	Number of Loops	Marker Placement
1	1	1	0
2	5	14	100
3	17	1	-1
4	12	18,045	10,000
5	12	64,000	12
6	34	64,000	0
.....			
k	15	20	10,000

Sequence m : Stepped Trigger Mode			
Sequence Segment	Waveform	Number of Loops	Marker Placement
1	1	1	0
2	2	340	4
3	35	1	-1
4	2	10	0
5	340	5	10,000
6	34	64,000	0
7	20,000	1,000,000	13
8	1	1	0

Onboard Memory for Multichannel Waveform Generation

On multichannel devices, onboard memory is allocated separately for each configured channel. When you write a waveform to the onboard memory of a multichannel device, the space required for the waveform is allocated in the onboard memory for each channel.

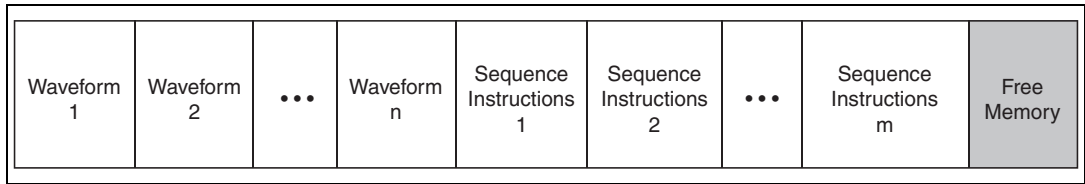
You can write different data to the waveform allocated for each channel, as long as the data written requires the same amount of memory on each channel. For example, Waveform 1 can contain a ramp wave on channel 0 and a square wave on channel 1, as shown in the following figure.



Waveform and Generation Instruction Memory Size

Waveform Memory Size

Waveforms are stored in the NI 5450 onboard memory in contiguous blocks. These blocks are allocated in multiples of 128 bytes. This allocation style means that while waveform sizes may be multiples of two samples (four bytes) on the NI 5450, the amount of onboard memory allocated for each waveform is a multiple of 128 bytes. The following figure represents the total memory of a device and shows memory that was initially empty, but it now has multiple waveforms written to it, nearly filling the device memory.



Calculate the amount of memory that a waveform takes up in the onboard memory with the following two rules.

1. Each sample in the waveform uses two bytes of memory space. Four bytes are used when the onboard signal processing block is enabled and the Data Processing Mode property is set to Complex or the `NIFGEN_ATTR_OSP_DATA_PROCESSING_MODE` is set to `NIFGEN_VAL_OSP_COMPLEX`.
2. Memory is written to in blocks of 4 bytes.

Calculate the memory size by multiplying the number of samples in the waveform by two (or four) and then rounding this value up to the nearest multiple of 128.

Examples

1. A waveform containing 16 samples occupies 32 bytes in memory. By rounding up to the nearest multiple of 128, you can determine that the waveform occupies 128 bytes in memory.
2. A waveform containing 64 samples occupies 128 bytes in memory. By rounding up to the nearest multiple of 128, you can determine that the waveform occupies 128 bytes in memory.
3. A waveform containing 68 samples occupies 136 bytes in memory. By rounding up to the nearest multiple of 128, you can determine that the waveform occupies 256 bytes in memory.
4. A waveform containing 10,000 samples occupies 20,000 bytes in memory. By rounding up to the nearest multiple of 128, you can determine that the waveform occupies 20,096 bytes in memory.
5. A waveform containing 64 complex samples occupies 256 bytes in memory. By rounding up to the nearest multiple of 256, you can determine that the waveform occupies 256 bytes in memory. This example is only possible with the OSP block enabled.

Instruction Memory Size

Instruction Memory Size* Formulae	
Arbitrary Waveform Mode	Size in bytes = 256 per waveform
Arbitrary Sequence Mode†	Stepped: Size in bytes = $208 + (80 \times N)$
	Continuous: Size in bytes = $208 + (64 \times N)$
	Single: Size in bytes = $80 + (64 \times N)$
	Burst: Size in bytes = $160 + (128 \times N)$
<p>* The instruction size in memory is the size, in bytes, rounded up to the nearest multiple of 128 bytes.</p> <p>† N = Number of segments in sequence</p>	

Examples

1. The memory size required to generate a waveform in Arbitrary Waveform mode is always 256 bytes of onboard memory for that specific waveform. Each waveform that is saved to onboard memory uses 256 bytes of memory for instructions.
2. The memory size required to generate a waveform using Arbitrary Sequence mode and Stepped trigger mode with 50 segments in a sequence list is determined by the following formula:
 Size in Bytes = $208 + (80 \times 50) = 4,208$ bytes.
 Size in memory = 4,208 coerced up to the next multiple of 128 = 4,224 bytes.
3. The memory size required to generate a waveform using Arbitrary Sequence mode and Continuous trigger mode with 500 segments in a sequence list is determined by the following formula:
 Size in Bytes = $208 + (64 \times 500) = 32,208$ bytes.
 Size in memory = 32,208 coerced up to the next multiple of 128 = 32,256 bytes.
4. The memory size required to generate a waveform using Arbitrary Sequence mode and Single trigger mode with 1,003 segments in a sequence list is determined by the following formula:
 Size in Bytes = $80 + (64 \times 1,003) = 64,272$ bytes.
 Size in memory = 64,272 coerced up to the next multiple of 128 = 64,284 bytes.

- The memory size required to generate a waveform using Arbitrary Sequence mode and Burst trigger mode with 2345 segments in a sequence list is determined by the following formula:

Size in Bytes = $160 + (128 \times 2,345) = 300,320$ bytes.

Size in memory = 300,320 coerced up to the next multiple of 128 = 300,416 bytes.

Total Memory Size

The following examples show how to calculate total memory for an application. The examples use each of the four trigger modes for the Arbitrary Sequence mode and use varying numbers of waveforms, waveform sizes, and number of segments in the sequences.



Note The following examples only consider the memory used for instructions for one sequence. It is possible to create and save to memory the instructions for as many sequences as the available free memory allows.

Examples

- An application requires using three waveforms with the following sizes: 72; 132; and 260 samples. The waveforms are generated by using Arbitrary Sequence mode and Single trigger mode to configure 20,000 segments in a sequence list. The following tables show all the numbers used to determine the total memory stored in the onboard memory: 1,281,408 bytes.

Waveforms	Samples	Bytes	Rounded Size
A	72	144	256
B	132	264	384
C	260	520	640
Memory Size =			1,280

Number of Segments in Sequence	Memory Calculation	Bytes	Rounded Size
20,000	$80 + (64 \times 20,000) =$	1,280,080	1,280,128

Total Onboard Memory Used = 1,281,408 bytes

2. An application requires using six waveforms with the following sizes: 480; 260; 960; 492; 516; and 604 samples. The waveforms are generated by using Arbitrary Sequence mode and Burst trigger mode to configure 10,000 segments in a sequence list. The following table shows all the numbers used to determine the total memory stored in the onboard memory: 135,296 bytes.

Waveforms	Samples	Bytes	Rounded Size
A	480	960	1,024
B	260	520	640
C	960	1,920	1,920
D	492	984	1,024
E	516	1,032	1,152
F	604	1,208	1,280
Memory Size =			7,040

Number of Segments in Sequence	Memory Calculation	Bytes	Rounded Size
10,000	$160 + (128 \times 10,000) =$	128,160	128,256

Total Onboard Memory Used = 135,296 bytes

3. An application requires using five waveforms with the following sizes: 10,000; 1,000,000; 2,000,000; 30,000,000; and 5,000 samples. The waveforms are generated by using Arbitrary Sequence mode and Stepped trigger mode to configure 2,000 segments in a sequence list. The following table shows all the numbers used to determine the total memory stored in the onboard memory: 66,190,464 bytes.

Waveforms	Samples	Bytes	Rounded Size
A	10,000	20,000	20,096
B	1,000,000	2,000,000	2,000,000
C	2,000,000	4,000,000	4,000,000
D	30,000,000	60,000,000	60,000,000
E	5,000	10,000	10,112
Memory Size =			66,030,208

Number of Segments in Sequence	Memory Calculation	Bytes	Rounded Size
2,000	$208 + (80 \times 2,000) =$	160,208	160,256

Total Onboard Memory Used = 66,190,464 bytes

4. An application requires using seven waveforms with the following sizes: 1,000; 2,000; 2,000; 10,000; 20,000; 500; and 260 samples. The waveforms are generated by using Arbitrary Sequence mode and Continuous trigger mode to configure 100 segments in a sequence list. The following table shows all the numbers used to determine the total memory stored in the onboard memory: 78,720 bytes.

Waveforms	Samples	Bytes	Rounded Size
A	1,000	2,000	2,048
B	2,000	4,000	4,096
C	2,000	4,000	4,096
D	10,000	20,000	20,096
E	20,000	40,000	40,064
F	500	1,000	1,024
G	260	520	640
Memory Size =			72,064

Number of Segments in Sequence	Memory Calculation	Bytes	Rounded Size
100	$208 + (64 \times 100) =$	6,608	6,656

Total Onboard Memory Used = 78,720 bytes

5. An application requires using seven complex waveforms with the following sizes: 500; 1,000; 1,000; 5,000; 10,000; 250; and 130 samples with the OSP block enabled and the Data Processing Mode property set to Complex or the NIFGEN_ATTR_OSP_DATA_PROCESSING_MODE attribute set to NIFGEN_VAL_OSP_COMPLEX. Additionally, the signal generator is configured for Arbitrary Sequence mode and Continuous trigger mode with 100 segments in a sequence list. The following table shows all the numbers used to determine the total memory stored in the onboard memory: 78,720 bytes.

Waveforms	Samples	Bytes	Rounded Size
A	500	2,000	2,048
B	1,000	4,000	4,096
C	1,000	4,000	4,096
D	5,000	20,000	20,096
E	10,000	40,000	40,064
F	250	1,000	1,024
G	130	520	640
Memory Size =			72,064

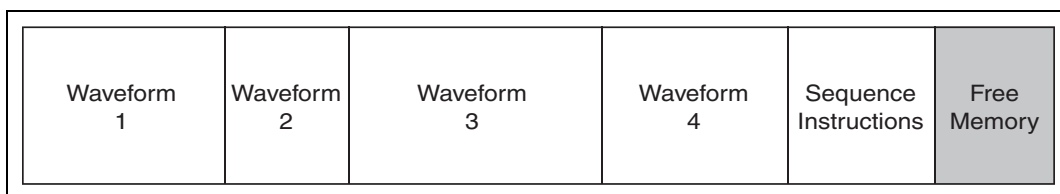
Number of Segments in Sequence	Memory Calculation	Bytes	Rounded Size
100	208 + (64 × 100) =	6,608	6,656

Total Onboard Memory Used = 78,720 bytes

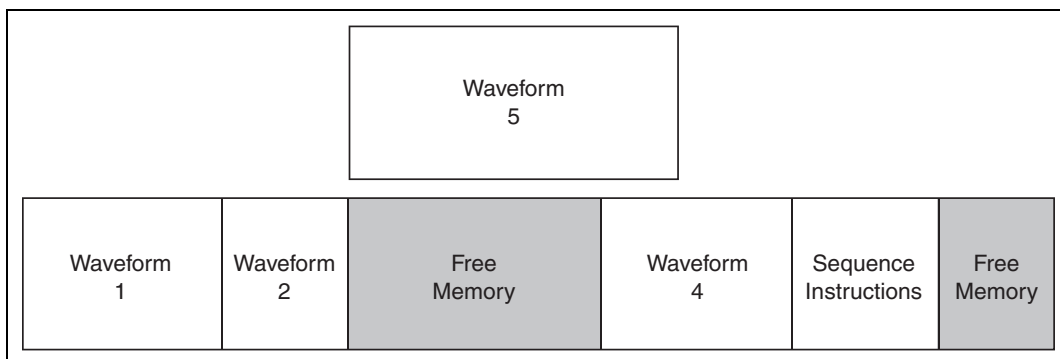
Memory Fragmentation

When storing multiple waveforms in NI 5450 memory, fragmentation can become a problem. Both waveforms and instructions are stored in NI 5450 memory in contiguous blocks. These blocks are allocated in multiples of 128 bytes, and they are written in the order that you configure them. Fragmentation occurs when you delete a waveform or script from memory that was not the last block written.

Every new NI-FGEN session begins with empty memory. First, multiple waveforms are written to memory, nearly filling the device memory, as shown in the following diagram.



If you now try to write Waveform 5 (shown in the following figure) to the device, you find there is not enough memory. To make room for the waveform, you could delete Waveform 3 to create enough space in memory for Waveform 5.



You now have enough free memory space for Waveform 5, but this space is fragmented, so you must also clear and re-download all waveforms and generation instructions following the deleted waveform. The following figure illustrates the result.

Waveform 1	Waveform 2	Waveform 4	Waveform 5	Sequence Instructions	F r e e
---------------	---------------	---------------	---------------	--------------------------	------------------

Signal Routing

An NI signal generator is capable of sending and receiving signals through the front panel and the PXI or RTSI trigger bus. The front panel connectors provides connectivity for the output channel as well as for control lines for sending and receiving clocks, triggers, and events. You can use the PXI and RTSI trigger bus to send and receive events, triggers, and Sample and Reference clocks.

All signal routing operations can be characterized by a *source* and a *destination*. To determine the possible signal routes for your device, complete the following steps.

1. Launch MAX, either by navigating to **Start»All Programs»National Instruments»Measurement & Automation** or by double-clicking the **Measurement & Automation** icon on the desktop.
2. Expand **Devices and Interfaces**. Expand **NI-DAQmx Devices**.



Note If you are using a remote RT target, expand **Remote Systems**, find and expand your target, and then expand **Devices and Interfaces**.

3. Select your device. The view to the right of the MAX configuration tree shows the attributes of your device.
4. Click the **Device Routes** tab below the attributes view. A table in the **Device Routes** view shows the possible sources and destinations for the signal generator. Sources are listed in the far left column, and the possible destinations span the top of the table. Each cell in the table is an index with the valid source and destination terminal for the device.

If a route is possible between a source and destination terminal, the intersecting cell is colored green or yellow. A green cell indicates the route can be made without consuming any important resource of your device. A

yellow cell indicates that although the route is possible, something important must be consumed to create the route. Placing the cursor over a yellow square reveals the resource used in the **subsystem used** indicator.

5. Use the niFgen Export Signal VI or the niFgen_ExportSignal function to route the signals. For terminal name syntax, refer to Syntax for Terminal Names.



Tip You can use the niFgen Export Signal VI or the niFgen_ExportSignal function to route the same signal to multiple destinations.

Syntax for Terminal Names

The syntax for terminal names is a unique identifier that refers to a physical terminal in your system. To guarantee the uniqueness of a terminal name across multiple devices, terminal names begin with a forward slash, followed by the name of the device as configured in MAX, such as Dev1. A forward slash and the name of the terminal follow the device identifier, such as PFI1. For example, the fully qualified terminal name for PFI1 on Dev1 is /Dev1/PFI1.

Waveform Generation

The NI 5450 supports the following output, or generation, modes:

- Arbitrary Waveform
- Arbitrary Sequence
- Script

To select an output mode, set the **Output Mode** parameter of the niFgen Configure Output Mode VI or the niFgen_ConfigureOutputMode function.

Output Modes

The output mode of your signal generator determines the type of waveforms your signal generator produces. To select an output mode, set the **Output Mode** parameter of the niFgen Configure Output Mode VI or the niFgen_ConfigureOutputMode function.

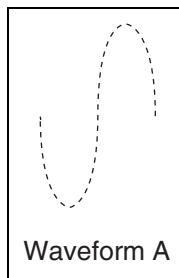
Arbitrary Waveform Mode

The NI 5450 supports Arbitrary Waveform output mode. Arbitrary Waveform mode generates waveforms from user-created/provided waveform arrays of numeric data. The waveform arrays are downloaded to the arbitrary waveform generator onboard memory. Arbitrary Waveform mode also uses memory to store the instructions for generating waveform sequences in the onboard memory.

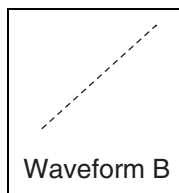
Arbitrary Sequence Mode

Arbitrary Sequence output mode allows you to load multiple waveforms in the onboard memory of the signal generator. A finite number of samples make a waveform. To generate these downloaded waveforms in a specific order, you must prepare a sequence, which contains a number of segments in a specific order. Each segment specifies a downloaded waveform, a number of loops to repeat the selected waveform, and a numeric offset in which a marker is generated by the device. The timing and behavior of the generation of a waveform sequence is dependent on the trigger mode selected.

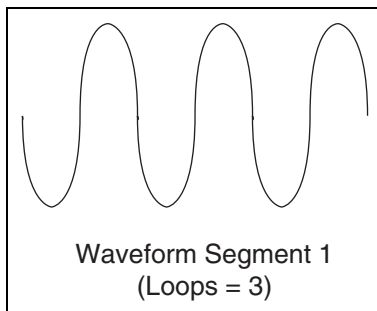
The following figures show the concepts of waveforms and segment sequencing.



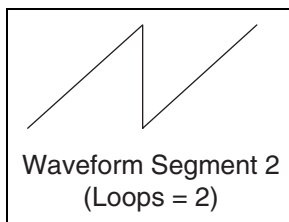
Waveform A represents a single cycle of a sine wave that is downloaded to onboard memory.



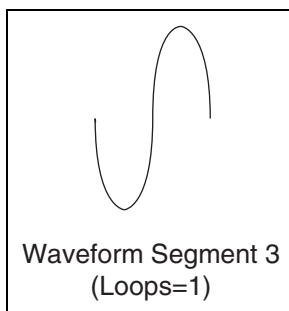
Waveform B represents a single cycle of a ramp waveform that is downloaded to onboard memory.



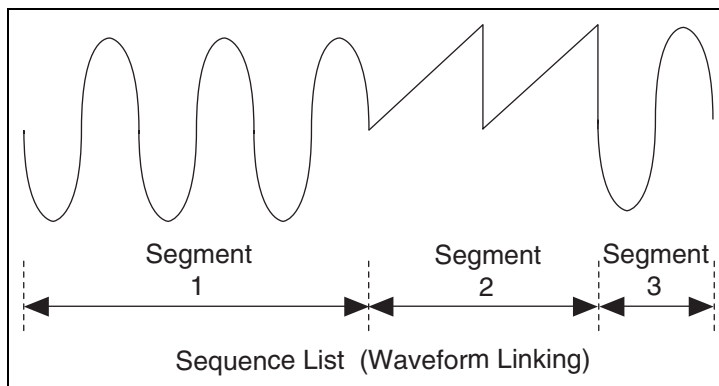
Waveform Segment 1 shows a segment created using Waveform A, repeating, or looping, three times.



Waveform Segment 2 contains Waveform B looping two times.



Waveform Segment 3 contains Waveform A looping only once.



These waveforms are linked in a sequence. The concept of using a sequence to generate waveforms is referred to as “waveform sequencing” or “linking and looping” waveforms.

Segment Components

You create a sequence segment by segment. Each segment is made up of the four components shown in the following table.

Component	Description
Waveform Handle	Specifies the downloaded waveform to be accessed by the segment. A waveform handle is returned for each waveform that is downloaded to the onboard memory. Refer to the niFgen Create Waveform or niFgen Allocate Waveform VIs, or the <code>niFgen_CreateArbWaveform</code> or <code>niFgen_AllocateWaveform</code> functions for more information about downloading waveforms.
Sample Count	Specifies how many samples of a downloaded waveform the segment uses. The sample count may not be the actual size of the downloaded waveform. If the sample count is less than the actual size of the downloaded waveform, only a part of that waveform is used for that segment, starting with the first sample of the waveform. If the count is more than the actual size of that waveform, NI-FGEN sends an error. If the sample count is set to zero, NI-FGEN automatically uses the true size of that waveform.
Waveform loops	Specifies the number of times that the waveform (or portion indicated by sample count of the waveform) loops. The maximum number of loops is 16,777,215.
Marker offset	Specifies where the marker generates within that waveform. The offset is referenced to the beginning of the waveform, with sample 0 being the first sample of the waveform. For more information about markers, refer to Markers.

Script Mode

Script mode allows you to use scripting to link and loop multiple waveforms in complex combinations using a *script*. A script is a series of instructions that indicates how waveforms saved in the onboard memory should be sent to the DUT. The script can specify the order in which the waveforms are generated, the number of times they are generated, and the triggers and markers associated with the generation.

The following are the basic steps you should use to create your script.

1. Call the niFgen Configure Output Mode VI or the `niFgen_ConfigureOutputMode` function to switch to Script mode.

2. Write all waveforms that are referenced in the script by calling the niFgen Write Named Waveform VI or one of the niFgen Write Named Waveform Functions and associate the proper names to them.
3. After your waveforms are written to your device, call the niFgen Write Script VI or the `niFgen_WriteScript` function to write the script(s) containing the generation instructions to be executed.

The script you write can manage waveform generation based on multiple waveforms and triggers. For example, you could download waveforms A, B, C, and D into device memory. You could then write a script that would wait for a trigger to initiate generation and, upon receiving this trigger, generate waveform A three times with a marker at position 16 each time and finally generate waveforms B, C, and D twice (BCDBCD). The following is the script of this example:

```
script myFirstScript
  wait until scriptTrigger0
  repeat 3
    generate waveformA marker0(16)
  end repeat
  repeat 2
    generate waveformB
    generate waveformC
    generate waveformD
  end repeat
end script
```

4. (Optional) You can write multiple scripts that exist simultaneously on your device. If you write multiple scripts to your device, you must select the one you wish to execute by setting the Script to Generate property or the `NIFGEN_ATTR_SCRIPT_TO_GENERATE` attribute.
5. Call the niFgen Initiate Generation VI, or the `niFgen_InitiateGeneration` function to execute the selected script.



Note Internally, the script stores physical device memory locations to refer to named waveforms. Thus, you must write all waveforms to the device *before* writing the script, or the device does not know where the waveform is located. The niFgen Initiate Generation VI or the `niFgen_InitiateGeneration` function produces an error if this rule is violated. If you delete waveforms and rewrite them, rewrite the script to update it with the new locations, even if the script text has not changed.

In some cases at high Sample clocks, your script may result in an underflow error. Underflow errors in a script can be created by waveform size, marker placement, and specific script instructions. To avoid underflow errors, refer to the minimum waveform size in your device specifications.

Aborting Generation

You can abort the generation of the current waveform. Aborting the generation exhibits different behaviors for different waveform output modes.

Sample Size and Resolution

The NI 5450 stores arbitrary waveforms in memory as signed 16-bit digital words. On the NI 5450, the entire 16 bits are sent to the digital gain circuit, the OSP and the DAC.

Waveform Size and Quantum

The NI 5450 onboard memory architecture imposes certain requirements on the waveform size and quantum.

Waveform Size

The minimum waveform size on the NI 5450 depends on the output mode and the trigger mode. Refer to the device specifications for the minimum waveform size values for the different modes.



Note To provide greater programming flexibility, NI-FGEN does not strictly enforce the minimum waveform sizes stated in the device specifications. NI-FGEN enforces a minimum waveform size of four samples for all trigger modes (two if the OSP block is enabled and the waveform data points have been configured for complex data using the Data Processing Mode property or the `NIFGEN_ATTR_OSP_DATA_PROCESSING_MODE` attribute), so it is possible to generate waveforms that are smaller than the sizes given in the specifications. However, the device may not be able to fetch data from onboard memory fast enough to keep up with waveform generation at high sample rates.

This condition may occur if a segment is looping over a very small waveform, if a segment is generating a marker within a very small waveform, or if triggers are advancing the segments in a sequence very rapidly. When this occurs, NI-FGEN reports **Error -1074115901 (0xBFFA4AC3): Device Data Underflow**.

The simplest way to avoid this condition is to follow the minimum waveform size guidelines in the specifications. If these rules are followed, a data underflow error will not

occur under any sample rate. You can develop applications that generate waveforms smaller than those listed in the device specifications at slower sample rates. If a data underflow occurs, NI-FGEN reports the error when the generation is aborted. This is typically accomplished by calling the niFgen Abort Generation VI or the `niFgen_AbortGeneration` function, or if you call the niFgen Wait Until Done, or niFgen Is Done VIs (or the `niFgen_WaitUntilDone` or `niFgen_IsDone` functions) while the device is generating a signal. To monitor error conditions during waveform generation, the niFgen Is Done VI or the `niFgen_IsDone` function can be called repeatedly while the device is generating a signal.

The maximum waveform size allowed depends on the remaining available space in the onboard memory of the device. The remaining available space depends on factors such as any waveforms and generation instructions currently occupying memory space in the onboard memory. The maximum allowable size equals the memory size of the device minus the data already in memory. Query the Max Waveform Size property or the `NIFGEN_ATTR_MAX_WAVEFORM_SIZE` attribute for the current largest size waveform that can be downloaded to the device.

You can download floating point, signed 16-bit binary, or complex floating-point waveforms to the device onboard memory. For information about downloading waveforms to the onboard memory in LabVIEW, refer to the niFgen Create Waveform or niFgen Write Waveform VIs for more information. For information about downloading waveforms to the onboard memory in C, refer to the `niFgen_CreateWaveformF64`, `niFgen_CreateWaveformI16`, `niFgen_CreateWaveformComplexF64`, `niFgen_WriteWaveform`, `niFgen_WriteBinary16Waveform`, or `niFgen_WriteWaveformComplexF64` functions for more information.

Waveform Quantum

Quantum is the increment in samples that waveform sizes must adhere to. The NI 5450 has a sample quantum of two, allowing waveforms of any even numbered size (between the maximum and minimum waveform sizes) to be downloaded.

For example, if while in Arbitrary Waveform mode, you request to load a waveform of seven samples, the task will not complete successfully because the waveform is not an integer multiple of the quantum size. Waveform sizes that meet the conditions include 2, 4, 8, 10, 12, and so on, up to maximum allowable waveform size.

Streaming

Streaming is a way to generate waveforms that are too large to fit in the onboard memory of the signal generator. Streaming can be used in Arbitrary Waveform, Arbitrary Sequence, or Script output modes.

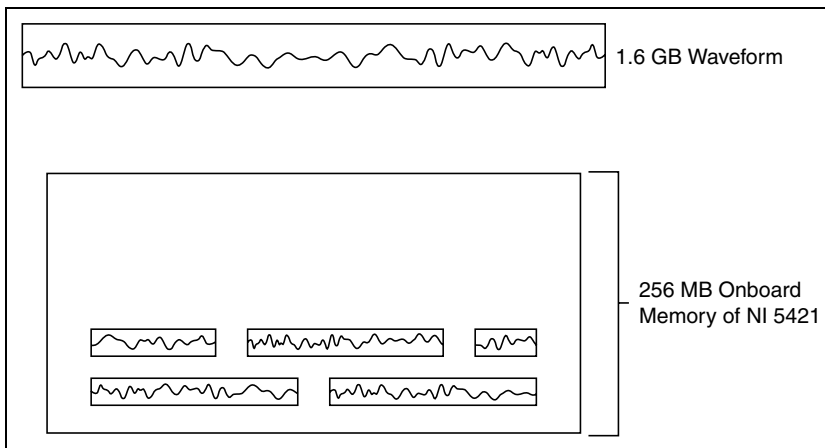
To stream waveform data, allocate and identify all or a portion of the signal generator onboard memory to act as an onboard waveform for streaming. Before initiating waveform generation, fill that onboard memory with the first part of your waveform. As the waveform is generated, space in the onboard memory becomes free and fill that space with new waveform data. Repeat the process of filling the freed onboard memory in blocks of new waveform data until the waveform is complete.

Streaming Waveform Data

The following instructions are a guide for configuring your application for streaming. For a programmatic example, refer to

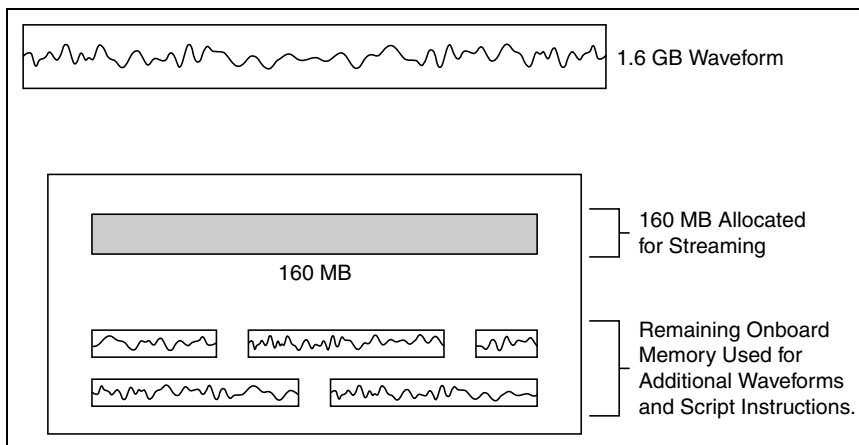
`Fgen Arb Waveform Streaming.vi` for LabVIEW or
`ArbitraryWaveformStreaming.prj` for LabWindows/CVI.

As an example, we have a 1.6 GB waveform we want to generate and an NI arbitrary waveform generator with 256 MB of onboard memory. This 1.6 GB waveform may be in the host memory, on disk, or data that your application generates dynamically during generation.

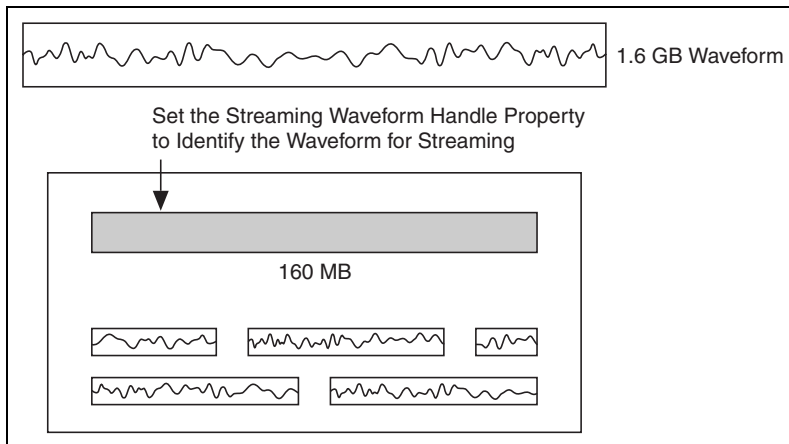


1. **Specify the amount of onboard memory to be used for streaming**—Call the `niFgen Allocate Waveform VI` or the `niFgen_AllocateWaveform` function to specify the amount of onboard memory to reserve for streaming. The allocated memory, known as the *streaming waveform*, serves as a buffer for the streaming

process. The size of the waveform you wish to stream must be evenly divisible by the amount of onboard memory allocated for streaming to prevent the streaming waveform from being overwritten before it has generated.



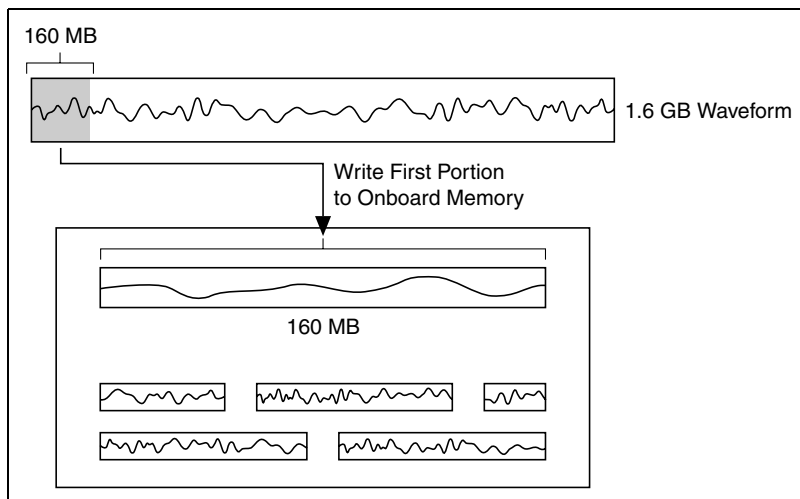
2. **Identify the streaming waveform**—Set the Streaming Waveform Handle property or the `NIFGEN_ATTR_STREAMING_WAVEFORM_HANDLE` attribute to the waveform handle returned in step 1. Setting this property or attribute ensures that none of your streaming data is overwritten before it is generated. NI-FGEN monitors your progress to ensure that you write fresh data fast enough to keep up with the generation. If your application fails to keep up or attempts to write fresh data over data that has not been generated, NI-FGEN returns an error.



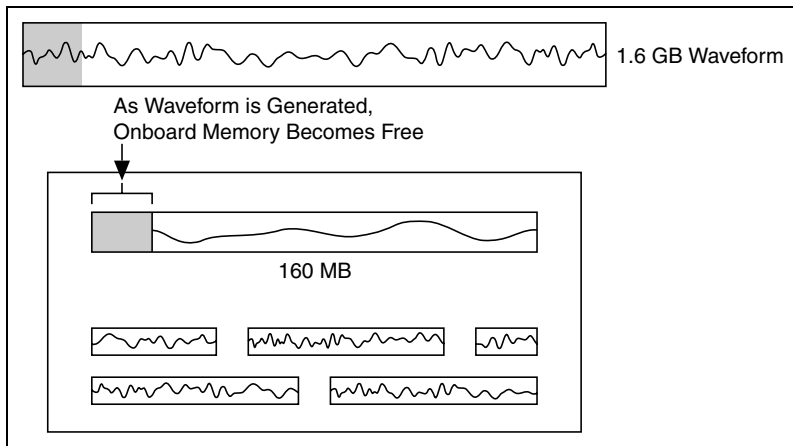
3. **Fill the streaming waveform with initial data**—Call the niFgen Write Waveform VI or the niFgen_WriteWaveform function to write the first part of the waveform data to the streaming waveform in onboard memory.



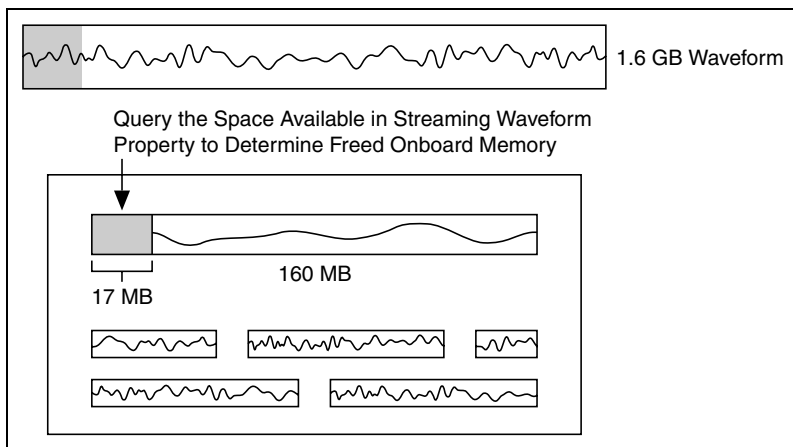
Tip When transferring large blocks of waveform data, break the data into smaller blocks and call the niFgen Write Waveform VI or the niFgen_WriteWaveform function multiple times. The data is appended sequentially. A computer can allocate smaller blocks of a large waveform faster than allocating a single large contiguous block in memory. Depending on the amount of RAM on the computer, transferring ten 16 MB blocks may be faster than transferring one 160 MB block.



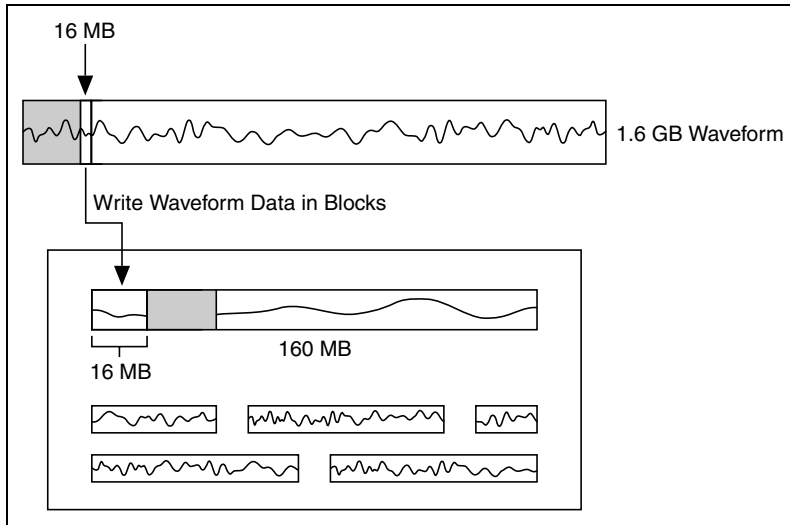
4. **Begin generating the waveform**—Call the niFgen Initiate Generation VI or the niFgen_InitiateGeneration function to begin the waveform generation. As the waveform generates, space in the streaming waveform becomes free.



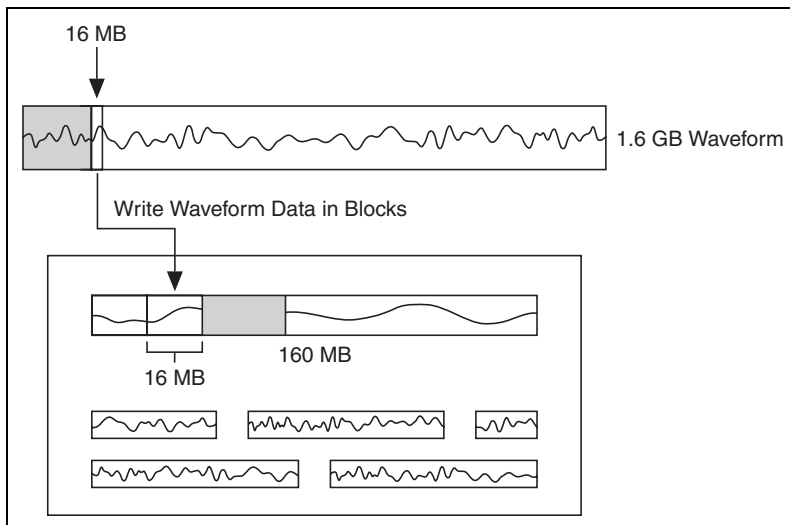
5. **Monitor available memory as the waveform generates**—Use the Space Available in Streaming Waveform property or the NIFGEN_ATTR_STREAMING_SPACE_AVAILABLE_IN_WAVEFORM attribute to determine how much of the streaming waveform is free for writing new data. As the waveform generates, space becomes available to write more waveform data. After a certain amount, say 10 percent, of the allocated onboard memory becomes available, you can write a block of waveform data to the streaming waveform in onboard memory.



6. **Write a block of waveform data**—Call niFgen Write Waveform VI or the niFgen_WriteWaveform function to write a new block of waveform data to the streaming waveform in onboard memory.



7. Repeat steps 5 and 6 as free space becomes available.



Streaming to Multiple Channels

To stream data to multiple channels, you must provide data that is interleaved. For example, to stream I16 data to two channels, you must interleave channel 0 and channel 1 samples, so the first sample will go to channel 0, the second to channel 1, the third to channel 0, and so on. You cannot stream to two or more channels with individual, non-interleaved writes for each channel.

Average Performance Rates

The following tables list the average data rates possible for PXI, PCI, and PXI Express signal generators. Average data transfer rates are highly system dependent. The following table is intended to give you an idea of the average sustainable transfer rates using 16-bit (or 2 byte) samples.

PXI and PCI

Data Source	Data Rate (MB/s)*
Host memory on desktop computer or PXI embedded controller	~90 to 115
Desktop IDE or SATA hard drive	~55 to 70 †
Laptop or low RPM hard drive	25 to 30 †
Host memory on desktop across MXI-3 to PXI board	25
Host memory on desktop across MXI-4 to PXI board	25
* All data rates highly dependent on chipset. † Measurements were taken using the Windows API for unbuffered file I/O.	

PXI Express

Data Source	Data Rate (MB/s)*
Host memory on desktop computer or PXI embedded controller	~524
Desktop IDE or SATA hard drive	~310
* All data rates highly dependant on chipset. † These numbers were obtained using several file I/O optimizations.	

Improving Streaming Performance

To improve your maximum sustainable transfer rate for streaming, consider the following recommendations:

- Adjust the Data Transfer Block Size property or the `NIFGEN_ATTR_DATA_TRANSFER_BLOCK_SIZE` attribute. The default data transfer block size for NI-FGEN is 2 MS (or 4 MB). If you were to write a 16 MB waveform to the signal generator, the complete transfer would occur using four separate DMA transfers. If you modify the data transfer block size to 8 MS (16 MB), for example, the data transfer is more efficient and is instead accomplished in a single transfer.
- Configure advanced streaming properties by calling the Maximum In-Flight Read Requests, PCI DMA Optimization Enabled, or Preferred Packet Size property or the `NIFGEN_ATTR_DATA_TRANSFER_MAXIMUM_IN_FLIGHT_READS`, `NIFGEN_ATTR_DATA_TRANSFER_PCI_DMA_OPTIMIZATIONS`, or `NIFGEN_ATTR_DATA_TRANSFER_PREFERRED_PACKET_SIZE` attributes.
- Optimize the bus bandwidth usage for multi-device streaming applications by calling the Maximum Bandwidth property or the `NIFGEN_ATTR_DATA_TRANSFER_MAXIMUM_BANDWIDTH` attribute.
- When streaming from hard drives, consider the hard drive speed for maximum sustainable rates. Laptop hard drives typically have a data transfer rate of 25 to 30 MB/s. Desktop hard drives often can meet 55 to 70 MB/s.

Transfer rates from hard drives can vary for a number of reasons, including where the data is physically stored on the hard drive and how much data is stored. Storing your waveform files on a fairly empty, defragmented hard drive may help increase performance.

- Consider using a redundant array of independent disks (RAID) configuration to utilize striping to increase data transfer rates from disk.
- When using 18-slot PXI chassis, install the signal generator used for streaming in the first segment (Slots 2 to 6) of the PXI chassis.
- Utilize Direct DMA.

PXI Express Bandwidth Considerations

National Instruments PXI Express signal generators use PCI Express as the interface to the computer. The physical connection between a PXI Express signal generator and a computer is called a *PCI Express link*. When a signal generator generates a waveform, it can saturate this link. Saturation occurs when the signal generator is copying data to its onboard memory from computer memory as rapidly as possible, utilizing all of the bandwidth of the PCI Express link.

The theoretical bandwidth of the onboard memory of the signal generator is 3.2 GB/s, and the theoretical bandwidth of the PCIe link is approximately 850 MB/s. This difference in bandwidths means that transferring data to the onboard memory can saturate the PCI Express link. The waveform data download rate is dependent on the system configuration, with a maximum of approximately 600 MB/s.

High-speed transfers that saturate the PCI Express link can affect other devices when multiple devices share a single PCI Express link. For example, if an NI PXI Express signal generator is installed in slot 9 of an NI PXIe-1065 chassis controlled by an NI PXIe-8130 controller, the signal generator will share bandwidth with any devices installed in Slots 10 through 14. This bandwidth sharing becomes a problem if other devices in the application require guaranteed bandwidth to the PCI Express bus.

You can configure the NI PXI Express signal generator to limit its use of the PCI Express bus, leaving bandwidth for other devices that are more susceptible to short-term bursts of traffic on a shared PCI Express link. You may also be able improve the performance of your device based on your system configuration. The following table lists the properties and attributes that allow you to modify the way that the signal generator uses the PXI Express bus.

LabVIEW Property	C/C++ Attribute	Purpose
Maximum Bandwidth	NIFGEN_ATTR_DATA_TRANSFER_MAXIMUM_BANDWIDTH	Allows you to optimize bus bandwidth usage for multi-device streaming applications.

LabVIEW Property	C/C++ Attribute	Purpose
Maximum In-Flight Read Requests	NIFGEN_ATTR_DATA_TRANSFER_MAXIMUM_IN_FLIGHT_READ_REQUESTS	Allows you to specify, based on the requirements of your application, the maximum number of in-flight read requests for data transfers.
Preferred Packet Size	NIFGEN_ATTR_DATA_TRANSFER_PREFERRED_PACKET_SIZE	Allows you to configure, based on the requirements of your system, the preferred size of the data field in the PCI Express data transfer packet.

Triggering

Triggers are signals that cause the signal generator to perform an action such as starting or stopping a generation operation. Triggers can be internal (software-generated) or external. External digital triggers can be several different types. External triggers can be re-exported and, along with events, can allow you to synchronize the hardware operation with external circuitry or other NI devices.

When triggering your NI signal generator, you can select the type of trigger, the trigger source, and the trigger mode that you want to use.

Triggers Summary

The following table describes the triggers supported by signal generators. The *Supported Types* column denotes which trigger types are valid for a given trigger.

Trigger Name	Supported Types	Description
Start	Digital Edge, Software	The Start trigger transitions a device from an idle state to a generation state where the device can respond to Sample clocks.
Script	Digital Edge, Digital Level, Software	The Script trigger is a general-purpose trigger with a role that is entirely determined by the context of the generation script. A script allows you to create sophisticated generation operations. For example, the script could configure the device to generate waveform A, then wait for the Script trigger, then generate waveform B. You can create multiple Script triggers for use in your application. Once a digital edge Script trigger has been received, that trigger remains true for all subsequent instructions until the clear instruction is called or the trigger is reset after being used in the wait, repeat/end repeat, or if instructions.

Types of Triggers

A trigger is an external stimulus that initiates one or more device functions. Trigger stimuli include digital edges, software functions, and analog levels.

You can trigger your NI signal generator with one of the following types of triggers:

- Edge
- Level
- Software

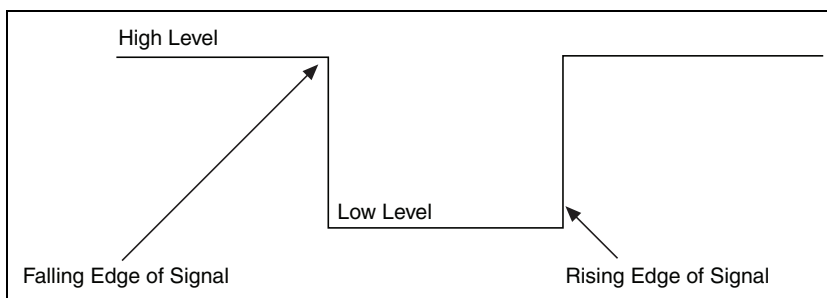


Note Individual triggers may not support all the trigger types listed here.

Edge Trigger

A digital signal has two discrete levels: a high level and a low level. When the signal transitions from high to low or from low to high, a *digital edge* is created. There are two types of edges: rising, which occurs when the signal transitions from low level to high level, and falling, which occurs with a transition from high level to low level. Triggers configured to act on a rising or falling edge of a digital signal are called *edge triggers*.

As the following figure shows, an edge trigger could be configured to occur either at the place labeled *Falling Edge of Signal* or at *Rising Edge of Signal*.



Level Trigger

You can configure certain triggers to act when a signal goes below the defined low level or above the defined high level. Triggers configured to act in this way are known as *level triggers*. Not all triggers can be configured to be level triggers.

Software Trigger

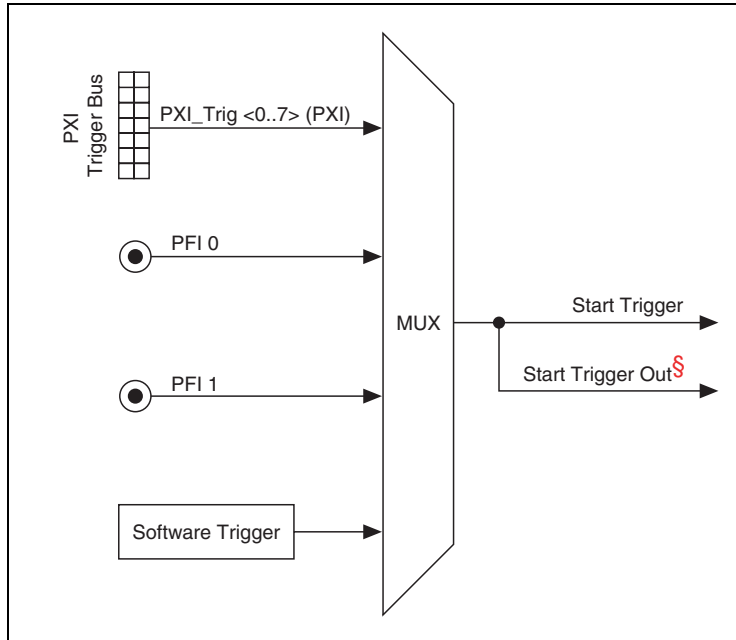
A software trigger is generated internally by a programmatic call to the `niFgen Send Software Edge Trigger VI` or the `niFgen_SendSoftwareEdgeTrigger` function and can occur at any time, based upon the conditions specified in the program.

Trigger Sources

Trigger sources are software selectable. You can use any of the following external input triggers:

- PFI 0 or PFI 1 on the front panel connectors
- PXI_TRIG<0..7> lines on the PXI trigger bus backplane

The following figure shows the possible trigger sources for the NI 5450.



§ Refer to Exporting Signals for more information routing signals.

All triggers are ignored until you call the `niFgen Initiate Generation VI` or the `niFgen_InitiateGeneration` function.

The default trigger source for NI-FGEN is Immediate, which causes an automatic Start trigger pulse to be generated internally as soon as hardware can generate signals after generation has been initiated. You can configure the trigger source with `niFgen Configure Trigger VI` or the `niFgen_ConfigureTriggerSource` function. Refer to the `niFgen Send Software Edge Trigger VI` or the `niFgen_SendSoftwareEdgeTrigger` function for more information about programmatically triggering the device.

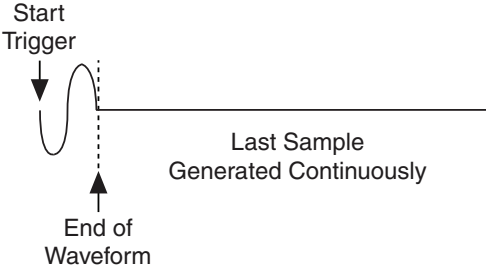
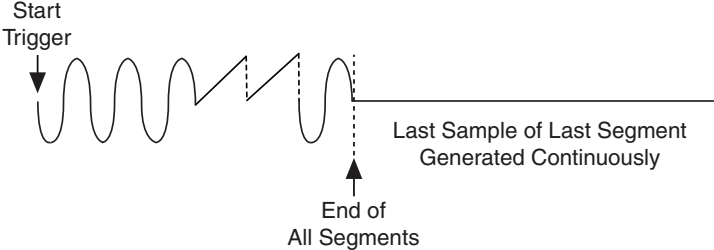
Refer to the device specifications for the minimum Start trigger pulse width required for operation.

Trigger Modes

The NI 5450 has four trigger modes: Single, Continuous, Stepped, and Burst. These trigger modes are available for Arbitrary Waveform, and Arbitrary Sequence output modes.

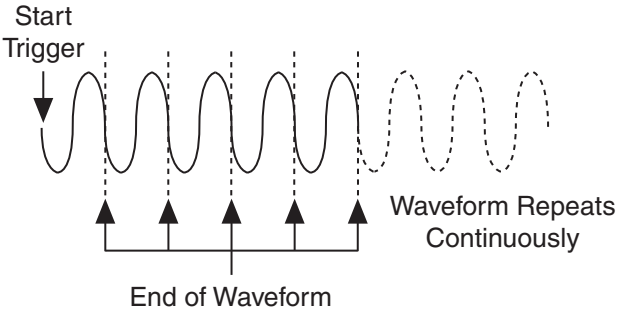
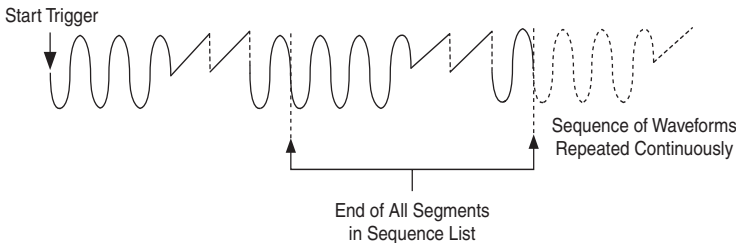
Single Trigger Mode

When your application is configured for Single trigger mode, only one Start trigger is required to begin waveform generation. All Start triggers after the first Start trigger are ignored. Once the waveform generation is complete, the analog output indefinitely settles at the DC value of the last sample in the waveform. The following table provides more information about waveform generation behavior in Arbitrary Waveform and Arbitrary Sequence output modes.

Output Mode	Trigger Behavior
Arbitrary Waveform Mode	<p>The waveform you downloaded generates only once and waveform generation halts, unless the Arbitrary Waveform Repeat Count property or the <code>NIFGEN_ATTR_ARB_REPEAT_COUNT</code> attribute is set, in which case the waveform generates the specified number of times.</p> 
Arbitrary Sequence Mode	<p>The waveform pattern you define in the sequence list generates only once. When a Start trigger is received, generation begins at the first segment and continues through the last segment, after which the waveform generation halts. You can determine the DC value at which waveform generation ends by configuring the last point in the final segment as the desired DC value, or you can add an extra segment filled with the same DC value.</p> 

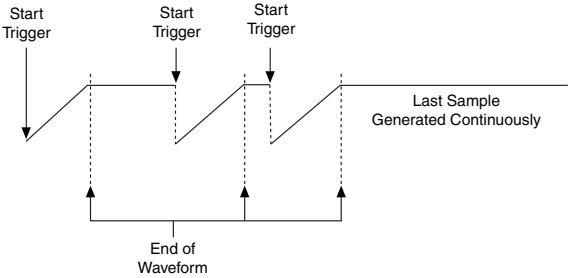
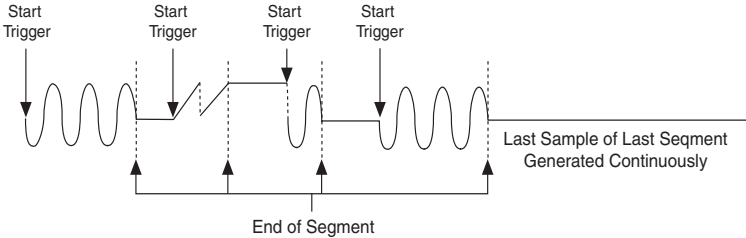
Continuous Trigger Mode

The waveform you downloaded generates continuously after receiving one Start trigger. All Start triggers after the first Start trigger are ignored. The following table provides more information about waveform generation behavior in Arbitrary Waveform and Arbitrary Sequence output modes.

Output Mode	Trigger Behavior
Arbitrary Waveform Mode	<p>The waveform you downloaded generates continuously after receiving one Start trigger. All Start triggers after the first Start trigger are ignored.</p>  <p>The diagram shows a solid sine wave starting at a point labeled 'Start Trigger' with a downward arrow. The wave continues for several cycles, then transitions into a dashed sine wave. Below the solid wave, four upward arrows point to the peaks of the cycles, with a bracket underneath labeled 'End of Waveform'. To the right of the dashed wave, the text 'Waveform Repeats Continuously' is displayed.</p>
Arbitrary Sequence Mode	<p>The waveform pattern you define in the sequence list generates continuously by continually cycling through the sequence list. Only one Start trigger is required to start waveform generation. After the device receives a Start trigger, the waveform generation starts at the first segment and continues through the last segment, and then loops back to the start of the first segment, continuing indefinitely. All Start triggers after the first Start trigger that starts waveform generation are ignored.</p>  <p>The diagram shows a sequence of different waveform segments: a sine wave, a sawtooth wave, and another sine wave. It starts at a point labeled 'Start Trigger' with a downward arrow. The segments are connected by dashed lines, indicating a continuous sequence. At the end of the last segment, a bracket points to the text 'End of All Segments in Sequence List'. The sequence then loops back to the beginning of the first segment. To the right, the text 'Sequence of Waveforms Repeated Continuously' is displayed.</p>

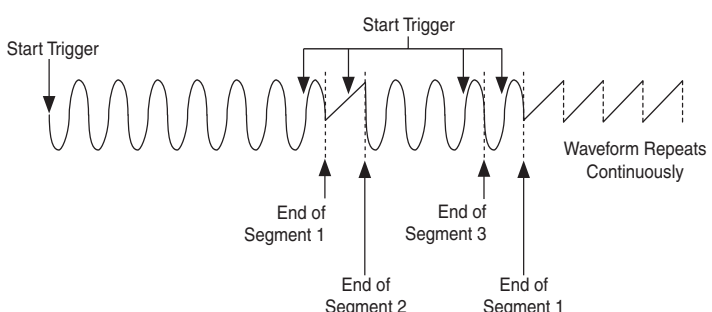
Stepped Trigger Mode

The waveform you downloaded generates each time a Start trigger occurs. After a waveform finishes generating, the last sample of the waveform repeats continuously until the next Start trigger is received. When the next Start trigger is received, the waveform generates again. If a Start trigger is received while a waveform is generating, the Start trigger is ignored and another Start trigger is required to regenerate the waveform after the last sample generates. The following table provides more information about waveform generation behavior in Arbitrary Waveform and Arbitrary Sequence output modes.

Output Mode	Trigger Behavior
Arbitrary Waveform Mode	<p>If the Arbitrary Waveform Repeat Count property or the NIFGEN_ATTR_ARB_REPEAT_COUNT attribute is set, the waveform generates the specified number of times instead of just once.</p> 
Arbitrary Sequence Mode	<p>The waveforms you define in the sequence list generate one segment at a time, each time a Start trigger occurs. The waveform loops as many times as has been configured for that particular segment. After the generation of a segment has halted, the last sample of the waveform repeats continuously until the next Start trigger is received. After the sequence list is exhausted, the waveform generation returns to the first segment and subsequent Start triggers restart the process.</p> 

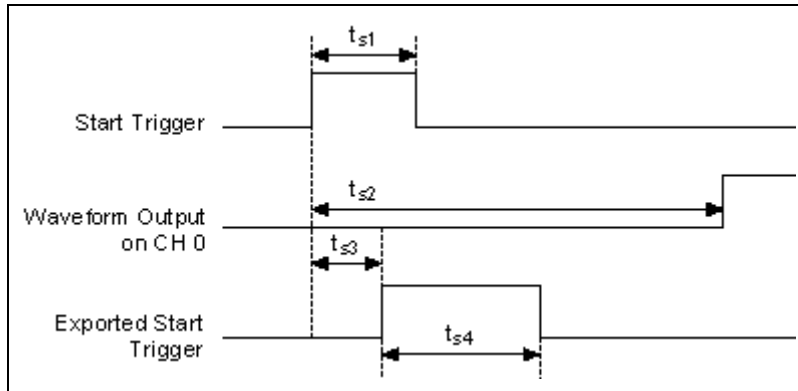
Burst Trigger Mode

In Burst trigger mode, calling the first Start trigger begins waveform generation. The waveform then generates continually. The following table provides more information about waveform generation behavior in Arbitrary Waveform and Arbitrary Sequence output modes.

Output Mode	Trigger Behavior
Arbitrary Waveform Mode	Burst trigger mode operates the same as Continuous trigger mode when the device is operating in Arbitrary Waveform mode.
Arbitrary Sequence Mode	<p>Each waveform you define in the sequence list generates continuously until another Start trigger occurs. A Start trigger causes the waveform generation to switch to the waveform defined by the next segment, after the current waveform finishes. After the sequence list is exhausted, the waveform generation returns to the waveform defined by the first segment and subsequent Start triggers will restart the process. Only the first Start trigger which signals a transition to the next segment is recognized, all subsequent Start triggers are ignored until the currently generating waveform finishes. The transition of one waveform to the next can be made amplitude continuous if waveforms in all segments start and end at the same amplitude. Alternatively, this also can be accomplished by ensuring that the waveforms from one segment to the next end and start at the same amplitude. This amplitude continuous transition is shown in the previous Arbitrary Sequence Mode examples by the transitions of Segments 1 to Segment 2, and Segment 3 to Segment 4. The transition from Segment 2 to Segment 3 shows a discontinuous transition, going from a positive value on the last sample of the ramp waveform right to a midrange value of the sine waveform.</p> 

Trigger Timing

The following figure shows the relationship between Start trigger and the waveform output. t_{s1} is the required pulse width on the Start trigger signal. t_{s2} is the delay from the Start trigger to the waveform output. Refer to the NI 5450 specifications for more information about these timing parameters.



The NI 5450 also allows you to export signals to trigger other devices based on the waveform output of the signal generator. The exported Start trigger Marker event can be exported from the signal generator to signal other devices that waveform generation has started. NI-FGEN refers to the exported Start trigger as the Out Start trigger.

The exported Start Trigger event is a slightly delayed version of the Start trigger used for waveform generation. It is guaranteed to be at least 150 ns wide. The preceding figure also shows the relationship between Start trigger and the exported Start trigger. t_{s3} is the delay between the Start trigger and the time the device generates the exported Start trigger. t_{s4} is the pulse width of the exported Start trigger signal.

Filtering Effects

The delay from the time at which the device receives a trigger to the time at which the analog output signal is generated increases if the digital and/or analog filters in the Analog Output path are enabled. In the case of digital filtering, delay also increases with increase in interpolation. Enabling the onboard signal processing block can also introduce delay.



Note The digital filter for the signal generator is inside the FPGA, before the Analog Output path.

Data Mask

The signal generator supports analog data masks and static values. The data mask allows you to shield bits of the data to be replaced with the corresponding static value bits. For example, a mask of 0xFF00 and a static value of 0xAAAA applied to a DC waveform with a value of 0x1111 produces a DC waveform with a value of 0x11AA.

NI-FGEN supports separate and independent analog and digital data masks and static values. The analog data mask and analog static value apply to the digital data applied to the DAC, and ultimately to the signal on the analog output terminal. You can configure an analog data mask by calling the Analog Data Mask or Analog Static Value properties or the `NIFGEN_ATTR_ANALOG_DATA_MASK` and `NIFGEN_ATTR_ANALOG_STATIC_VALUE` attributes.

Events

An event is a signal generated by the NI device at a device state. Typically, events are configured to indicate when a specific hardware condition has been met.

Event Output Behaviors

Events can have one of three output behaviors. Refer to the following table to determine which output behaviors are supported by each event.

- **Toggle**—Each instance of the event toggles between high and low. You can set the initial state of the event.
- **Pulse**—Each event triggers a pulse for a specified period of time.
- **Level**—While the event is active, it shifts high or low depending on the active state you specify.

Event Status

Events can return their status in two ways. Refer to the following table to determine what status can be read for each event type.

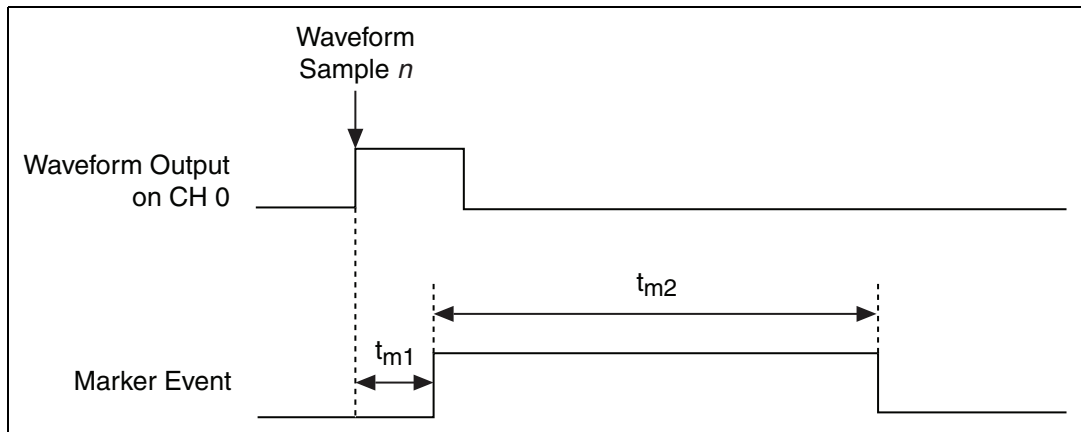
- **Live**—Returns the current state of the event.
- **Latched**—Returns whether the event has ever been active.

The following table describes the event output behaviors and statuses supported by the NI 5450.

Event Name	Description	Output Behavior	Status
Ready for Start Event	Ready For Start event indicates that the signal generator is configured and ready to receive a Start trigger.	Level	Live
Started Event	Started event indicates when the signal generator has received a Start trigger and is generating a waveform.	Level, Pulse	Latched
Marker Event	A Marker is an event that the device generates in relation to a waveform that is generated. The event is configured to occur at the time that a specific location or sample n if the waveform generates on the CH 0 connector. If the waveform loops multiple times in a segment, the marker generates each time the waveform loops.	Pulse, Toggle	Latched, Live
Data Marker Event	A Data Marker is an event that the signal generator generates in relation to the data bits of a waveform that is generated. Up to four bits can be configured to export to any valid destination on the signal generator.	Level	N/A
Done Event	The Done event indicates that the generation of the previous waveform is complete.	Level, Pulse	Latched

Marker Events

A marker is an event that the device generates in relation to a waveform that is generated. The event is configured to occur at the time that a specific location or sample n in the waveform generates on the CH 0 connector. If the waveform loops multiple times in a segment, the marker generates each time the waveform loops. The following figure shows a pulse that represents a waveform sample n that is one Sample clock in width of a waveform being generated on the CH 0 connector. The second pulse, the Marker event, represents the pulse that generates when the corresponding waveform sample n outputs at the CH 0 connector.



t_{m1} represents the delay in time of the Marker event generated relative to the configured waveform sample n being generated.

t_{m2} represents the Marker event pulse width in time.

NI-FGEN takes into account the factors that affect the delays in the Digital and Analog paths in assuring that the Marker event appears within one Sample clock of the waveform output. Therefore, t_{m1} is less than one Sample clock period.

The Marker event pulse width, t_{m2} , is at least 150 ns and can be significantly longer than 150 ns for slower Sample clocks. You can configure the pulse width by setting the Marker Event Pulse Width property or the `NIFGEN_ATTR_MARKER_EVENT_PULSE_WIDTH` attribute. Instruments commonly have a minimum pulse width specification for a trigger to be registered, and trigger pulses of smaller width are ignored. The signal generator ensures that a minimum pulse width exists on the Marker event by using a pulse stretching circuit. A Sample clock rate of 100 MS/s

has a period of 10 ns, requiring the pulse to be lengthened for many devices to register the marker as a good trigger pulse. Refer to the device specifications for the timing specifications.

Markers as Trigger Outputs

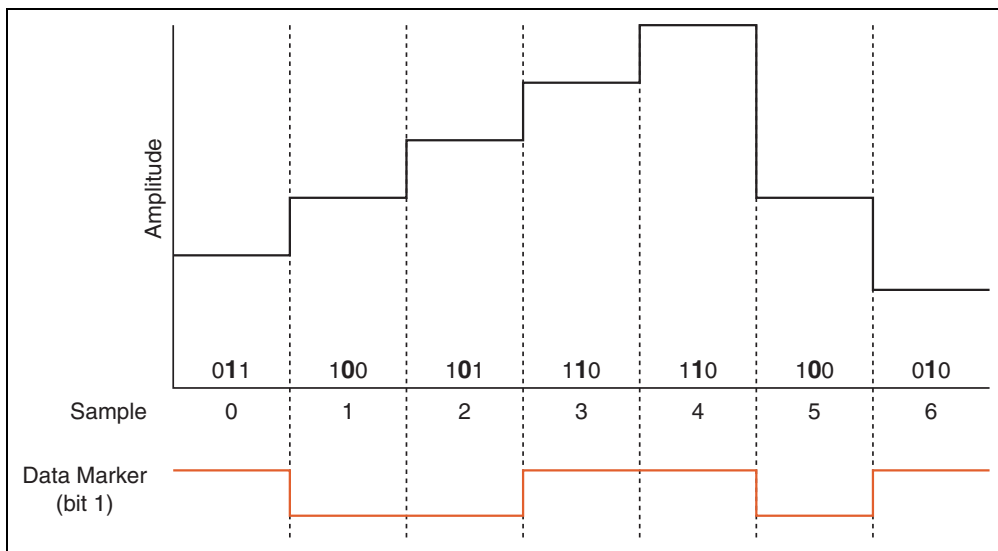
A delay of at least 44 Sample clocks exists between the Start trigger and the analog waveform generation on the output connector. Therefore, synchronizing the signal generator output signal to other devices with fast trigger response times is accomplished using the Marker event from the signal generator as the trigger source for the other device for more precise alignment to the generating waveform. You can do this using the RTSI bus, PXI trigger lines, SYNC OUT/PFI 0 and PFI 1.

Data Marker Events

The Data Marker events allow you to export any one of the 16 waveform data bits to any valid destination on the device. Up to four of the 16 waveform data bits can be exported at one time.

The level of a Data Marker event changes at the time that a specific data bit toggles in the waveform data. If the waveform data bit toggles multiple times in a segment, the Data Marker event level changes each time. When the data bit level is high, the Data Marker event level is high. You can invert this relationship by setting the Data Marker Event Level Polarity property or the `NIFGEN_ATTR_DATA_MARKER_EVENT_LEVEL_POLARITY` attribute.

The following figure shows the exported data marker event shifting between low and high as the specified data bit toggles.



NI-FGEN compensates for the factors that affect the delays in the digital and analog paths in assuring that the Data Marker event appears within one Sample clock of the waveform output.

Data Markers as Trigger Outputs

A delay of at least 44 Sample clocks exists between the Start trigger and when the analog waveform generation appears on the output connector. Therefore, synchronizing the signal generator output signal to other devices with fast trigger response times is accomplished using the data marker event from the signal generator as the trigger source for the other device for more precise alignment to the generating waveform. You can do this using the RTSI bus, PXI trigger lines, SYNC OUT/PFI 0 and PFI 1 or PFI 4 and PFI 5.



Note Devices without a DDC connector do not support PFI <4..5>.

Event Delays

The NI 5450 supports event delays that can manually delay Marker, Started, and Done events so that they are aligned on a particular Sample clock period.

Delay is applied to the event with respect to the analog output of the signal generator. For example, a delay of 0 Sample clocks aligns the event with the analog output signal, while a delay of +2 Sample clocks causes the event to appear two Sample clock periods after the analog output appears. All event delays are adjusted in increments of Sample clock periods, regardless of the units used to set the delay. For example, if you provide a value for delay with units of seconds, the delay is coerced up to the nearest Sample clock period.

The event delay attributes must be set before waveform generation is initiated. Any changes made to other attributes during waveform generation may change the analog output delay. NI-FGEN does not compensate for this change in the analog output delay, and continues to apply the event delay that you was originally configured.

If an event delay is applied to an event that is being exported to multiple output terminals, NI-FGEN aligns the event on the first terminal you specified.

You can configure event delays by calling the Started Event Delay property or the `NIFGEN_ATTR_STARTED_EVENT_DELAY` attribute, or the Done Event Delay property or the `NIFGEN_ATTR_DONE_EVENT_DELAY` attribute.

Exporting Signals

The signal generator contains seven PXI trigger lines that are available for sending signal generator-specific information to other devices that have PXI trigger or RTSI bus connectors.

The signal generator has connectors on the front panel to route signals to devices external to the PXI Express chassis. The following table shows the signals available for export and the lines they can be routed to. To determine all possible signal routes for your device, refer to Signal Routing.



Note The PFI outputs have a bandwidth of 200 MHz. The PXI Trigger lines have a bandwidth of <50 MHz.

		Destination		
		PXI_TRIG<0..6>	PFI 0 and PFI 1 Connectors	CLK OUT
Exported Clocks, Triggers, and Events	Sample Clock	Yes (when /K with $K \geq 2$)	Yes (when /K with $K \geq 2$)	Yes
	Sample Clock Timebase	Yes (when /M with $M \geq 2$)	Yes (when /M with $M \geq 2$)	Yes
	PLL Reference Source	Yes	Yes	Yes
	Out Start trigger	Yes	Yes	No
	Marker Event	Yes	Yes	No

Sample Clock—The clock signal that tells the DAC when to convert the digital waveform values to an analog voltage. The Sample clock frequency is referred to as the Sample clock rate; the rate at which the digital waveforms from device memory are generated. The Sample clock is also known as update clock.



Note The Sample clock can be exported directly, or it can first be divided down by an integer. This configuration provides a variable frequency signal related to the waveform sample rate to synchronize other devices to the generation. NI does not recommend exporting clocks greater than 20 MHz over PXI_TRIG<0..6>. If you export the divided-down Sample clock to another device to synchronize sampling, you can also use the Sample clock as the Start trigger for the signal generator. Using the divided-down Sample clock as the Start trigger begins signal generation at the same place each time relative to the divided-down Sample clock. This technique is more useful as the divisor becomes larger and, while an improvement over using an immediate Start trigger, there remains an uncertainty of one Sample clock.

Sample Clock Timebase—The 200-400 MHz clock signal from which the internal Sample clock is derived. The Sample clock timebase is also known as the board clock.



Note When the Sample clock timebase (board clock) is exported over PXI_TRIG<0..6> or the PFI 0 and PFI 1 connectors, it is always divided-down first. The default divide-down value is 2. Valid divide-down values range from 2 to 4,194,304. If you export the Sample clock timebase to another device to synchronize sampling, you can also use the Sample

clock timebase as the Start trigger for the signal generator. Using the Sample clock timebase as the Start trigger begins signal generation at the same place each time relative to the Sample clock timebase. This technique is more useful as the divisor becomes larger and while an improvement over using an immediate Start trigger there remains an uncertainty of one Sample clock.

PLL Reference clock source—A clock signal that is only available when a PLL Reference source has been configured. The clock is the source selected as the PLL Reference clock source.

Out Start trigger—A signal generated by the device upon recognizing a start condition that can be routed out various connectors to signal other devices.

Marker event—A digital signal that can be used as a trigger corresponding to a specific sample in the waveform generation. This signal controls other devices that require timing information related to a specific point in the generated waveform.

Routing Signals

You can route signals in the following ways:

- The Marker event generated during an Arbitrary Waveform Generation mode waveform generation to any of the PXI trigger lines or the PFI 0 and PFI 1 connectors.
- The signal generator Start trigger output signal to other devices through any of the PXI trigger lines or the PFI 0 and PFI 1 connectors.
- The signal generator Sample clock signal to other devices through any of the PXI trigger lines or front panel connectors.
- The signal generator Sample clock timebase signal to other devices through any of the PXI trigger lines or front panel connectors.
- The PLL Reference clock source to other devices through any of the PXI trigger lines or front panel connectors.

In NI-FGEN, the PXI trigger lines are referred to as RTSI<0..6>. The correlation between PXI_TRIG<x> and RTSI<x> is one to one. For more information about configuring and routing the device internal signals, refer to the niFgen Export Signal VI or the niFgen_ExportSignal function.

Synchronization

Your signal generator is based on the National Instruments Synchronization and Memory Core (SMC) technology and therefore supports TClk synchronization. Refer to the NI-TClk Synchronization Help for more information about NI-TClk Synchronization.

Specifications

For information about the signal generator specifications, refer to the device specifications. You can access these specifications by navigating to **Start»All Programs»National Instruments»NI-FGEN»Documentation»Hardware Specifications**, or you can visit ni.com/manuals.

Calibration

Before shipping your signal generator, NI calibrated your device to ensure that all features are within specifications.

Calibration is a set of operations that compares the values indicated by a measuring instrument or measuring system to the corresponding values realized by external standards. You can use the results of calibration to determine the measurement error and can then correct for it in the adjustment process.

The calibration process consists of verifying, adjusting, and reverifying a device. During verification, you compare the measured performance to an external standard of known measurement uncertainty to confirm that the product meets or exceeds specifications. During adjustment, you correct the measurement error of the device by adjusting the calibration constants and storing the new calibration constants in the EEPROM. The host computer reads the calibration constants and the software uses them to compensate for errors in the data and to present calibrated data to the user.

Accessories

National Instruments offers a variety of products to use with your signal generator, including cables and other accessories. Visit ni.com for more information.

Integration and System Considerations

This section contains information about integrating NI signal generators into a PXI-based or a PCI-based measurement system.

The PXI architecture has built-in timing and triggering features that can synchronize multiple devices over a backplane timing bus. Multiple devices in a modular instrumentation system can share a common Reference clock and synchronize to triggers that are distributed over controlled signal paths that ensure matched propagation. PC plug-ins with RTSI also provide an internal bus that can be accessed by multiple devices. Internal routing of these timing signals in PXI and PC plug-ins with RTSI eliminate complicated external wiring. Standardized timing protocols eliminate incompatibilities, giving you the best performance when synchronizing any kind of analog, digital, or timing measurements.

Peripheral Component Interconnect (PCI) is a high-performance expansion bus architecture originally developed by Intel to replace ISA and EISA. It has achieved widespread acceptance as a standard for PCs and workstations, and offers a theoretical maximum transfer rate of 132 Mbytes/s.

Environment

Device performance and reliability may be limited at temperatures above the specified operating range. For best performance take the following precautions:

- Ensure that the ambient temperature is within the specifications for the device and is stable (± 5 °C).
- Follow standard metrology practices.
- Use a PXI or PXI Express chassis with a well-designed cooling system.

Operating NI PXI and PXI Express signal generators outside the specified operating temperatures can increase bias currents in the electronic

components, increase noise, accelerate drifts, and decrease product life. Beyond the maximum specified operating temperatures, the device may perform differently than during factory calibration, resulting in additional measurement errors. Also, operating the device outside of the humidity specification ($>80\%$, $>35\text{ }^{\circ}\text{C}$) may cause leakages between circuit components and introduce measurement error.

To optimize cooling and ensure best performance and reliability the use the following guidelines:

- Chassis that provide multiple fan speed settings should always be run with fans set on high or auto if applicable to your chassis. Never set the fans to low or turn them off.



Note In newer NI chassis the settings are HIGH and AUTO, in some older NI chassis the fan settings may be HI and LO.

- All empty slots in the chassis should be covered with a blank slot filler panel.
- Remove and clean the inlet filters often to prevent buildup of dust and other foreign material that may restrict airflow.
- The chassis should be located such that the fan inlets and outlet vents are not obstructed. Other objects and equipment should be kept a minimum of 3 inches from the fan inlets.

For more information about forced-air cooling, refer to your chassis documentation.

NI PXI and PXI Express signal generators are designed to operate at shock up to 30 g, 11 ms, half-sine. It is specified to withstand shock up to 50 g, 11 ms, half-sine when not operating (shipping/storage).

NI PXI and PXI Express signal generators are designed to withstand total random vibration of 0.31 g_{rms} operational and 2.46 g_{rms} non operational per IEC 68-2-64.

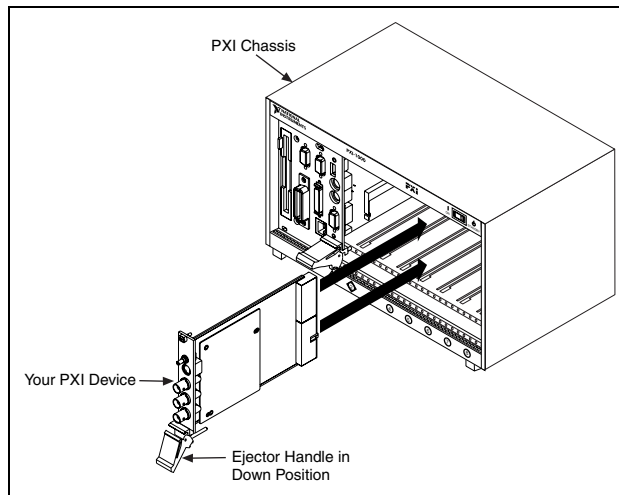
PXI/PXI Express Chassis Cooling

Not all PXI or PXI Express chassis provide the same cooling. When selecting a PXI or PXI Express chassis, consideration should be given to providing adequate airflow for high power and sensitive devices such as NI signal generators.

NI PXI and PXI Express signal generators are high-precision instruments and may be sensitive to interference from other electronic devices. To optimize the accuracy and performance of the device, you may need to locate the device in a slot away from devices with power supplies and other noisy circuitry. The device may also be sensitive to heat generated by high-power products in neighboring slots. When possible, consider locating the device away from high-power devices to optimize cooling.

PXI Modules

PCI eXtensions for Instrumentation (PXI) modular instrumentation delivers a PC-based, standardized, high-performance measurement and automation system. PXI combines the high-speed PCI bus with integrated timing and triggering designed specifically for measurement and automation applications to deliver significant performance improvements over older architectures. The following figure shows a typical PXI chassis installation.



Chassis Guidelines

NI PXI signal generators can be installed in the following chassis and slots:

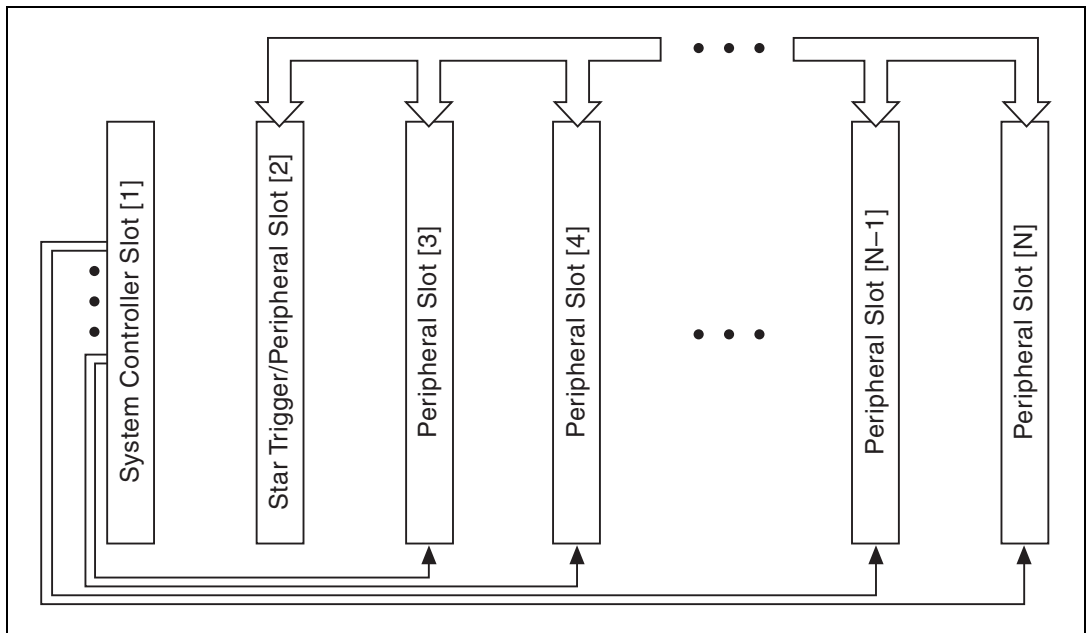
- **PXI chassis**—PXI signal generators can be installed in any peripheral slot of a PXI chassis.
- **PXI-Express chassis**—PXI signal generators can be installed in the following PXI Express chassis slots:
- **PXI-1 slots**—Accepts PXI modules
- **PXI hybrid slots**—Accepts either PXI modules that are hybrid slot-compatible or PXI Express modules

Using PXI-Compatible Products with Standard CompactPCI Products

The ability to use PXI-compatible products with standard CompactPCI products is an important feature provided by the *PXI Specification*, revision 2.1. If you use a PXI-compatible plug-in device in a standard CompactPCI chassis, you cannot use PXI-specific functions, but you can still use the basic plug-in device functions. For example, the PXI trigger bus on NI signal generators is available in a PXI chassis but not in a CompactPCI chassis. The CompactPCI specification permits vendors to develop sub-buses that co-exist with the basic PCI interface on the CompactPCI bus. Compatible operation is not guaranteed between CompactPCI devices with different sub-buses nor between CompactPCI devices with sub-buses and PXI. The standard implementation for CompactPCI does not include these sub-buses. NI signal generators work in any standard CompactPCI chassis. PXI-specific features, such as PXI_Trig bus and PXI_CLK10 reference are implemented on the J2 connector of the CompactPCI bus.

PXI Trigger Lines

Eight PXI bus trigger lines are highly flexible and can be used in a variety of ways. For example, triggers can be used to synchronize the operation of several different PXI peripheral devices. In other applications, one device can control carefully timed sequences of operations performed on other devices in the system. Triggers may be passed from one device to another, allowing precisely timed responses to asynchronous external events that are being monitored or controlled. The number of triggers that a particular application requires varies with the complexity and number of events involved.



The PXI Specification is implemented with the RTSI bus through the PXI trigger lines. PXI Specification requires eight lines, PXI_Trig<0..7>, on the P2/J2 connector of the PXI chassis for the trigger lines. The RTSI features of NI signal generators is implemented on this sub-bus. The RTSI triggers <0..6> are implemented on PXI_Trig<0..6>, and the RTSI clock is routed on PXI_Trig7.

System Reference Clock, PXI_CLK10

The PXI chassis supplies the PXI 10 MHz system Reference clock signal (PXI_CLK10) independently to each peripheral slot. An independent buffer drives the clock signal to each peripheral slot. The buffer has a source impedance matched to the backplane and a skew ranging from less than 1 ns to better than 250 ps between slots. You can use this common Reference clock signal to synchronize multiple devices in a measurement or control system. You can drive PXI_CLK10 from an external source through the PXI_CLK10_IN pin on the P2 connector of the PXI star trigger slot, which is slot 2. Sourcing an external clock on this pin automatically disables the 10 MHz source on the backplane. You can synchronize multiple chassis that have connectors on the back panel for 10 MHz reference in and 10 MHz reference out. Refer to your PXI chassis documentation for more information.

PFI Lines

PFI lines are multipurpose programmable function input/outputs. These lines serve as connections to virtually all internal timing signals. NI signal generators have up to six digital lines that can accept or generate a trigger, generate a marker, accept or generate a Reference clock. The function of each PFI line is independent.

If you are using LabVIEW to program your signal generator and you want to connect external signal generators to the PFI lines, you can use the niFgen Configure Sample Clock Source VI, the niFgen Configure Reference Clock VI, or the niFgen Configure Trigger VI to route external signals to internal sources. You can use the niFgen Export Signal VI to route internal signals to the PFI lines on the front panel.

If you are using LabWindows/CVI to program your signal generator, you can use the niFgen_ConfigureSampleClockSource function, the niFgen_ConfigureReferenceClock function, or the niFgen_ConfigureTriggerSource function to route external signals to internal sources. You can use the niFgen_ExportSignal function to route internal signals to the PFI lines on the front panel.



Caution If you enable a PFI line for output, do *not* connect any external signal source to it; doing so can damage the device, the computer, and the connected equipment.

MXI Optimization Application

MXI-3

If you are using the MXI-3 interface to control the PXI chassis, the MXI-3 Optimization Application must be run prior to using the NI signal generator. By default, this application runs automatically when Windows starts. If you have an initialization, timeout, or performance issue with your module, or if you are not certain that the application ran, select **Start»All Programs»National Instruments MXI-3»MXI-3 Optimization** to run the application. If you continue to have initialization or performance issues, refer to the MXI-3 documentation at **Start»All Programs»National Instruments MXI-3**, or visit NI Technical Support at ni.com/support.

MXI-4 and MXI-Express Optimization

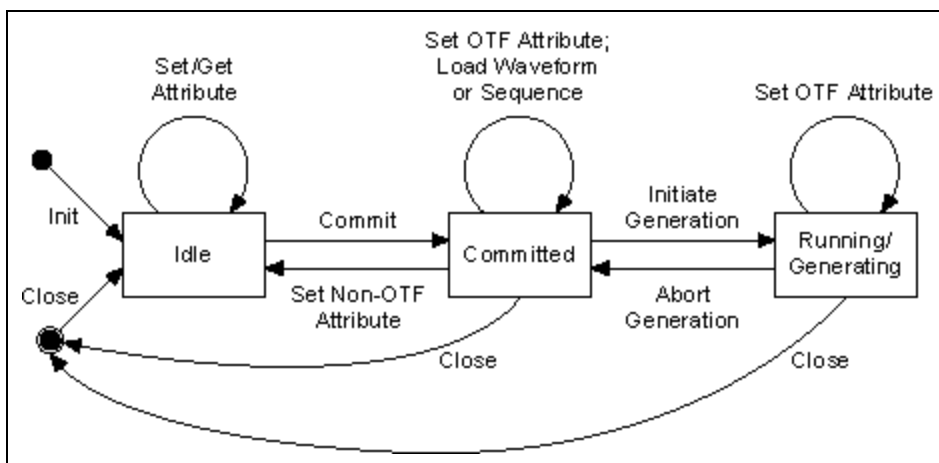
Optimization for MXI-4 and MXI Express are performed automatically by the hardware.

Programming

Programming State Model

In this topic the word “property,” when not referring to a specific property, refers to both properties in LabVIEW and attributes in C or CVI.

The NI-FGEN programming model has three main states: Idle, Committed, and Generating, as shown in the following figure.



Idle—You can program all session properties in the Idle state. However, when in the Idle state, the properties may not have been applied to the device yet, so the device hardware configuration may not match the session property values—the device remains configured as it was the last time a session was committed. If the computer has just been reset or the niFgen Reset Device VI or the `niFgen_ResetDevice` function has just been called, the device is in the default hardware state. This means the device is not generating a waveform, although, depending on the previous state, a constant DC voltage from the last waveform sample generated on the output connector may be present.

Committed—All of the session properties are applied to the device when the session enters the Committed state. In the Committed state, waveforms and sequences can be loaded into onboard memory. If any properties are changed, the session implicitly transitions back to idle, and the hardware configuration still reflects the previously committed properties. Calling the niFgen Commit VI or the `niFgen_Commit` function from the Idle state verifies all properties, configures the device, and transitions to the Committed state.

Generating—In the Generating state, session properties always reflect the current state of the device, and the device is either waiting on a trigger or generating a signal. Dynamic properties, such as the Arbitrary Waveform Gain property or the `NIFGEN_ATTR_ARB_GAIN` attribute and the Arbitrary Waveform Offset property or the `NIFGEN_ATTR_ARB_OFFSET` attribute, are applied to the device immediately if set while the session is in the Generating state.

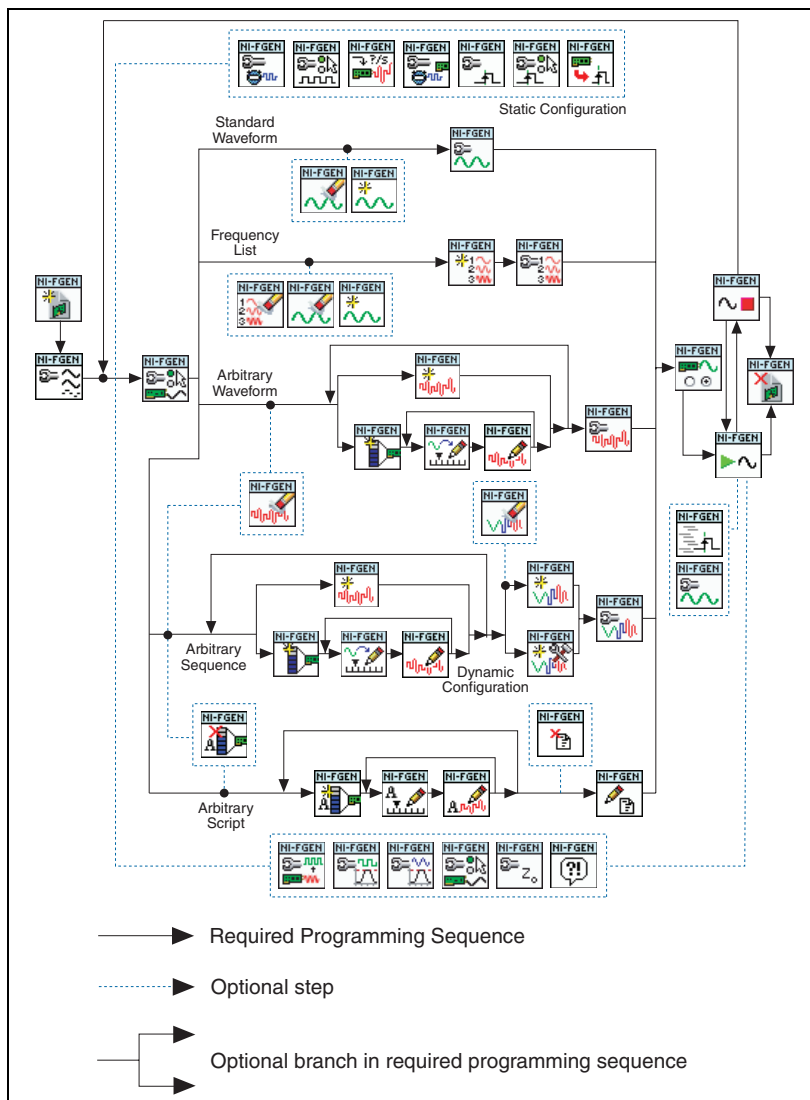
The following actions or settings cause a transition between states:

- Calling the niFgen Initiate Generation VI or the `niFgen_InitiateGeneration` function in the Idle state causes a transition to the Generating state.
- Calling the niFgen Commit VI or the `niFgen_Commit` function in the Idle state causes a transition to the Committed state.
- Calling a create or write waveform VI or function in the Idle state causes a transition to the Committed state.
- Calling the niFgen Create Arbitrary Sequence VI or the `niFgen_CreateArbSequence` function, or the niFgen Create Advanced Arb Sequence VI or the `niFgen_CreateAdvancedArbSequence` function in the Idle state causes a transition to the Committed state.
- Changing any property in the Committed state causes a transition to the Idle state.
- Changing a property that is not dynamic in the Generating state returns an error, but does not transition out of the Generating state.
- Calling the niFgen Abort Generation VI or the `niFgen_AbortGeneration` function in the Generating state causes a transition to the Committed state.
- Calling the niFgen Close VI or the `niFgen_close` function from any state closes the NI-FGEN session and transitions to the close state. If the session is in the Generating state, the generation is aborted first.

- Calling the niFgen Reset VI or the `niFgen_reset` function from any state causes a transition to the Idle state. If the session is in the Generating state, the generation is aborted first.

General Programming Flow

The following diagram shows the general programming flow for applications using NI-FGEN. Not all NI-FGEN VIs appear in the general programming flow as some VIs are considered utility VIs, which perform tasks such as resetting the device and returning the revision number of NI-FGEN. Refer to the *NI-FGEN LabVIEW Reference* or the *NI-FGEN C Function Reference* for more information.



Instrument Driver Overview

To create your application, you need an industry-standard instrument driver such as NI-FGEN to control your device. NI-FGEN is IVI-compliant and works with NI LabVIEW, NI LabWindows™/CVI™, and conventional programming languages such as Microsoft Visual C, C++, and Visual Basic.

NI-FGEN includes a set of standard functions for configuring, creating, starting, and stopping waveform generation. NI-FGEN reduces your program development time and simplifies device control by eliminating the need to learn a complex programming protocol for your device.

Refer to the NI-FGEN Instrument Driver Readme for more information. You can access this document by selecting **Start»All Programs»National Instruments»NI-FGEN»Documentation**.

Creating an Application with NI-FGEN and Your ADE

This topic covers how to begin using NI-FGEN with your application development environment (ADE) and lists any files that you need to include in your application.

To successfully build your application, you need to have NI-FGEN installed, along with one of the following ADEs:

- NI LabVIEW
- NI LabVIEW Real-Time
- NI LabWindows/CVI
- Microsoft Visual C/C++
- Microsoft Visual Basic

Creating an Application with LabVIEW

This topic assumes that you are using LabVIEW to manage your code development and that you are familiar with the ADE.

To develop an NI-FGEN application in LabVIEW, follow these general steps:

1. Open an existing or new LabVIEW VI.
2. From the Function palette, locate the NI-FGEN VIs at **Instrument I/O»Instrument Drivers»NI-FGEN**.
3. Click the Vis that you want to use, and drop them on the block diagram to build your application.

NI-FGEN Example Programs for LabVIEW

If you are using LabVIEW 7.0 or later, you can use the NI Example Finder to search or browse examples. NI-FGEN examples are classified by keyword, so you can search for a particular device or measurement function.

To browse the NI-FGEN examples available in LabVIEW, launch LabVIEW, click **Find Examples**, and navigate to **Hardware Input and Output»Modular Instruments»NI-FGEN**.

For the installation location of the LabVIEW example files, refer to the *NI-FGEN Instrument Driver Readme*.

Considerations for using the LabVIEW Real-Time Module

To develop an NI-FGEN application in the LabVIEW Real-Time Module, follow the same steps used for developing any application in the LabVIEW Real-Time Module, with the addition of using the NI-FGEN LabVIEW VIs.

Supported LabVIEW Versions

LabVIEW Real-Time Module 7.1 or later

Unsupported Hardware

The following signal generators are not supported as targets for your LabVIEW RT application:

- NI PXI/PCI-5401
- NI PXI/PCI-5411
- NI PXI/PCI-5431

Unsupported Features

When using the National Instruments signal generators with LabVIEW RT, the following features are *not* supported:

- External calibration
- Express VIs
- FGEN Soft Front Panel

Related Documentation

- For configuration instructions for remote systems, refer to the *MAX Remote Systems Help* in Measurement & Automation Explorer (MAX) by selecting **Help»Help Topics»Remote Systems** in MAX.
- For more information about the LabVIEW Real-Time Module, refer to the *LabVIEW Real-Time Module User Manual* at ni.com/manuals.
- For additional troubleshooting and support information, refer to the LabVIEW Real-Time Support main page at ni.com/support/labview/real-time.

Creating an Application with LabWindows/CVI

This topic assumes that you are using LabWindows/CVI to manage your code development and that you are familiar with the ADE.

To develop an NI-FGEN application in LabWindows/CVI, follow these general steps:

1. Open an existing or new project file.
2. Load the NI-FGEN function tree (`niFgen.fp`) from `VXIPnP\<WinNT|9x>\niFgen`.
3. Use the function tree to navigate the function hierarchy and to generate function calls with the proper syntax and variable values.

NI-FGEN Example Programs for LabWindows/CVI

To locate the example programs installed with NI-FGEN, refer to the *NI-FGEN Instrument Driver Readme*.

If you are using LabWindows/CVI 7.0 or later, you can use the NI Example Finder to search or browse examples. NI-FGEN examples are classified by keyword, so you can search for a particular device or measurement function.

To browse the NI-FGEN examples available in LabWindows/CVI, launch LabWindows/CVI, select **Help»Find Examples**, and navigate to **Hardware Input and Output»Modular Instruments»NI-FGEN**. You can also access the examples using the Start menu, by selecting **Start»All Programs»National Instruments»NI-FGEN»Examples**.

Creating an Application with Visual C/C++

This topic assumes that you are using Visual C/C++ to manage your code development and that you are familiar with the ADE.

To develop an NI-FGEN application in Visual C/C++, follow these general steps:

1. Open an existing or new Visual C/C++ project.
2. Create source files—`.c` (C source code) or `.cpp` (C++ source code)—and add them to the project. Make sure that you include the NI-FGEN header file (`niFGEN.h`) in your source code files as follows:

```
#include "niFGEN.h"
```
3. Specify the directory that contains the NI-FGEN header file under the **Preprocessor»Additional include directories** settings in your

compiler—for Visual C++ 6.0 these files are under **Project»Settings»C/C++**. For the location of the NI-FGEN header files, refer to the *NI-FGEN Instrument Driver Readme*.

4. Add the NI-FGEN import library (`niFGEN.lib`) to the project under **Link»General»Object/Library Modules**. For the location of the NI-FGEN import library files, refer to the *NI-FGEN Instrument Driver Readme*.
5. Add NI-FGEN function calls to your application.
6. Build your application.

NI-FGEN Example Programs for Visual C/C++

To locate the example programs installed with NI-FGEN, refer to the *NI-FGEN Instrument Driver Readme*.

Special Considerations

String Passing

To pass strings, pass a pointer to the first element of the character array. Be sure that the string is null-terminated.

Parameter Passing

By default, Visual C passes parameters by value. Remember to pass pointers to variables when you need to pass by address.

Creating an Application with Visual Basic

This topic assumes that you are using Visual Basic to manage your code development and that you are familiar with the ADE.

To develop an NI-FGEN application in Visual Basic, follow these general steps:

1. Open an existing or new Visual Basic project.
2. Create the following files, which are necessary for your application, and add them to your project:
 - `.frm` (form definition and event handling code)
 - (optional) `.bas` (Visual Basic generic code module)
 - (optional) `.cls` (Visual Basic class module)
3. Add a reference to the National Instruments Function Generator library (NI-FGEN), which is part of `niFgen_32.dll` by selecting

Project»References, and then **National Instruments Function Generator**.



Note If you do not see the NI-FGEN library listed there, click **Browse** and locate `niFGEN_32.dll` in the directory listed in the NI-FGEN Instrument Driver Readme.

4. Use the Object Browser <F2> to find function prototypes and constants.
5. Add NI-FGEN function calls to your application.
6. Run your application by clicking **Run»Start**.

NI-FGEN Tutorial

Example Programs

NI-FGEN ships with several examples that demonstrate basic signal generator applications. You can access these examples through the Start menu, by navigating to **Start»All Programs»National Instruments»NI-FGEN»Examples**.



Note The NI-FGEN examples assume that you are already familiar with the ADE in which you will be programming. If you are unfamiliar with the ADE, consult an introductory text on the ADE before you begin the studying the NI-FGEN examples.

NI-FGEN provides the same functionality in two different formats—as virtual instruments (VIs) in LabVIEW and as functions in C-based programming languages.

Basic Steps

The tutorial explains how to complete the following programming steps:

1. Initialize the session
2. Configure an application
3. Initiate generation
4. Abort generation
5. Close the session
6. Retrieve error information

After you understand the programming process outlined in this tutorial, you can find advanced information about programming specific signal

generator features with the NI-FGEN instrument driver in the [Features](#) section.

Initialize

Because you can have multiple signal generators connected to your computer, you must tell NI-FGEN which signal generator to communicate with by opening a session to the signal generator.

A session establishes a connection between the signal generator and your application. After this connection is established, the signal generator can transmit data to your application. Sessions also allow the driver to cache previous settings, which greatly improves performance.

LabVIEW Example

Call the niFgen Initialize VI to create a session.

- **Resource Name** must be set to the device identifier assigned to the signal generator in Measurement & Automation Explorer (MAX). You can find or set the resource name for your signal generator by launching MAX and selecting **Devices and Interfaces**.
- **Id Query** specifies whether or not to verify that NI-FGEN supports the device you initialize. Circumstances can arise where sending an ID query to the device is undesirable. When you set this parameter to FALSE, the VI initializes the device without performing an ID query.
- **Reset Device** allows you to reset the signal generator during initialization.
- **Instrument Handle Out** returns a handle that, when passed to subsequent VIs, allows you to communicate with the signal generator throughout your session.

C Example

Call the niFgen_init function to create a session.

- The **resourceName** parameter must be set to the device identifier assigned to the signal generator in MAX. You can find or set the resource name for your signal generator by launching MAX and selecting **Devices and Interfaces**.
- The **idQuery** parameter specifies whether or not to verify that NI-FGEN supports the device you initialize. Circumstances can arise where sending an ID query to the device is undesirable. When you set this parameter to VI_FALSE, the function initializes the device without performing an ID query.

- The **resetDevice** parameter allows you to reset the signal generator during initialization.
- The **vi** parameter returns a handle that, when passed to subsequent functions, allows you to communicate with the signal generator throughout your session.

Configuration

Once you have opened a session to your signal generator, you need to configure the session to generate the signals you desire for your application. If you are using a multichannel device, you must configure channels immediately after initializing and before configuring any other feature of the device. When configuring the output mode of your device, you can choose to generate a standard waveform, an arbitrary waveform, an arbitrary sequence, a frequency list, or a script. Refer to the Features Supported topic for your device for more information about the type of output modes it supports.



Note If your application requires triggers, clocking, or exported signals, you must configure them before waveform generation begins. Refer to the Features section for more information on configuring your signal generator.

Configure Channels

If you want to configure a multichannel signal generator to generate data on more than one channel, you must configure the channels to be used.



Note If you are not using a multichannel signal generator or if you are only concerned with data generated on one channel of a multichannel signal generator, you do not need to perform this step.

LabVIEW Example

Call the niFgen Configure Channels VI with **Channels** set to the channel or channels you want to configure. Valid values are non-negative integers. For example, 0 is the only valid value on devices with one channel, while devices with two channels support values of 0 and 1. You can specify more than one channel by inserting commas between values (for example, “0,1”).

C Example

Call the `niFgen_ConfigureChannels` function with **channels** set to the channel or channels you want to configure. Valid values are non-negative integers. For example, 0 is the only valid value on devices with one channel, while devices with two channels support values of 0 and 1. You can specify more than one channel by inserting commas between values (for example, "0,1").

Configure Output Mode

The Configure Output Mode step determines the type of waveforms that will be generated by your device. Options include standard waveforms, arbitrary waveforms, arbitrary sequences, frequency lists, and scripts. Refer to the Features Supported topic for your device for more information about the type of output modes it supports.

Configure Standard Function Mode

Standard Function output mode allows you to generate standard function waveforms such as sine, square, triangle, etc.

LabVIEW Example

The procedure below provides the basic steps required to configure Standard Function mode. For a more detailed example of the use of Standard Function mode in LabVIEW, refer to the Fgen Basic Standard Function.vi example for LabVIEW.

1. Call the niFgen Configure Output Mode VI. Set **Output Mode** to Standard Function.
2. Choose the type of waveform you would like to generate and set the **Waveform** parameter of the niFgen Configure Standard Waveform VI to the waveform you have chosen.

C Example

The procedure below provides the basic steps required to configure Standard Function mode. For a more detailed example of the use of Standard Function mode in C, refer to the BasicStandardFunction example for CVI.

1. Call the `niFgen_configureOutputMode` function. Set **outputMode** to `NIFGEN_VAL_OUTPUT_FUNC`.
2. Choose the type of waveform you would like to generate and set the **waveform** parameter of the `niFgen_configureStandardWaveform` function to the waveform you have chosen.

Configure Arbitrary Waveform Mode

You can use Arbitrary Waveform mode to generate waveforms from user-created or user-provided waveform arrays of numeric data.

LabVIEW Example

The procedure below provides the basic steps required to configure Arbitrary Waveform mode. For a more detailed example of the use of Arbitrary Waveform mode in LabVIEW, refer to the `Fgen Basic Arb Waveform.vi` or the `Fgen Arbitrary Waveform.vi` examples for LabVIEW.

1. Call the niFgen Configure Output Mode VI with **Output Mode** set to Arbitrary Waveform.
2. (Optional) Call the niFgen Clear Arbitrary Memory VI. This clears any previously created arbitrary waveforms, sequences, and scripts from the signal generator memory.

Choose one of the following two options for creating your arbitrary waveform:

Option 1—Allow NI-FGEN to configure the size and allocated space of your waveform.

1. Call the niFgen Create Waveform (poly) VI. This VI creates a waveform the size of the data you provide.
2. Call the niFgen Configure Arbitrary Waveform VI to configure the gain and offset of the waveform.

Option 2—Manually configure the size and allocated space of your waveform.

1. Call the niFgen Allocate Waveform VI to specify the size of the waveform to allocate in the onboard memory of the signal generator.
2. Call the niFgen Write Waveform (poly) VI to write waveform data to the onboard memory you allocated in step 3.
3. Call the niFgen Configure Arbitrary Waveform VI to configure the gain and offset of the waveform.

C Example

The procedure below provides the basic steps required to configure Arbitrary Waveform mode. For a more detailed example of the use of Arbitrary Waveform mode in C, refer to the BasicArbitraryWaveform or the ArbitraryWaveform examples for CVI.

1. Call the `niFgen_ConfigureOutputMode` function with the **outputMode** parameter to `NIFGEN_VAL_OUTPUT_ARB`.
2. (Optional) Call the `niFgen_ClearArbWaveform` function. This clears any previously created arbitrary waveforms from the signal generator memory.
3. Call one of the `niFgen Create Waveform` functions (`niFgen_CreateWaveformF64`, `niFgen_CreateWaveformI16`, `niFgen_CreateWaveformComplexF64`, `niFgen_CreateWaveformFromFileI16`, or `niFgen_CreateWaveformFromFileHWS`). The function you choose creates a waveform the size and type of the data you choose.
4. Call the `niFgen_ConfigureArbWaveform` function to configure the gain and offset of the waveform.

Configure Arbitrary Sequence Mode

You can use Arbitrary Sequence mode to load multiple waveforms in the onboard memory of the signal generator.

LabVIEW Example

The procedure below provides the basic steps required to configure Arbitrary Sequence mode. For more detailed examples of the use of Arbitrary Sequence mode in LabVIEW, refer to the `Fgen Basic Arb Sequence.vi` or the `Fgen Arbitrary Sequence.vi` examples for LabVIEW.

1. Call the `niFgen Configure Output Mode VI` with **Output Mode** set to Arbitrary Waveform.
2. (Optional) Call the `niFgen Clear Arbitrary Memory VI` to clear any previously created arbitrary waveforms, sequences, and scripts from the signal generator memory.

Choose one of the following two options for creating your arbitrary sequence:

Option 1—Allow NI-FGEN to configure the size and allocated space of your waveform.

1. Call the niFgen Create Waveform (poly) VI. This VI creates a waveform the size of the data you provide.
2. Call the niFgen Create Arbitrary Sequence VI or the niFgen Create Advanced Arb Sequence VI.
3. Call the niFgen Configure Arbitrary Sequence VI to configure the gain and offset of the sequence of waveforms.

Option 2—Manually configure the size and allocated space of your waveform.

1. Call the niFgen Allocate Waveform VI to specify the size of the waveform to allocate in the onboard memory of the signal generator.
2. Call the niFgen Write Waveform (poly) VI to write waveform data to the onboard memory you allocated in step 3.
3. Call the niFgen Create Arbitrary Sequence VI or the niFgen Create Advanced Arb Sequence VI.
4. Call the niFgen Configure Arbitrary Sequence VI to configure the gain and offset of the sequence of waveforms.

C Example

The procedure below provides the basic steps required to configure Arbitrary Waveform mode. For a more detailed example of the use of Arbitrary Sequence mode in C, refer to the BasicArbitrarySequence or the ArbitrarySequence examples for CVI.

1. Call the niFgen_ConfigureOutputMode function with **outputMode** to NIFGEN_VAL_OUTPUT_SEQ.
2. (Optional) Call the niFgen_ClearArbMemory function to clear any previously created arbitrary waveforms, sequences, and scripts from the signal generator memory.
3. Call one of the niFgen Create Waveform functions (niFgen_CreateWaveformF64, niFgen_CreateWaveformI16, niFgen_CreateWaveformComplexF64, niFgen_CreateWaveformFromFileI16, or niFgen_CreateWaveformFromFileHWS). The function you choose creates a waveform the size and type of the data you choose.

4. Call the `niFgen_CreateArbSequence` function or the `niFgen_CreateAdvancedArbSequence` function.
5. Call the `niFgen_ConfigureArbSequence` function to configure the gain and offset of the waveform.

Configure Frequency List Mode

You can use Frequency List mode to generate a standard function using a list of frequencies you define.

LabVIEW Example

The procedure below provides the basic steps required to configure Frequency List mode. For an example of the use of Frequency List mode in LabVIEW, refer to the `Fgen Sweep Generator.vi` example.

1. Call the `niFgen Configure Output Mode VI` with **Output Mode** set to Frequency List.
2. (Optional) Call the `niFgen Clear Frequency List VI` to remove any previously created frequency lists from the signal generator memory.
3. Call the `niFgen Create Frequency List VI` to set the function type, the frequency list, and the duration of each step in the list.
4. Call the `niFgen Configure Frequency List VI` to select the active frequency list and configure the amplitude, DC offset, and start phase of the generation.

C Example

The procedure below provides the basic steps required to configure Frequency List mode. For an example of the use of Frequency List mode in C, refer to the `Fgen Sweep SweepGenerator` example for CVI.

1. Call the `niFgen_ConfigureOutputMode` function with **outputMode** set to `NIFGEN_VAL_OUTPUT_FREQ_LIST`.
2. (Optional) Call the `niFgen_ClearFreqList` function to remove a previously created frequency lists from the signal generator memory.
3. Call the `niFgen_CreateFreqList` function to set the function type, the frequency list, and the duration of each step in the list.
4. Call the `niFgen_ConfigureFreqList` function to select the active frequency list and configure the amplitude, DC offset, and start phase of the generation.

Configure Script Mode

You can use Script mode to use scripting to link and loop multiple waveforms in complex combinations using a script.

LabVIEW Example

The procedure below provides the basic steps required to configure Script mode. To see a more detailed example of the use of Script mode in LabVIEW, refer to the `Fgen Arb Script.vi` example for LabVIEW.

1. Call the niFgen Configure Output Mode VI with **Output Mode** set to Script.
2. Write all waveforms that are referenced in the script by calling the niFgen Write Named Waveform VI and associate the proper names to them.
3. After your waveforms are written to your device, call the niFgen Write Script VI to write the script(s) containing the generation instructions to be executed.

The script you write can manage waveform generation based on multiple waveforms and triggers. For example, you could download waveforms A, B, C, and D into device memory. You could then write a script that would wait for a trigger to initiate generation and, upon receiving this trigger, generate waveform A three times with a marker at position 16 each time and finally generate waveforms B, C, and D twice (BCDBCD). The following is the script of this example:

```
script myFirstScript
    wait until scriptTrigger0
    repeat 3

generate waveformA marker0(16)
    end repeat
    repeat 2

generate waveformB

generate waveformC

generate waveformD
    end repeat

end script
```

4. (Optional) You can write multiple scripts that exist simultaneously on your device. If you write multiple scripts to your device, you must

select the one you wish to execute by setting the Script to Generate property.

C Example

The procedure below provides the basic steps required to configure Script mode. To see a more detailed example of the use of Script mode in C, refer to the ArbitraryScript example for CVI.

1. Call the `niFgen_configureOutputMode` function with **outputMode** set to `NIFGEN_VAL_OUTPUT_FUNC`.
2. Write all waveforms that are referenced in the script by calling the one of the `niFgen Write Named Waveform` functions (`niFgen_WriteNamedWaveformF64`, `niFgen_WriteNamedWaveformI16`, `niFgen_WriteNamedWaveformComplexF64`, `niFgen_WriteNamedWaveformComplexI16`) and associate the proper names to them.
3. After your waveforms are written to your device, call the `niFgen_WriteScript` function to write the script(s) containing the generation instructions to be executed.

The script you write can manage waveform generation based on multiple waveforms and triggers. For example, you could download waveforms A, B, C, and D into device memory. You could then write a script that would wait for a trigger to initiate generation and, upon receiving this trigger, generate waveform A three times with a marker at position 16 each time and finally generate waveforms B, C, and D twice (BCDBCD). The following is the script of this example:

```
script myFirstScript
    wait until scriptTrigger0
    repeat 3

generate waveformA marker0(16)
    end repeat
    repeat 2

generate waveformB

generate waveformC

generate waveformD
    end repeat

end script
```

4. (Optional) You can write multiple scripts that exist simultaneously on your device. If you write multiple scripts to your device, you must select the one you wish to execute by setting the `NIFGEN_ATTR_SCRIPT_TO_GENERATE` attribute.

Initiate Generation

The Initiate Generation step transitions the device from the Committed state to the Generation state. Once this transition has been made, the device is able to begin generating waveforms.

LabVIEW Example

Call the niFgen Initiate Generation VI to transition the device to the Generation state.

C Example

Call the `niFgen_InitiateGeneration` function to transition the device to the Generation state.

Abort Generation

The abort generation step aborts any signal generation that was initiated in the initiate generation step. When you abort generation, you can choose to either abort to ground or abort to a known voltage (not available in Standard Function or Frequency List output modes).

Abort to Ground

All operation modes can abort to ground. To abort to ground you must disable the output enable relay to remove the DC voltage from the output.

LabVIEW Example

To abort generation to ground, complete the following steps:

1. Call the niFgen Output Enable VI to with **Output Enable** set to **FALSE** to disable the analog output and remove any DC voltage on the analog output.
2. Call the niFgen Abort Generation VI to stop the waveform generation.

C Example

1. Call the `niFgen_ConfigureOutputEnabled` function with the **enabled** parameter set to `VI_FALSE` to disable the analog output and to remove any DC voltage on the analog output.
2. Call the `niFgen_AbortGeneration` function to stop the waveform generation.

Abort to a Known Voltage

Arbitrary Waveform, Arbitrary Sequence, and Script output modes can abort generation to a known voltage. When waveform generation is aborted, the analog output signal remains at the voltage corresponding to the last waveform generated until the device is reconfigured for another generation.



Note Closing the NI-FGEN session to the device while generating a waveform stops the waveform generation. Stopping waveform generation at an unknown point leaves an unknown DC voltage, corresponding to the sample value when generation stopped on the CH 0 analog output connector. To ensure the output voltage goes to zero volts when closing your applications, always disable the output enable relay first and then abort the generation.

LabVIEW Example

To abort the generation to known voltage, complete the following steps:

1. During your application, download a small, constant-amplitude waveform that corresponds to the desired output voltage. You will generate this waveform at the end of your application.
2. Abort generation of the current waveform by calling the `niFgen Abort Generation VI`.
3. Reconfigure the device to generate the constant-amplitude waveform.
4. Call the `niFgen Initiate Generation VI` to transition the device to the Generation state.
5. Call the `niFgen Abort Generation VI` to stop generation of the constant-amplitude waveform.

C Example

To abort the generation to known voltage, complete the following steps:

1. During your application, download a small, constant-amplitude waveform that corresponds to the desired output voltage. You will generate this waveform at the end of your application.

2. Abort generation of the current waveform by calling the `niFgen_AbortGeneration` function.
3. Reconfigure the device to generate the constant-amplitude waveform.
4. Call the `niFgen_InitiateGeneration` function to transition the device to the Generation state.
5. Call the `niFgen_AbortGeneration` function to stop generation of the constant-amplitude waveform.

Closing the Session

The closing step closes the session and deallocates any resources the session used. Closing the session is important because it releases any temporary buffers that were created to transfer data between the digitizer and the host memory.

LabVIEW Example

Call the `niFgen Close VI` to close the session.

C Example

Call the `niFgen_Close` function to close the session.

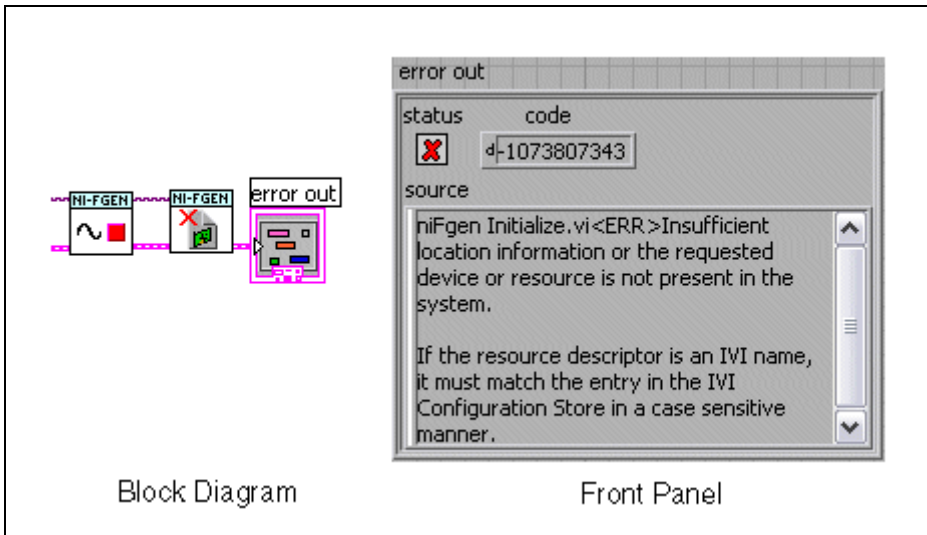
NI-FGEN Error Codes

When the NI-FGEN driver encounters an error, it returns an error code. This code value can be in hexadecimal, decimal, or text depending on your application. To understand the error code, you need to read the error description.

For example, the error “-1074135039” or “(0xBFFA0001 - Instrument Specific error)” encompasses many different error cases. To better understand the error specific to your application, you need to read the error description.

LabVIEW Example

LabVIEW users can read the error description by creating an error indicator from one of the NI-FGEN VIs as shown in the following figure.



C Example

```
void ErrorBox() {

ViUInt32 errMsgSize;

ViChar* errMsg;

if(error <0) {

errMsgSize = niFgen_GetError(vi, VI_NULL, 0, VI_NULL);

errMsg = (ViChar *) malloc(sizeof(ViChar) * errMsgSize);

niFgen_GetError(vi, &error, errMsgSize, errMsg);

ResetTextBox(fgenPanel, FGEN_PANEL_ERROR_MESSAGE,
errMsg);

free(errMsg);

}
```

```

else if(error == VI_SUCCESS) ResetTextBox(fgenPanel,
FGEN_PANEL_ERROR_MESSAGE, " ");

}

```

Features

This section provides instructions for using some of the features of National Instruments signal generators.

Configuring an Internal Sample Clock

You can use the internal (onboard) Sample clock to control the clocking rates of your signal generator. In Arbitrary Waveform or Arbitrary Sequence mode, you can choose a clocking mode that will allow you to configure the rate at which this Sample clock runs.



Note The onboard clock is the default Sample clock source. If you have not changed the settings for your Sample clock source, you do not need to perform this procedure.

LabVIEW Example

1. Call the niFgen Configure Sample Clock Source VI with **Source** set to “OnboardClock”.

Perform the following step only if your application is configured for Arbitrary Waveform or Arbitrary Sequence output mode:

2. Call the niFgen Configure Clock Mode VI with **Clock Mode** set to the clock mode required for your application.

C Example

1. Call the niFgen_ConfigureSampleClockSource function with the **sampleClockSource** parameter set to “OnboardClock”.

Perform the following step only if your application is configured for Arbitrary Waveform or Arbitrary Sequence output mode:

2. Call the niFgen_ConfigureClockMode function with the **clockMode** parameter set to the clock mode required for your application.

Configuring an External Sample Clock

Some NI signal generators can accept an external clock to directly drive the Sample clock. When using an external Sample clock, the frequency stability and accuracy of the Sample clock is determined by the external Sample clock provided.

LabVIEW Example

1. Call the niFgen Configure Sample Clock Source VI with the **Source** set to an external location.

Perform the following step if your application is configured for Arbitrary Waveform, Arbitrary Sequence, or Script output mode:

2. Call the niFgen Set Sample Rate VI with the **Sample Rate** set to the frequency of the external device you are using as a clock source.

C Example

1. Call the `niFgen_ConfigureSampleClockSource` function with the **sampleClockSource** parameter set to an external location.

Perform the following step if your application is configured for Arbitrary Waveform, Arbitrary Sequence, or Script output mode:

2. Call the `niFgen_ConfigureSampleRate` function with the **sampleRate** parameter set to the frequency of the external device you are using as a clock source.

Configuring a Reference Clock

You can specify the source for the Reference clock that will be used in a phase-locked loop to tune the Sample clock timebase to the frequency stability of the Reference clock.

LabVIEW Example

Call the niFgen Configure Reference Clock VI with **Source** set to the Reference clock source. For example, set **Source** to “ClkIn” to obtain the Reference clock signal from the Clk In front panel connector. Set **Reference Clock Frequency** to the frequency of the Reference clock.

C Example

Call the `niFgen_configureReferenceClock` function with the **referenceClockSource** parameter set to the Reference clock source. For example, set the **referenceClockSource** parameter to “ClkIn” to obtain the Reference clock signal from the Clk In front panel connector. Set **referenceClockFrequency** to the frequency of the Reference clock.

Configuring Triggers

Triggers are signals that cause the NI device to perform an action such as starting or stopping a generation operation. Triggers can be internal (software-generated) or external. External digital triggers can be several different types. When triggering your NI signal generator in Standard Function, Arbitrary Waveform, Arbitrary Sequence, Script, or Frequency List mode, you can select the type of trigger, the trigger source, and the trigger mode that you want to use.

LabVIEW Example

1. Call the `niFgen Configure Trigger Mode VI` to select the trigger mode in which your trigger will generate. This mode affects the behavior of the trigger and is dependant on the output mode of the signal generator.
2. Call the `niFgen Configure Trigger poly VI`. Choose the instance of the VI that corresponds to the type of trigger you wish to use.

C Example

1. Call the `niFgen_configureTriggerMode` function to select the trigger mode in which your trigger will generate. This mode affects the behavior of the trigger and is dependant on the output mode of the signal generator.
2. Call one of the following `niFgen Configure Trigger` functions:
`niFgen_ConfigureDigitalEdgeStartTrigger`,
`niFgen_ConfigureSoftwareEdgeStartTrigger`,
`niFgen_ConfigureDigitalEdgeScriptTrigger`,
`niFgen_ConfigureDigitalLevelScriptTrigger`,
`niFgen_ConfigureSoftwareEdgeScriptTrigger`

Creating a Marker Event

You can specify a marker and its location by setting an offset location value (in number of samples) from the start of the waveform. If the offset is out of range of the number of samples in that segment, NI-FGEN returns an error.

There are two rules for marker placement:

1. A marker can be specified only at offsets that are multiples of four samples (or two complex samples).
2. A marker must be placed at least four samples from the end of the waveform. In Burst trigger mode, a marker must be placed at least eight samples from the end of the waveform.

For example, for a waveform containing 100 samples, a marker at an offset of 0 or 4 is valid, but a marker at an offset of 3 is invalid. In addition, a marker at an offset of 97 or 100 is always invalid, while a marker at an offset of 96 is valid for all trigger modes except Burst. The marker can be placed at an offset of 92 for all trigger modes.

Creating a Marker Event in Arbitrary Waveform Mode

You can specify a marker and its location by setting an offset location value (in number of samples) from the start of the waveform. If the offset is out of range of the number of samples in that segment, NI-FGEN returns an error.

LabVIEW Example

1. Specify the position of the Marker event by setting the Arbitrary Waveform Marker Position property.
2. Export the marker event by calling the niFgen Export Signal VI and setting **Signal** to “NIFGEN_VAL_MARKER_EVENT”.

C Example

1. Specify the position of the Marker event by setting the NIFGEN_ATTR_ARB_MARKER_POSITION attribute.
2. Export the marker event by calling the niFgen_ExportSignal function and setting the **signal** parameter to “NIFGEN_VAL_MARKER_EVENT”.

Creating a Marker Event in Arbitrary Sequence Mode

You can specify a marker and its location by setting an offset location value (in number of samples) from the start of the waveform. If the offset is out of range of the number of samples in that segment, NI-FGEN returns an error.

LabVIEW Example

1. Call the niFgen Create Advanced Arb Sequence VI and set **Marker Location Array** to the location at which you would like the marker to generate.
2. Export the marker event by calling the niFgen Export Signal VI and setting **Signal** to "NIFGEN_VAL_MARKER_EVENT".

C Example

1. Call the niFgen_CreateAdvancedArbSequence function and set the **markerLocationArray** parameter to the location at which you would like the marker to generate.
2. Export the marker event by calling the niFgen_ExportSignal function and setting the **signal** parameter to "NIFGEN_VAL_MARKER_EVENT".

Creating a Marker Event in Script Mode

You can specify a marker and its location by setting an offset location value (in number of samples) from the start of the waveform. If the offset is out of range of the number of samples in that segment, NI-FGEN returns an error.

In Script mode, you can create up to four markers for each waveform.

LabVIEW Example

1. To create markers in Script mode, refer to *Common Scripting Use Cases* in the NI Signal Generators Help.
2. Export the marker event by calling the niFgen Export Signal VI. Set **Signal** to "NIFGEN_VAL_MARKER_EVENT" and set **Signal Identifier** to the name of the marker to export.

C Example

1. To create markers in Script mode, refer to refer to Common Scripting Use Case.
2. Export the marker event by calling the `niFgen_ExportSignal` function. Set the **signal** parameter to “`NIFGEN_VAL_MARKER_EVENT`” and the **signalIdentifier** parameter to the name of the marker to export.

Creating a Data Marker Event

To create and export a Data Marker event, complete the following steps:

LabVIEW Example

1. Specify a data bit number using the Data Marker Event Bit Number property.
2. Set the output polarity of the data marker event using the Data Marker Event Level Polarity property.
3. To export the data marker, use the `niFgen Export Signal VI`. To determine all possible signal routes for your device, refer to Signal Routing.



Note When exporting data markers, you must specify the signal identifier for the data marker using the `niFgen Export Signal VI`.

C Example

1. Specify a data bit number using the `NIFGEN_ATTR_DATA_MARKER_EVENT_DATA_BIT_NUMBER` attribute.
2. Set the output polarity of the data marker event using the `NIFGEN_ATTR_DATA_MARKER_EVENT_LEVEL_POLARITY` attribute.
3. To export the data marker, use the `niFgen_ExportSignal` function. To determine all possible signal routes for your device, refer to Signal Routing.



Note When exporting data markers, you must specify the signal identifier for the data marker using the `niFgen_ExportSignal` function.

Configuring an Application for Streaming

The following instructions are a guide for configuring your application for streaming. For a more detailed programmatic example, refer to `Fgen Arb Waveform Streaming.vi` for LabVIEW or `ArbitraryWaveformStreaming.prj` for LabWindows/CVI.

LabVIEW Example

The procedure below provides the basic steps required to configure streaming. For a more detailed example of the use of streaming in LabVIEW, refer to the `Fgen Arb Waveform Streaming.vi` example for LabVIEW.

1. Call the `niFgen Allocate Waveform VI` to specify the amount of onboard memory to reserve for streaming.
2. Set the `Streaming Waveform Handle` property to the waveform handle returned in step 1.
3. Call the `niFgen Write Waveform VI` to write the first part of the waveform data to the streaming waveform in onboard memory.



Tip When transferring large blocks of waveform data, break the data into smaller blocks and call the `niFgen Write Waveform VI` multiple times. The data is appended sequentially. A computer can allocate smaller blocks of a large waveform faster than allocating a single large contiguous block in memory. Depending on the amount of RAM on the computer, transferring ten 16 MB blocks may be faster than transferring one 160 MB block.



Tip NI-FGEN requires the quotient of the waveform size divided by the data transfer block size to be an integer value. If the waveform size is not an integer multiple of the block size, change either the waveform size or the block size. A fractional number of data blocks in the waveform returns an error message.

4. Call the `niFgen Initiate Generation VI` to begin the waveform generation.
5. Use the `Space Available in Streaming Waveform` property to determine how much of the streaming waveform is free for writing new data.



Note The `Space Available in Streaming Waveform` property specifies the total amount of space available in the streaming waveform. During generation, this available space may be in multiple locations with, for example, part of the available space at the end of the streaming waveform and the rest at the beginning. In this situation, writing a block of waveform data the size of the total space available in the streaming waveform causes NI-FGEN to return an error, as NI-FGEN will not wrap the data from the end of the waveform to the beginning and cannot write data past the end of the waveform buffer. To

avoid writing data past the end of the waveform, write new data to the waveform in a fixed size that is an integer divisor of the total size of the streaming waveform.

6. Call the `niFgen_WriteWaveform VI` to write a new block of waveform data to the streaming waveform in onboard memory.

Repeat the process of monitoring the available memory and writing waveform data in blocks as free space becomes available.

C Example

The procedure below provides the basic steps required to configure streaming. For a more detailed example of the use of streaming in C, refer to the `ArbitraryWaveformStreaming.prj` example for CVI.

1. Call the `niFgen_AllocateWaveform` function to specify the amount of onboard memory to reserve for streaming.
2. Set the `NIFGEN_ATTR_STREAMING_WAVEFORM_HANDLE` attribute to the waveform handle returned in Step 1.
3. Call the `niFgen_WriteWaveform` function to write the first part of the waveform data to the streaming waveform in onboard memory.



Tip When transferring large blocks of waveform data, break the data into smaller blocks and call the `niFgen_WriteWaveform` function multiple times. The data is appended sequentially. A computer can allocate smaller blocks of a large waveform faster than allocating a single large contiguous block in memory. Depending on the amount of RAM on the computer, transferring ten 16 MB blocks may be faster than transferring one 160 MB block.



Tip NI-FGEN requires the quotient of the waveform size divided by the data transfer block size to be an integer value. If the waveform size is not an integer multiple of the block size, change either the waveform size or the block size. A fractional number of data blocks in the waveform returns an error message.

4. Call the `niFgen_InitiateGeneration` function to begin the waveform generation.
5. Use the `NIFGEN_ATTR_STREAMING_SPACE_AVAILABLE_IN_WAVEFORM` attribute to determine how much of the streaming waveform is free for writing new data.



Note The `NIFGEN_ATTR_STREAMING_SPACE_AVAILABLE_IN_WAVEFORM` attribute specifies the total amount of space available in the streaming waveform. During generation, this available space may be in multiple locations with, for example, part of the available space at the end of the streaming waveform and the rest at the beginning. In this situation, writing a block of waveform data the size of the total space available in the streaming waveform causes NI-FGEN to return an error, as NI-FGEN will not wrap the data from the end of the waveform to the beginning and cannot write data past the end of the waveform buffer. To avoid writing data past the end of the waveform, write new data to the waveform in a fixed size that is an integer divisor of the total size of the streaming waveform.

6. Call the `niFgen_WriteWaveform` function to write a new block of waveform data to the streaming waveform in onboard memory.

Repeat the process of monitoring the available memory and writing waveform data in blocks as free space becomes available.

Configuring Your Application for Direct DMA

You can achieve high rates of data transfer to the onboard memory by configuring your device for Direct DMA. Direct DMA establishes a direct connection between the signal generator onboard memory and a specialized waveform data source.

The following instructions are a guide for configuring your application for direct DMA.

LabVIEW Example

1. Enable the signal generator for direct DMA writes by setting the Direct DMA Enabled property. Once enabled, NI-FGEN monitors and reports any issues with the direct DMA transfer.
2. Identify the waveform data source and set the Direct DMA Window Address property to the address provided by your direct DMA-compatible data source.
3. Set the Direct DMA Window Size property to the size of the memory window provided by your direct DMA-compatible data source.
4. Use the `niFgen Write Waveform I16 Direct DMA VI` to write blocks of data to the signal generator. For each block of data written to the signal generator, you provide the address of the direct DMA window instead of an array of samples residing in host memory. NI-FGEN detects when the address is within the direct DMA window and handles the transfer appropriately.

C Example

1. Enable the signal generator for direct DMA writes by setting the `NIFGEN_ATTR_DIRECT_DMA_ENABLED` attribute. Once enabled, NI-FGEN monitors and reports any issues with the direct DMA transfer.
2. Identify the waveform data source and set the `NIFGEN_ATTR_DIRECT_DMA_WINDOW_ADDRESS` attribute to the address provided by your direct DMA-compatible data source.
3. Set the `NIFGEN_ATTR_DIRECT_DMA_WINDOW_SIZE` attribute to the size of the memory window provided by your direct DMA-compatible data source.
4. Use the `niFgen_WriteBinary16Waveform` function to write blocks of data to the signal generator. For each block of data written to the signal generator, you provide the address of the direct DMA window instead of an array of samples residing in host memory. NI-FGEN detects when the address is within the direct DMA window and handles the transfer appropriately.

Simulation Mode

NI signal generators support simulation. Simulating a device enables you to perform the following tasks:

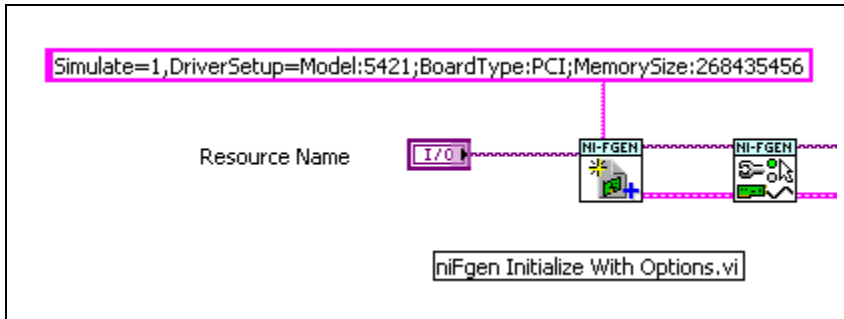
- Protect your devices by first testing settings and configurations on simulated devices.
- Verify device behaviors under a wide variety of operating conditions.
- Start or speed up application development before you have the hardware.
- Optimize designs and determine ideal design parameters.

Enabling simulation allows you to verify that you have correctly configured the device. For example, if a parameter is set to an invalid value for the device, NI-FGEN returns the same error it would for a real device. While simulation is useful for verifying your configuration, there are some areas where simulation is not sufficient to verify that your configuration is correct. For example, no errors will be returned for configurations that involve or depend upon external signals, such as configuring an external Sample clock or routing signals. Also, the amount of time a generation takes to complete will be ignored in simulation mode; a finite generation will finish immediately after it is initiated, regardless of how much data is downloaded and how fast it is generated.

LabVIEW Example

In LabVIEW, simulation is enabled with the Option String parameter of the niFgen Initialize With Options VI. Enable simulation (Simulate=1) and specify the device you want to simulate with the option string input.

The following example enables simulation of the NI PCI-5421 with 256 MB of onboard memory:



For more information, refer to the niFgen Initialize With Options VI.

C Example

In LabWindows/CVI, simulation is enabled with the niFgen_InitWithOptions function. Enable simulation (Simulate=1) and specify the device you want to simulate with the option string parameter.

The following example enables simulation of the NI PCI-5421 with 256 MB of onboard memory:

```
niFgen_InitWithOptions (Resource, VI_ON, VI_ON,
    "Simulate=1,
    DriverSetup=Model:5421;BoardType:PCI;MemorySize:2684354
    56",&vi );
```

For more information, refer to the niFgen_InitWithOptions function.

Signal Generation Fundamentals

Bandwidth and Passband Flatness

The bandwidth of a signal source is defined as the frequency at which the amplitude of the frequency response is 3 dB lower than the amplitude of the frequency response at DC or a low frequency. The bandwidth of a source is limited by the output amplifier design or by filters in the analog output circuit. Bandwidth is one of the factors that determines the capability of the source to create signals with specific frequency content.

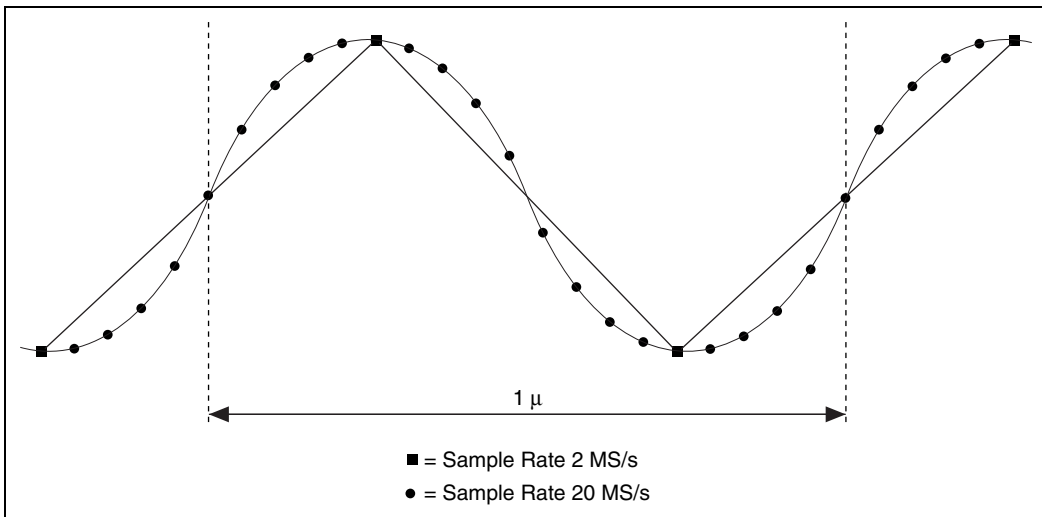
Passband flatness is a measure of the amplitude accuracy of the frequency response with respect to frequency. Passband flatness is usually specified in \pm dB, and it is usually referenced to the amplitude of the frequency response at a designated frequency.

For example, a specification might be listed as ± 1 dB with respect to the amplitude of the frequency response at 50 kHz. This method is used because two different metrology instruments, a digital multimeter (DMM) and a power meter, are used to measure passband flatness. The power meter is an excellent metrology instrument for measuring passband flatness, but its performance can be improved by calibrating its frequency response at a low frequency, such as 50 kHz, with a DMM. In other words, the DMM measures the amplitude of a 50 kHz tone, and the power meter measures the amplitude of all other frequencies with respect to the amplitude of the 50 kHz tone measured by the DMM.

Passband flatness is important in many applications. For example, if the sensitivity of a receiver is being tested, it is important to know the variation of the amplitude of the test tone as it is swept across the frequency band of interest. Some NI signal generators have a Direct Output analog path that has been optimized for passband flatness. Others allow you to select a frequency at which the calibrated amplitudes can be finely adjusted to achieve the best amplitude accuracy near the selected frequency.

Sample Rate

Sample rate is the rate at which digital data is transferred from the memory to the digital-to-analog converter (DAC). According to Shannon's Sampling theorem, a digital waveform must be updated at least twice as fast as the bandwidth of the signal to be accurately generated. Ideally, a sample rate many times greater than the frequency of the signal produces accurate waveforms. A higher sample rate also captures more waveform details. The following figure illustrates a 1 MHz sine wave generated by a sampled 2 MS/s DAC and a 20 MS/s DAC. The faster DAC generates 20 points per cycle of the expected signal compared with 2 points per cycle with the slower DAC. In this example, the higher sample rate more accurately defines the waveform shape.

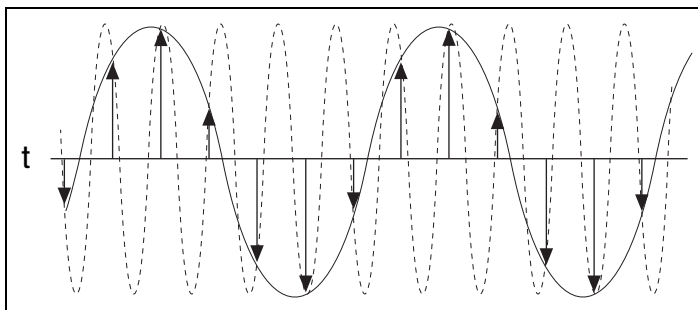


Nyquist and Shannon's Sampling Theorems

The Nyquist theorem concerns digital sampling of a continuous time analog waveform, while Shannon's Sampling theorem concerns the creation of a continuous time analog waveform from digital, discrete samples.

Nyquist Theorem

The Nyquist theorem states that an analog signal must be sampled at least twice as fast as the bandwidth of the signal to accurately reconstruct the waveform; otherwise, the high-frequency content creates an alias at a frequency inside the spectrum of interest (passband). An alias is a false lower frequency component that appears in sampled data acquired at too low a sampling rate. The following figure shows a 5 MHz sine wave digitized by a 6 MS/s analog-to-digital converter (ADC). In this figure, the solid line represents the sine wave being digitized, while the dotted line represents the aliased signal recorded by the ADC at that sample rate.

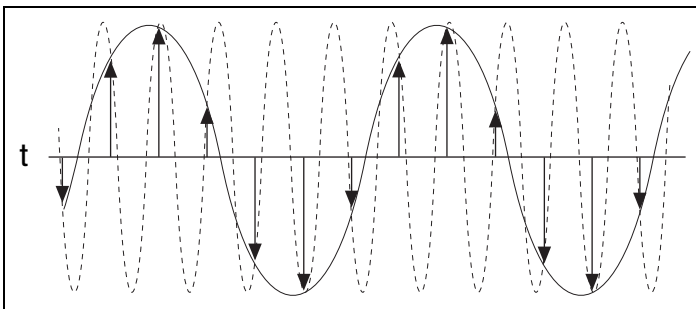


The 5 MHz frequency aliases back in the passband, falsely appearing as a 1 MHz sine wave.

Shannon's Sampling Theorem

Shannon's Sampling theorem states that a digital waveform must be updated at least twice as fast as the bandwidth of the signal to be accurately generated. The same image that was used for the Nyquist example can be used to demonstrate Shannon's Sampling theorem.

The following figure shows a desired 5 MHz sine wave generated by a 6 MS/s DAC. The solid line represents the desired waveform, and the arrows represent the digitized samples that are available to recreate the continuous time 5 MHz sine wave. The dotted line indicates the signal that would be seen, for example, with an oscilloscope at the output of a DAC.



In this case, the high-frequency sine wave is the desired signal, but was severely undersampled by only being generated by a 6 MS/s DAC; the actual resulting waveform is a 1 MHz signal.

In systems where you want to generate accurate signals using sampled data, the sampling rate must be set high enough to prevent aliasing.

Aliased Images

An aliased image is a frequency component that appears in continuous time waveforms being recreated from discrete-time, digital waveforms. The frequencies where these extra components appear are related to both the frequency of the signals being recreated as well as the frequency of the sample rate. Looking only at positive frequencies, the two frequencies are related by the following equation:

$$f_{ai} = |f_o + nf_s|$$

where

f_{ai} = the aliased images

f_o = the desired waveform frequency

f_s = the sample rate

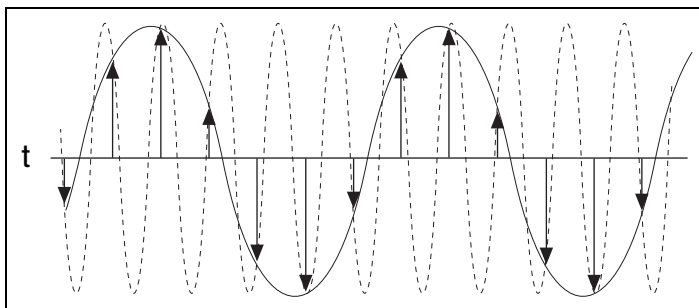
n = an integer (either positive or negative)

As the equation indicates, there are an infinite number of these aliased images that occur. As n gets larger, however, the power content of these extra frequencies “falls off.”

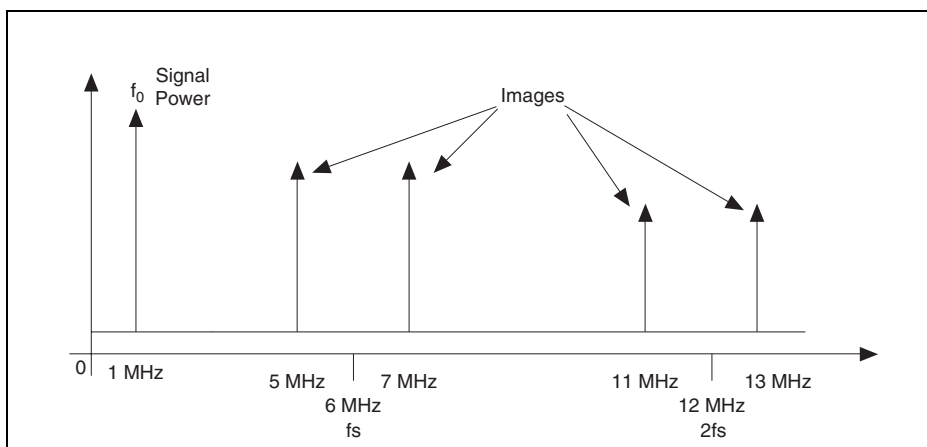
The following figure shows a 1 MHz sine wave generated by a 6 MS/s DAC. The dotted line represents an aliased image signal that shows up as a 5 MHz component. In this case, f_o is 1 MHz, n is -1 , and f_s is 6 MHz; resulting in the following formula:

$$f_{ai} = 5 \text{ MHz} = 1 \text{ MHz} + (-1)(6 \text{ MHz})$$

The other possible frequencies of sine waves can be calculated and superimposed onto the sampling points of the image.



The following figure shows the frequency domain representation of the previous example. The vertical arrow at f_o represents the frequency and signal power of the desired generated signal. The other vertical arrows represent the frequencies and signal powers of the aliased image frequency components that appear in the frequency spectrum.



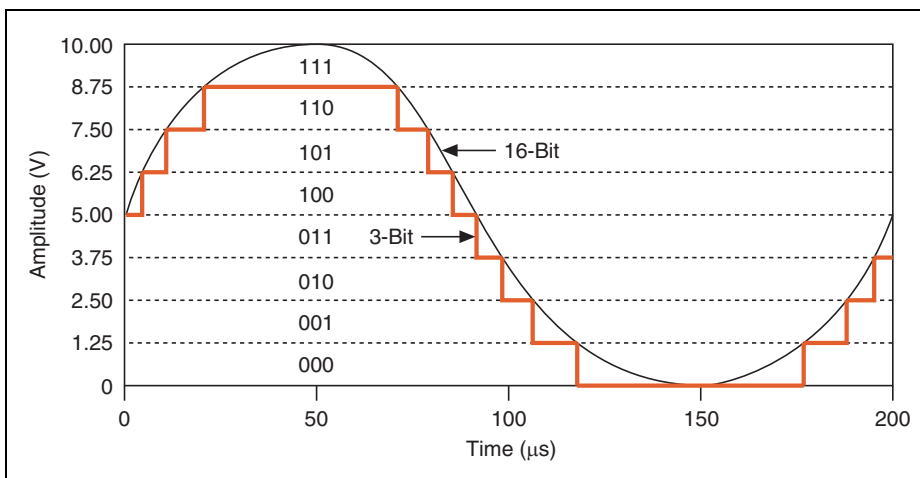
In systems where you want to generate accurate signals using sampled data, an optional lowpass filter must be introduced after the DAC to restrict the

bandwidth of the output signal to meet the sampling criteria (Shannon's Sampling theorem).

DAC Resolution

Digital-to-analog converter (DAC) resolution is a limiting factor in determining the accuracy of the re-creation of an analog waveform from digital samples. More details are present in the waveform if the DAC resolution is increased. A 3-bit DAC divides its vertical range into eight discrete levels. With a vertical range of 10 V, the 3-bit DAC cannot generate voltage differences smaller than 1.25 V. In comparison, a 16-bit DAC with 65,536 discrete levels can generate voltage differences as small as 153 μV .

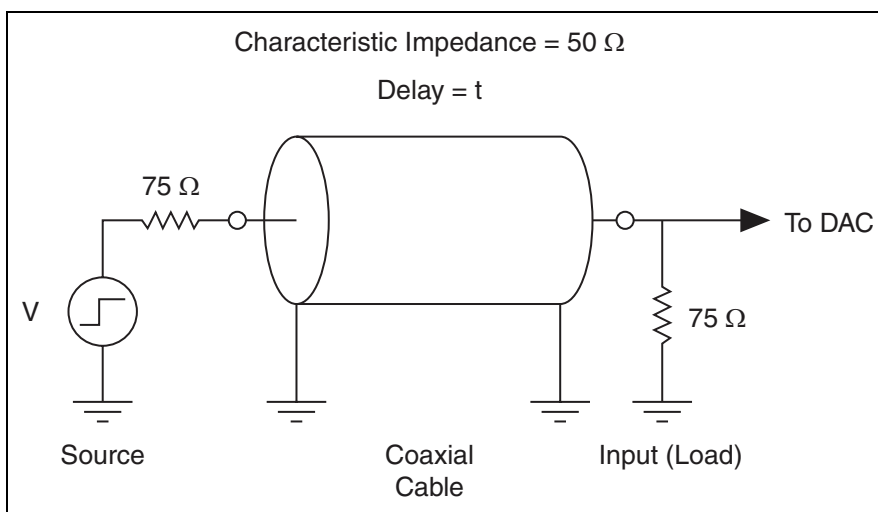
The following figure shows the difference between two waveforms. The 16-bit waveform looks like a continuous sine wave, but if you were to zoom in, you would see the discrete steps of 153 μV . Both waveforms are composed of discrete voltage steps, but the 16-bit version looks much closer to a “pure” continuous-time sine waveform.



Impedance Matching

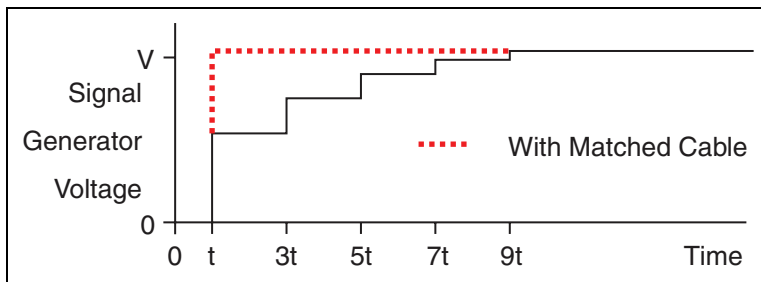
When broadband signals are carried on transmission lines of any significant length, care must be taken that the transmission line is matched to its terminations. The source and load impedances should equal the characteristic impedance of the transmission line, as this minimizes signal reflections. The presence of impedance discontinuities or mismatches degrade the amplitude and phase accuracy, as well as the temporal fidelity, of waveforms generated with a signal generator.

One of the most common mismatch errors encountered in such measurements is shown in the following figure.



In this example, selectable source impedances are provided at the signal generator outputs to accommodate the most popular coaxial cable characteristic impedances: 50 Ω and 75 Ω.

The following figure shows what happens when, as in this example, a coaxial cable of the wrong characteristic impedance ($50\ \Omega$) is used with $75\ \Omega$ source and load impedances.



The pulse encounters impedance mismatches at each end of the cable, causing the pulse to be partially reflected. The reflected pulse traverses the cable back and forth numerous times, diminishing at each end by the reflection coefficient, Γ .

$$\Gamma = \frac{v_r}{v_i} = \frac{z_t - z_0}{z_t + z_0}$$

where

v_r = reflected voltage

v_i = incident voltage

z_t = terminating impedance

z_0 = characteristic impedance

The resulting voltage waveform is distorted by the asymptotic decay of the reflected pulse as shown, exaggerated for visual effect. Impedance discontinuities of smaller magnitude and/or duration have correspondingly smaller effects. Also displayed is the waveform that results when a cable of matched impedance ($75\ \Omega$) is used.

Mismatch Uncertainty

Impedance matching is also important for preserving the absolute delivered power from a device. The accuracy with which power can be delivered is limited by mismatch error. The mismatch error in a z_0 system can be shown to be bounded by:

$$\frac{(1 - |\Gamma_L|^2)}{(1 + |\Gamma_L| \cdot |\Gamma_G|)^2} \leq \text{mismatch error} \leq \frac{(1 - |\Gamma_L|^2)}{(1 - |\Gamma_L| \cdot |\Gamma_G|)^2}$$

where:

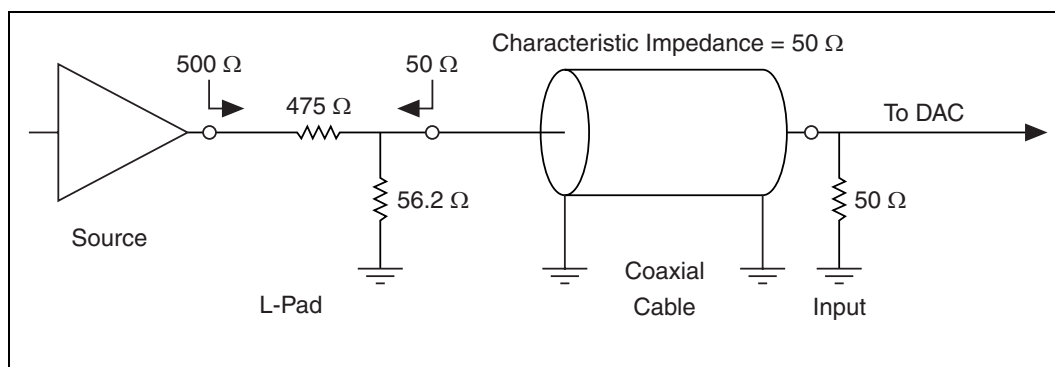
Γ_L = load reflection coefficient

Γ_G = generator reflection coefficient

The denominator term represents mismatch uncertainty, which is a fundamental limit to the power transfer accuracy that can be achieved across a mismatched junction.

Resistive Matching

Signal generators with low/high-source impedance can be matched with a resistor placed in series (shunt) such that the total source impedance (admittance) is matched to the cable characteristic impedance (admittance). Signal generators that are not capable of driving the cable impedance directly can be coupled through a matching L-pad. In this case, the signal generator sees an approximately 500 Ω load, while the source impedance presented to the cable is 50 Ω , as shown in the following figure.



High-frequency components and layout techniques should be used throughout to minimize parasitic effects.

Output Attenuation

Output attenuation is a method of controlling the output voltage level of the signal being generated. NI signal generators typically generate signals with a digital-to-analog converter (DAC) that has an output voltage range of -5.0 V to $+5.0\text{ V}$ with a number of bits of resolution. This signal is applied to an attenuator that controls the output voltage of the signal source.

By attenuating the DAC output signal, you keep the dynamic range of the DAC; that is, you do not lose any bits from the digital representation of the signal because the attenuation is done after the DAC and not before it.

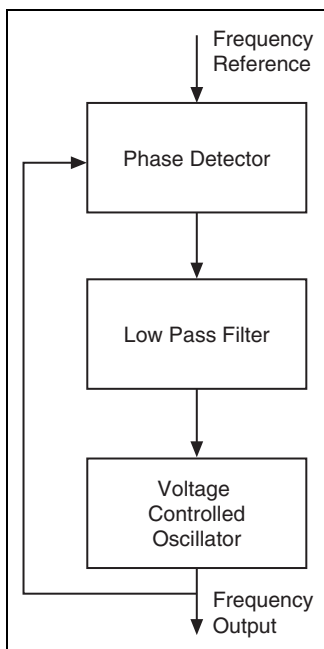
For example, if a DAC with a range of -5.0 V to $+5.0\text{ V}$ and a resolution of 12 bits with each bit corresponding to 2.44 mV $[(+5.0 - (-5.0)) / 2^{12}]$ does not use output attenuation, and the desired signal is $2.0\text{ V}_{\text{pk-pk}}$ (-1.0 V to $+1.0\text{ V}$), waveform values can be generated with the DAC that only use $1/5$ of the DAC range. The resolution of each digital bit is still 2.44 mV .

However, if the same DAC uses the output attenuation, the full range of the DAC generates the signal, creating the signal at the full $10.0\text{ V}_{\text{pk-pk}}$. The value of each digital bit is still the original 2.44 mV . The signal is applied to an attenuator, which reduces the voltage level by a factor of 5 to $2.0\text{ V}_{\text{pk-pk}}$. The attenuator also reduces the value of each bit, which results in an effective bit value of 0.488 mV at the analog output connector. The attenuator allows the use of the full range of the DAC, and reduces the effective value of each bit corresponding to the degree of attenuation.

Phase-Locked Looping

A phase-lock loop (PLL) is a circuit that adjusts a main clock to synchronize to a Reference clock. The frequency stability of the Sample clock timebase matches that of the Reference clock when the two are phase-locked. Phase locking also synchronizes clocks of multiple devices that are phase-locked to the same Reference clock.

The following figure shows a block diagram of a basic PLL.



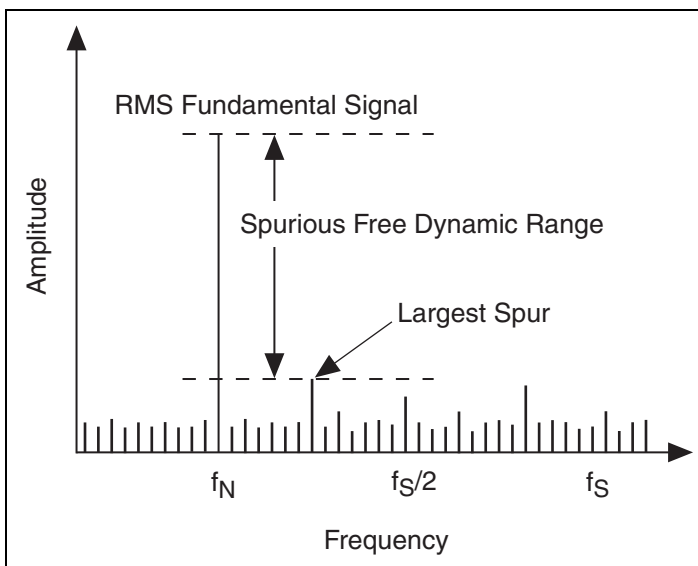
The operation of this circuit is typical of all PLLs. A PLL is a feedback control system that controls the phase of a voltage-controlled oscillator (VCO). The frequency reference signal is applied to a phase detector. The output of the VCO connects to the other input. Normally the frequencies of both signals are almost the same. The output of the phase detector has a voltage proportional to the phase difference between the two input signals. The loop filter receives this signal from the phase detector. The loop filter determines the dynamic characteristics of the PLL.

Frequency Domain Fundamentals

SFDR

Spurious-free dynamic range (SFDR) is the usable dynamic range before spurious noise interferes with or distorts the fundamental signal. For specification purposes, the amplitude of the fundamental signal is usually -1 dBFS. SFDR is the measure of the difference in amplitude between the fundamental signal and the largest harmonically or nonharmonically related spur from DC to the full Nyquist bandwidth (half the sampling rate). A spur is any frequency bin on a spectrum analyzer, or from a Fourier transform, of the analog signal. SFDR is expressed in dBc.

The following figure illustrates how SFDR is measured.



THD

The total harmonic distortion (THD) of a signal is the ratio of the sum of the powers of the first five harmonics above the measured fundamental frequency to the power of the fundamental frequency. THD is usually expressed in dB or dBc. Measurements for calculating the THD are made at the output of a device under specified conditions.

SINAD

Signal-to-noise-and-distortion ratio (SINAD) is the ratio of the rms signal amplitude to the rms sum of all other spectral components, including the harmonics but excluding DC. SINAD is usually expressed in dB.

ENOB

Effective number of bits (ENOB) is another way of specifying signal-to-noise and distortion ratio (SINAD). ENOB is calculated using the following formula:

$$\text{ENOB} = \frac{\text{SINAD} - 1.76}{6.02}$$



Note Assumes the full scale of the DAC is utilized.

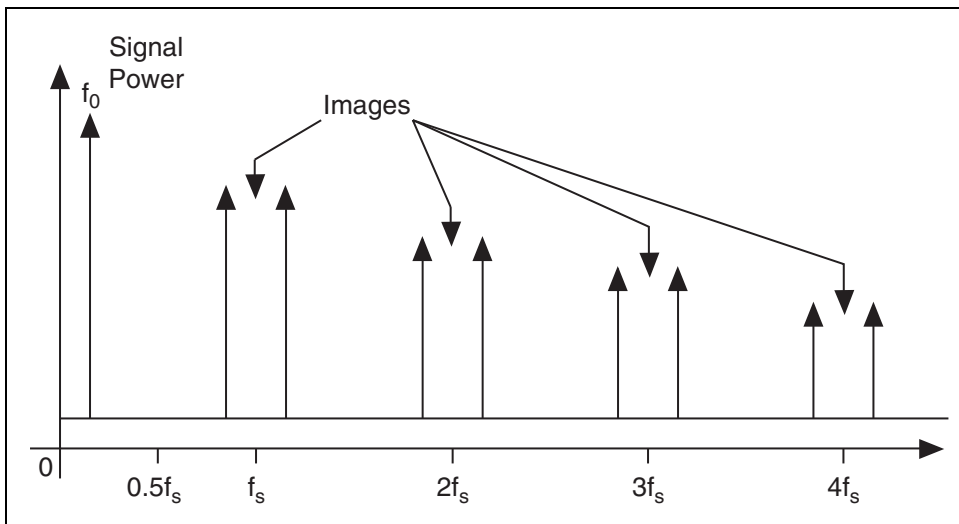
The ENOB value is the value of an ideal DAC that is equivalent to the DAC of the device.

Filtering and Interpolation

All NI signal generators use a digital-to-analog converter (DAC) to generate the signals or waveforms that eventually appear at the output connector. These generated signals have a number of discrete voltage levels dependent on the number of bits in the DAC.

A digital waveform must be updated at least twice as fast as the bandwidth of the desired analog signal to be accurately generated (Shannon's Sampling Theorem). Even though the theoretical requirement for

Sample clock, f_s , is twice that of the signal bandwidth, f_o , images are introduced in the output signal at $|f_o \pm nf_s|$, as shown in the following figure.



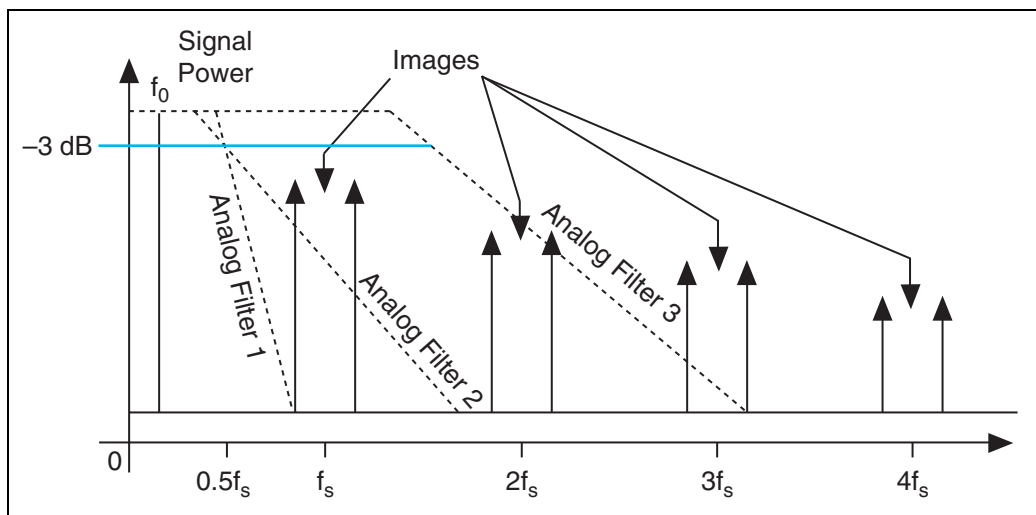
The images shown in the previous figure degrade the spectral purity of the signal, creating the need to filter these images out of the signal.

To create quality signals, all NI signal generators can lowpass filter the generated signal. A lowpass filter can smooth the raw DAC output. The filter removes high-frequency aliased components that are introduced through the digital generation of the signal. You can implement the lowpass filter through both analog and digital filters.

Designing an analog filter that rejects the images and yet gets maximum output bandwidth (0 to $0.43f_s$) is difficult and is represented by the curve Analog Filter 1 in the following figure. Analog Filter 2 represents a more practical filter. This filter is not as aggressive as Analog Filter 1. Analog Filter 2 does not filter out the images near f_s , but it does reject all the others. Analog filters have trade-offs between the roll-off of the attenuation after the 3 dB point and the flatness of the attenuation before the 3 dB point.

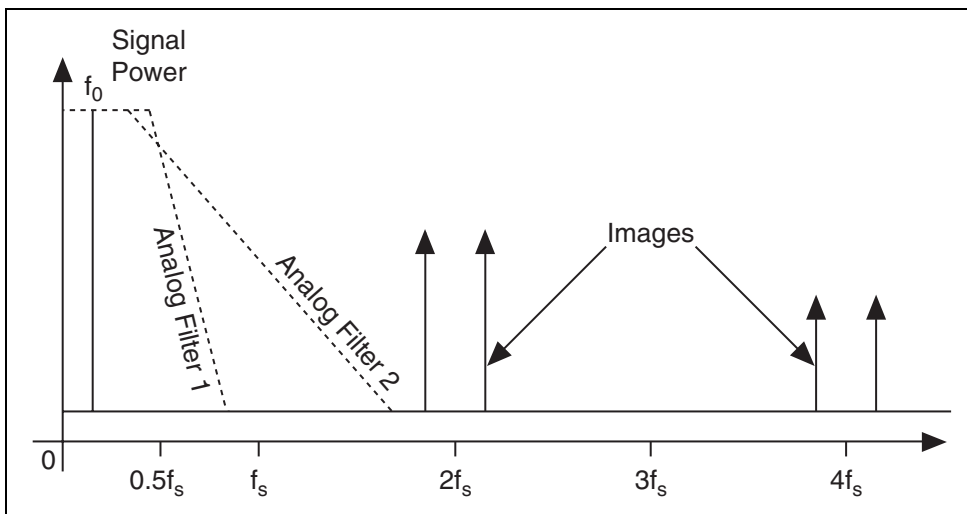
Another aspect of the analog filter is group delay—the amount of time needed for a signal having finite time duration, such as a pulse, to pass through the analog filter. Ideally, in an analog filter with linear group delay, all frequencies present in the signal should have the same time delay so that the signal is not distorted.

The third filter, Analog Filter 3, has a much higher 3 dB point than the first two analog filters. Because of the higher 3 dB point, the filter is very nearly flat in the passband (0 to $0.43f_s$). Analog Filter 3 does not filter the images produced at f_s and $2f_s$ at all, but this shortcoming can be alleviated with a digital interpolation filter.

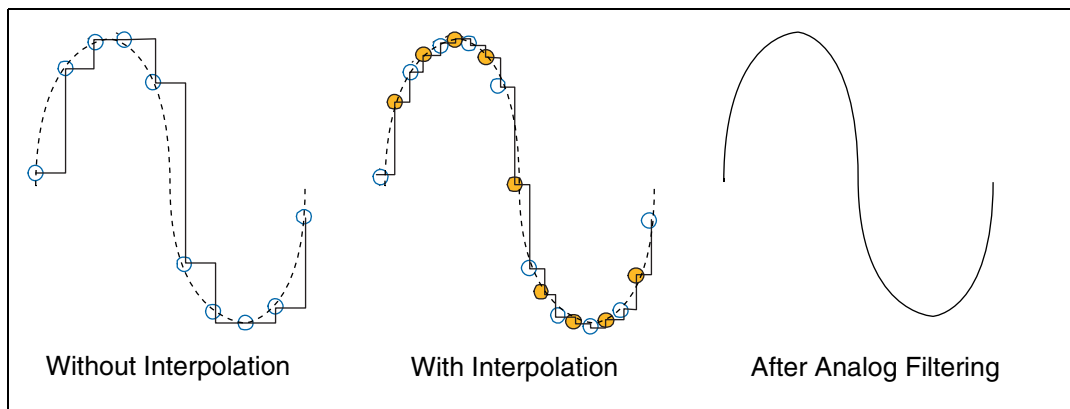


To ease the requirements of the analog filter and to get more output bandwidth, NI signal generators use a halfband digital filter to interpolate one, three, or seven samples between every two waveform samples at two times, four times, and eight times the sample frequency, f_s . Also, the DAC operates at an effective sampling rate that is two times ($2f_s$), four times ($4f_s$) and eight times ($8f_s$) the sample frequency—specifically, the rate at which the data is clocked from the memory into the DAC.

In the following figure, the two times interpolating filter is used and the effective sample rate of the DAC is $2f_s$. The images at $f_s \pm f_0$ are no longer an issue, and the images are now at $|2f_s \pm f_0|$.



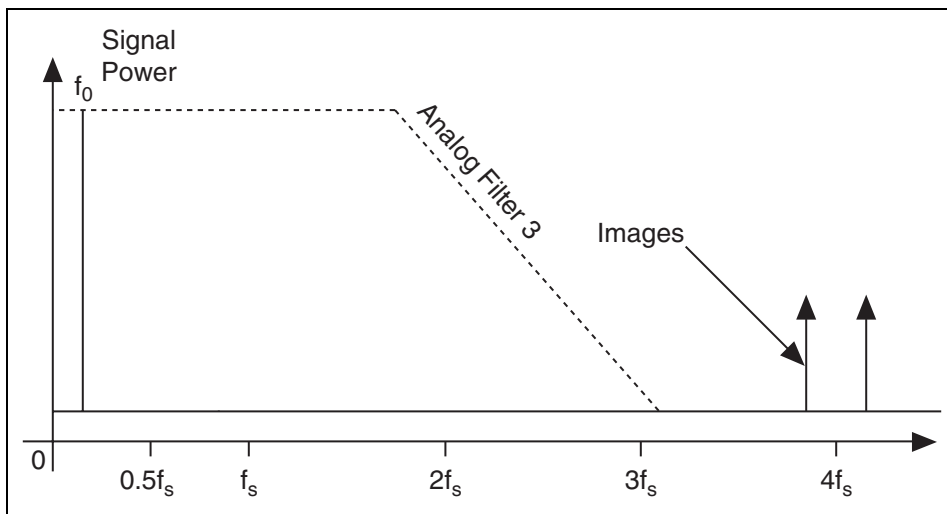
Now, Analog Filter 2 can easily filter out all the images due to the digital generation of the signal. This behavior is seen in the frequency domain representation in the previous figure and in the time domain representation in the following figure.



Note The allowable range of interpolation factors is dependent on the NI signal generator being used.

Using two times interpolation filtering with a DAC effective sample rate of $2f_s$ eliminates images well and generates a good signal. However, increasing the interpolation filter to 4 further improves the output signal.

The following figure shows a signal image with four times interpolation, and the effective DAC sample rate at $4f_s$. The images are shifted up to $4f_s$, and well above the cutoff frequency of Analog Filter 3. This configuration eliminates the spectral images and has a filter that is maximally flat within the passband. This configuration approaches an ideal design in digitally generating spectrally pure waveforms.



To generate the most spectrally pure signals using the digital filter, you should use the highest interpolation factor that you can.

Technical Support and Professional Services

Visit the following sections of the award-winning National Instruments Web site at ni.com for technical support and professional services:

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- **Calibration Certificate**—If your product supports calibration, you can obtain the calibration certificate for your product at ni.com/calibration.

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